

## Summary

The Xilinx® Zynq® UltraScale+™ MPSoCs are available in -3, -2, -1 speed grades, with -3E devices having the highest performance. The -2LE and -1LI devices can operate at a  $V_{CCINT}$  voltage at 0.85V or 0.72V and are screened for lower maximum static power. When operated at  $V_{CCINT} = 0.85V$ , using -2LE and -1LI devices, the speed specification for the L devices is the same as the -2I or -1I speed grades. When operated at  $V_{CCINT} = 0.72V$ , the -2LE and -1LI performance and static and dynamic power is reduced.

DC and AC characteristics are specified in extended (E) and industrial (I) temperature ranges. Except the operating temperature range or unless otherwise noted, all the DC and AC electrical parameters are the same for a particular speed grade (that is, the timing characteristics of a -1 speed grade extended device are the same as for a -1 speed grade industrial device). However, only selected speed grades and/or devices are available in each temperature range.

All supply voltage and junction temperature specifications are representative of worst-case conditions. The parameters included are common to popular designs and typical applications.

This data sheet, part of an overall set of documentation on the Zynq UltraScale+ MPSoCs, is available on the Xilinx website at [www.xilinx.com/documentation](http://www.xilinx.com/documentation).

## DC Characteristics

### Absolute Maximum Ratings

*Table 1: Absolute Maximum Ratings<sup>(1)</sup>*

Symbol	Description	Min	Max	Units
<b>Processor System (PS)</b>				
$V_{CC\_PSINTFP}$	PS primary logic full-power domain supply voltage.	-0.500	1.000	V
$V_{CC\_PSINTLP}$	PS primary logic low-power domain supply voltage.	-0.500	1.000	V
$V_{CC\_PSAUX}$	PS auxiliary supply voltage.	-0.500	2.000	V
$V_{CC\_PSINTFP\_DDR}$	PS DDR controller and PHY supply voltage.	-0.500	1.000	V
$V_{CC\_PSADC}$	PS SYSMON ADC supply voltage relative to GND_PSADC.	-0.500	2.000	V
$V_{CC\_PSPLL}$	PS PLL supply voltage.	-0.500	1.320	V
$V_{PS\_MGTRAVCC}$	PS-GTR supply voltage.	-0.500	1.000	V
$V_{PS\_MGTRAVTT}$	PS-GTR termination voltage.	-0.500	2.000	V
$V_{PS\_MGTREFCLK}$	PS-GTR reference clock input voltage.	-0.500	1.100	V
$V_{PS\_MGTRIN}$	PS-GTR receiver input voltage.	-0.500	1.100	V

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Table 1: Absolute Maximum Ratings<sup>(1)</sup> (Cont'd)

Symbol	Description	Min	Max	Units
$V_{CCO\_PSDDR}$	PS DDR I/O supply voltage.	-0.500	1.650	V
$V_{CC\_PSDDR\_PLL}$	PS DDR PLL supply voltage.	-0.500	2.000	V
$V_{CCO\_PSIO}$	PS I/O supply.	-0.500	3.630	V
$V_{PSIN}^{(2)}$	PS I/O input voltage.	-0.500	$V_{CCO\_PSIO} + 0.550$	V
	PS DDR I/O input voltage.	-0.500	$V_{CCO\_PSDDR} + 0.550$	V
$V_{CC\_PSBATT}$	PS battery-backed RAM and battery-backed real-time clock (RTC) supply voltage.	-0.500	2.000	V
<b>Programmable Logic (PL)</b>				
$V_{CCINT}$	Internal supply voltage.	-0.500	1.000	V
$V_{CCINT\_IO}^{(3)}$	Internal supply voltage for the I/O banks.	-0.500	1.000	V
$V_{CCAUX}$	Auxiliary supply voltage.	-0.500	2.000	V
$V_{CCBRAM}$	Supply voltage for the block RAM memories.	-0.500	1.000	V
$V_{CCO}$	Output drivers supply voltage for HD I/O banks.	-0.500	3.400	V
	Output drivers supply voltage for HP I/O banks.	-0.500	2.000	V
$V_{CCAUX\_IO}^{(4)}$	Auxiliary supply voltage for the I/O banks.	-0.500	2.000	V
$V_{REF}$	Input reference voltage.	-0.500	2.000	V
$V_{IN}^{(2)(5)(7)}$	I/O input voltage for HD I/O banks. <sup>(6)</sup>	-0.550	$V_{CCO} + 0.550$	V
	I/O input voltage for HP I/O banks.	-0.550	$V_{CCO} + 0.550$	V
$I_{DC}$	Available output current at the pad.	-20	20	mA
$I_{RMS}$	Available RMS output current at the pad.	-20	20	mA
<b>GTH or GTY Transceiver</b>				
$V_{MGTAVCC}$	Analog supply voltage for transceiver circuits.	-0.500	1.000	V
$V_{MGTAVTT}$	Analog supply voltage for transceiver termination circuits.	-0.500	1.300	V
$V_{MGTVCCAUX}$	Auxiliary analog Quad PLL (QPLL) voltage supply for transceivers.	-0.500	1.900	V
$V_{MGTREFCLK}$	Transceiver reference clock absolute input voltage.	-0.500	1.300	V
$V_{MGTAVTRCAL}$	Analog supply voltage for the resistor calibration circuit of the transceiver column.	-0.500	1.300	V
$V_{IN}$	Receiver (RXP/RXN) and transmitter (TXP/TXN) absolute input voltage.	-0.500	1.200	V
$I_{DCIN-FLOAT}$	DC input current for receiver input pins DC coupled RX termination = floating. <sup>(8)</sup>	-	10	mA
$I_{DCIN-MGTAVTT}$	DC input current for receiver input pins DC coupled RX termination = $V_{MGTAVTT}$ .	-	10	mA
$I_{DCIN-GND}$	DC input current for receiver input pins DC coupled RX termination = GND. <sup>(9)</sup>	-	0	mA
$I_{DCIN-PROG}$	DC input current for receiver input pins DC coupled RX termination = programmable. <sup>(10)</sup>	-	0	mA
$I_{DCOUT-FLOAT}$	DC output current for transmitter pins DC coupled RX termination = floating.	-	6	mA
$I_{DCOUT-MGTAVTT}$	DC output current for transmitter pins DC coupled RX termination = $V_{MGTAVTT}$ .	-	6	mA

Table 1: Absolute Maximum Ratings<sup>(1)</sup> (Cont'd)

Symbol	Description	Min	Max	Units
<b>Video Codec Unit</b>				
V <sub>CCINT_VCU</sub>	Internal supply voltage for the video codec unit.	-0.500	1.000	V
<b>PL System Monitor</b>				
V <sub>CCADC</sub>	PL System Monitor supply relative to GNDADC.	0.500	2.000	V
V <sub>REFP</sub>	PL System Monitor reference input relative to GNDADC.	0.500	2.000	V
<b>Temperature</b>				
T <sub>STG</sub>	Storage temperature (ambient).	-65	150	°C
T <sub>SOL</sub>	Maximum soldering temperature. <sup>(12)</sup>	-	260	°C
T <sub>j</sub>	Maximum junction temperature. <sup>(12)</sup>	-	125	°C

**Notes:**

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- When operating outside of the recommended operating conditions, refer to Table 6, Table 7, and Table 8 for maximum overshoot and undershoot specifications.
- V<sub>CCINT\_IO</sub> must be connected to V<sub>CCBRAM</sub>.
- V<sub>CCAUX\_IO</sub> must be connected to V<sub>CCAUX</sub>.
- The lower absolute voltage specification always applies.
- If V<sub>CCO</sub> is 3.3V, the maximum voltage is 3.4V.
- For I/O operation, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).
- AC coupled operation is not supported for RX termination = floating.
- For GTY transceivers, DC coupled operation is not supported for RX termination = GND.
- DC coupled operation is not supported for RX termination = programmable.
- For more information on supported GTH or GTY transceiver terminations see the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) or *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)).
- For soldering guidelines and thermal considerations, see the *Zynq UltraScale+ MPSoC Packaging and Pinout Specifications* ([UG1075](#)).

## Recommended Operating Conditions

Table 2: Recommended Operating Conditions<sup>(1)(2)</sup>

Symbol	Description	Min	Typ	Max	Units
<b>Processor System</b>					
V <sub>CC_PSINTFP</sub> <sup>(3)</sup>	PS full-power domain supply voltage.	0.808	0.850	0.892	V
	For -1LI and -2LE ( $V_{CCINT} = 0.72V$ ) devices: PS full-power domain supply voltage.	0.808	0.850	0.892	V
	For -3E devices: PS full-power domain supply voltage.	0.873	0.900	0.927	V
V <sub>CC_PSINTLP</sub>	PS low-power domain supply voltage.	0.808	0.850	0.892	V
	For -1LI and -2LE ( $V_{CCINT} = 0.72V$ ) devices: PS low-power domain supply voltage.	0.808	0.850	0.892	V
	For -3E devices: PS low-power domain supply voltage.	0.873	0.900	0.927	V
V <sub>CC_PSAUX</sub>	PS auxiliary supply voltage.	1.710	1.800	1.890	V
V <sub>CC_PSINTFP_DDR</sub> <sup>(3)</sup>	PS DDR controller and PHY supply voltage.	0.808	0.850	0.892	V
	For -1LI and -2LE ( $V_{CCINT} = 0.72V$ ) devices: PS DDR controller and PHY supply voltage.	0.808	0.850	0.892	V
	For -3E devices: PS DDR controller and PHY supply voltage.	0.873	0.900	0.927	V
V <sub>CC_PSADC</sub>	PS SYSMON ADC supply voltage relative to GND_PSADC.	1.710	1.800	1.890	V
V <sub>CC_PSPLL</sub>	PS PLL supply voltage.	1.164	1.200	1.236	V
V <sub>PS_MGTRAVCC</sub>	PS-GTR supply voltage.	0.825	0.850	0.875	V
V <sub>PS_MGTRAVTT</sub>	PS-GTR termination voltage.	1.746	1.800	1.854	V
V <sub>CCO_PSDDR</sub> <sup>(4)</sup>	PS DDR I/O supply voltage.	1.06	–	1.575	V
V <sub>CCO_PSDDR_PLL</sub>	PS DDR PLL supply voltage.	1.710	1.800	1.890	V
V <sub>CCO_PSIO</sub> <sup>(5)</sup>	PS I/O supply.	1.710	–	3.465	V
V <sub>PSIN</sub>	PS I/O input voltage.	-0.200	–	$V_{CCO_PSIO} + 0.200$	V
	PS DDR I/O input voltage.	-0.200	–	$V_{CCO_PSDDR} + 0.200$	
V <sub>CC_PSBATT</sub> <sup>(6)</sup>	PS battery-backed RAM and battery-backed real-time clock (RTC) supply voltage.	1.200	–	1.500	V
<b>Programmable Logic</b>					
V <sub>CCINT</sub>	PL internal supply voltage.	0.825	0.850	0.876	V
	For -1LI and -2LE ( $V_{CCINT} = 0.72V$ ) devices: PL internal supply voltage.	0.698	0.720	0.742	V
	For -3E devices: PL internal supply voltage.	0.873	0.900	0.927	V
V <sub>CCINT_IO</sub> <sup>(7)</sup>	PL internal supply voltage for the I/O banks.	0.825	0.850	0.876	V
	For -1LI and -2LE ( $V_{CCINT} = 0.72V$ ) devices: PL internal supply voltage for the I/O banks.	0.825	0.850	0.876	V
	For -3E devices: PL internal supply voltage for the I/O banks.	0.873	0.900	0.927	V
V <sub>CCBRAM</sub>	Block RAM supply voltage.	0.825	0.850	0.876	V
	For -3E devices: block RAM supply voltage.	0.873	0.900	0.927	V
V <sub>CCAUX</sub>	Auxiliary supply voltage.	1.746	1.800	1.854	V

Table 2: Recommended Operating Conditions<sup>(1)(2)</sup> (Cont'd)

Symbol	Description	Min	Typ	Max	Units
$V_{CCO}^{(8)}$	Supply voltage for HD I/O banks.	1.140	–	3.400	V
	Supply voltage for HP I/O banks.	0.950	–	1.900	V
$V_{CCAUX\_IO}^{(9)}$	Auxiliary I/O supply voltage.	1.746	1.800	1.854	V
$V_{IN}^{(10)}$	I/O input voltage.	-0.200	–	$V_{CCO} + 0.200$	V
$I_{IN}^{(11)}$	Maximum current through any PL or PS pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
<b>GTH or GTY Transceiver</b>					
$V_{MGTAVCC}^{(12)}$	Analog supply voltage for the GTH or GTY transceiver.	0.873	0.900	0.927	V
$V_{MGTAVTT}^{(12)}$	Analog supply voltage for the GTH or GTY transmitter and receiver termination circuits.	1.164	1.200	1.236	V
$V_{MGTVCCAUX}^{(12)}$	Auxiliary analog QPLL voltage supply for the transceivers.	1.746	1.800	1.854	V
$V_{MGTAVTRCAL}^{(12)}$	Analog supply voltage for the resistor calibration circuit of the GTH or GTY transceiver column.	1.164	1.200	1.236	V
<b>VCU</b>					
$V_{CCINT\_VCU}$	Internal supply voltage for the VCU.	0.825	0.850	0.876	V
	For -1LI and -2LE ( $V_{CCINT} = 0.72V$ ) devices: Internal supply voltage for the VCU.	0.825	0.850	0.876	V
	For -3E devices: Internal supply voltage for the VCU.	0.873	0.900	0.927	V

Table 2: Recommended Operating Conditions<sup>(1)(2)</sup> (Cont'd)

Symbol	Description	Min	Typ	Max	Units
<b>PL System Monitor</b>					
V <sub>CCADC</sub>	PL System Monitor supply relative to GNDADC.	1.746	1.800	1.854	V
V <sub>REFP</sub>	PL System Monitor externally supplied reference voltage relative to GNDADC.	1.200	1.250	1.300	V
<b>Temperature</b>					
T <sub>j</sub> <sup>(13)</sup>	Junction temperature operating range for extended (E) temperature devices. <sup>(14)</sup>	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices.	-40	–	100	°C
	Junction temperature operating range for eFUSE programming.	-40	–	125	°C

**Notes:**

1. All voltages are relative to GND.
2. For the design of the power distribution system consult *UltraScale Architecture PCB Design Guide* ([UG583](#)).
3. V<sub>CC\_PSINTFP\_DDR</sub> must be tied to V<sub>CC\_PSINTFP</sub>.
4. Includes V<sub>CCO\_PSDDR</sub> of 1.2V, 1.35V, 1.5V at ±5% and 1.1V +0.07V/-0.04V depending upon the tolerances required by specific memory standards.
5. Applies to all PS I/O supply banks. Includes V<sub>CCO\_PSI0</sub> of 1.8V, 2.5V, and 3.3V at ±5%.
6. If the battery-backed RAM or RTC is not used, connect V<sub>CC\_PSBATT</sub> to GND or V<sub>CC\_PSAUX</sub>. The V<sub>CC\_PSAUX</sub> maximum of 1.89V is acceptable on an unused V<sub>CC\_PSBATT</sub>.
7. V<sub>CCINT\_IO</sub> must be connected to V<sub>CCBRAM</sub>.
8. Includes V<sub>CCO</sub> of 1.0V (HP I/O only), 1.2V, 1.35V, 1.5V, 1.8V, 2.5V (HD I/O only) at ±5%, and 3.3V (HD I/O only) at +3/-5%.
9. V<sub>CCAUX\_IO</sub> must be connected to V<sub>CCAUX</sub>.
10. The lower absolute voltage specification always applies.
11. A total of 200 mA per bank should not be exceeded.
12. Each voltage listed requires filtering as described in *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) or *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)).
13. Xilinx recommends measuring the T<sub>j</sub> of a device using the system monitor as described in the *UltraScale Architecture System Monitor User Guide* ([UG580](#)). The SYSMON temperature measurement errors (that are described in [Table 69](#) and [Table 124](#)) must be accounted for in your design. For example, when using the PL system monitor with an external reference of 1.25V, when SYSMON reports 97°C, there is a measurement error ±3°C. A reading of 97°C is considered the maximum adjusted T<sub>j</sub> (100°C – 3°C = 97°C).
14. Devices labeled with the speed/temperature grade of -2LE normally operate under Extended (E) temperature grade specifications with a maximum junction temperature of 100°C. However, E temperature grade devices can operate for a limited time at a junction temperature of 110°C. Timing parameters adhere to the same speed file at 110°C as they do at 100°C, regardless of operating voltage (nominal voltage of 0.85V or a low-voltage of 0.72V). Operation at T<sub>j</sub> = 110°C is limited to 1% of the device lifetime and can occur sequentially or at regular intervals as long as the total time does not exceed 1% of the device lifetime.

## Available Speed Grades and Operating Voltages

**Table 3** describes the speed grades per device and the  $V_{CCINT}$  operating supply voltages for the full-power, low-power, and DDR domains. For more information on selecting devices and speed grades, see the *UltraScale Architecture and Product Overview* ([DS890](#)).

**Table 3: Available Speed Grades and Operating Voltages**

Speed Grade	$V_{CCINT}$	$V_{CC\_PSINTLP}$	$V_{CC\_PSINTFP}$	$V_{CC\_PSINTFP\_DDR}$	Units
-3E	0.90	0.90	0.90	0.90	V
-2E	0.85	0.85	0.85	0.85	V
-2I	0.85	0.85	0.85	0.85	V
-2LE	0.85	0.85	0.85	0.85	V
-1E	0.85	0.85	0.85	0.85	V
-1I	0.85	0.85	0.85	0.85	V
-1LI	0.85	0.85	0.85	0.85	V
-2LE	0.72	0.85	0.85	0.85	V
-1LI	0.72	0.85	0.85	0.85	V

## DC Characteristics Over Recommended Operating Conditions

**Table 4: DC Characteristics Over Recommended Operating Conditions**

Symbol	Description	Min	Typ <sup>(1)</sup>	Max	Units
$V_{DRINT}$	Data retention $V_{CCINT}$ voltage (below which configuration data might be lost).	0.68	—	—	V
$V_{DRAUX}$	Data retention $V_{CCAUX}$ voltage (below which configuration data might be lost).	1.5	—	—	V
$I_{REF}$	$V_{REF}$ leakage current per pin.	—	—	15	$\mu A$
$I_L$	Input or output leakage current per pin (sample-tested). <sup>(2)</sup>	—	—	15	$\mu A$
$C_{IN}^{(3)}$	Die input capacitance at the pad (HP I/O).	—	—	3.1	pF
	Die input capacitance at the pad (HD I/O).	—	—	4.75	pF
$I_{RPU}$	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO} = 3.3V$ .	75	—	190	$\mu A$
	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO} = 2.5V$ .	50	—	169	$\mu A$
	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO} = 1.8V$ .	60	—	120	$\mu A$
	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO} = 1.5V$ .	30	—	120	$\mu A$
	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO} = 1.2V$ .	10	—	100	$\mu A$
$I_{RPD}$	Pad pull-down (when selected) at $V_{IN} = 3.3V$ .	60	—	200	$\mu A$
	Pad pull-down (when selected) at $V_{IN} = 1.8V$ .	29	—	120	$\mu A$
$I_{CCADCONPL}$	Analog supply current for the PL SYSMON circuits in the power-up state.	—	—	8	mA
$I_{CCADCONPS}$	Analog supply current for the PS SYSMON circuits in the power-up state.	—	—	10	mA
$I_{CCADCOFFPL}$	Analog supply current for the PL SYSMON circuits in the power-down state.	—	—	1.5	mA
$I_{CCADCOFFPS}$	Analog supply current for the PS SYSMON circuits in the power-down state.	—	—	1.8	mA

Table 4: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ <sup>(1)</sup>	Max	Units
$I_{CC\_PSBATT}^{(4)(5)}$	Battery supply current at $V_{CC\_PSBATT} = 1.50V$ , RTC enabled.	–	–	3650	nA
	Battery supply current at $V_{CC\_PSBATT} = 1.50V$ , RTC disabled.	–	–	650	nA
	Battery supply current at $V_{CC\_PSBATT} = 1.20V$ , RTC enabled.	–	–	3150	nA
	Battery supply current at $V_{CC\_PSBATT} = 1.20V$ , RTC disabled.	–	–	150	nA
$I_{PSFS}^{(6)}$	PS $V_{CC\_PSAUX}$ additional supply current during eFUSE programming.	–	–	115	mA
Calibrated programmable on-die termination (DCI) in HP I/O banks <sup>(8)</sup> (measured per JEDEC specification)					
$R^{(9)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_40.	–10% <sup>(7)</sup>	40	+10% <sup>(7)</sup>	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_48.	–10% <sup>(7)</sup>	48	+10% <sup>(7)</sup>	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_60.	–10% <sup>(7)</sup>	60	+10% <sup>(7)</sup>	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_40.	–10% <sup>(7)</sup>	40	+10% <sup>(7)</sup>	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_48.	–10% <sup>(7)</sup>	48	+10% <sup>(7)</sup>	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_60.	–10% <sup>(7)</sup>	60	+10% <sup>(7)</sup>	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_120.	–10% <sup>(7)</sup>	120	+10% <sup>(7)</sup>	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_240.	–10% <sup>(7)</sup>	240	+10% <sup>(7)</sup>	$\Omega$
Uncalibrated programmable on-die termination in HP I/Os banks (measured per JEDEC specification)					
$R^{(9)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_40.	–50%	40	+50%	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_48.	–50%	48	+50%	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_60.	–50%	60	+50%	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_40.	–50%	40	+50%	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_48.	–50%	48	+50%	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_60.	–50%	60	+50%	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_120.	–50%	120	+50%	$\Omega$
	Programmable input termination to $V_{CCO}$ where ODT = RTT_240.	–50%	240	+50%	$\Omega$
Uncalibrated programmable on-die termination in HD I/O banks (measured per JEDEC specification)					
$R^{(9)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ where ODT = RTT_48.	–50%	48	+50%	$\Omega$
Internal $V_{REF}$	50% $V_{CCO}$	$V_{CCO} \times 0.49$	$V_{CCO} \times 0.50$	$V_{CCO} \times 0.51$	V
	70% $V_{CCO}$	$V_{CCO} \times 0.69$	$V_{CCO} \times 0.70$	$V_{CCO} \times 0.71$	V

Table 4: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ <sup>(1)</sup>	Max	Units
Differential termination	Programmable differential termination (TERM_100) for HP I/O banks.	-35%	100	+35%	Ω
n	Temperature diode ideality factor.	-	1.026	-	-
r	Temperature diode series resistance.	-	2	-	Ω

**Notes:**

1. Typical values are specified at nominal voltage, 25°C.
2. For HP I/O banks with a  $V_{CCO}$  of 1.8V and separated  $V_{CCO}$  and  $V_{CCAUX\_IO}$  power supplies, the  $I_L$  maximum current is 70 μA.
3. This measurement represents the die capacitance at the pad, not including the package.
4. Maximum value specified for worst case process at 25°C.
5.  $I_{CC\_PSBATT}$  is measured when the battery-backed RAM (BBRAM) is enabled.
6. Do not program eFUSE during device configuration (e.g., during configuration, during configuration readback, or when readback CRC is active).
7. If VRP resides at a different bank (DCI cascade), the range increases to ±15%.
8. VRP resistor tolerance is (240Ω ±1%)
9. On-die input termination resistance, for more information see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 5: PS MIO Pull-up and Pull-down Current

Symbol	Description	Min	Max	Units
$I_{RPU}$	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO\_PSMIO} = 3.3V$ .	20	80	μA
	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO\_PSMIO} = 2.5V$ .	20	80	μA
	Pad pull-up (when selected) at $V_{IN} = 0V$ , $V_{CCO\_PSMIO} = 1.8V$ .	15	65	μA
$I_{RPD}$	Pad pull-down (when selected) at $V_{IN} = 3.3V$ .	20	80	μA
	Pad pull-down (when selected) at $V_{IN} = 2.5V$ .	20	80	μA
	Pad pull-down (when selected) at $V_{IN} = 1.8V$ .	15	65	μA

## V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot

Table 6: V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot for HD I/O Banks<sup>(1)</sup>

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
V <sub>CCO</sub> + 0.30	100%	-0.30	100%
V <sub>CCO</sub> + 0.35	100%	-0.35	90%
V <sub>CCO</sub> + 0.40	100%	-0.40	78%
V <sub>CCO</sub> + 0.45	100%	-0.45	40%
V <sub>CCO</sub> + 0.50	100%	-0.50	24%
V <sub>CCO</sub> + 0.55	100%	-0.55	18.0%
V <sub>CCO</sub> + 0.60	100%	-0.60	13.0%
V <sub>CCO</sub> + 0.65	100%	-0.65	10.8%
V <sub>CCO</sub> + 0.70	92%	-0.70	9.0%
V <sub>CCO</sub> + 0.75	92%	-0.75	7.0%
V <sub>CCO</sub> + 0.80	92%	-0.80	6.0%
V <sub>CCO</sub> + 0.85	92%	-0.85	5.0%
V <sub>CCO</sub> + 0.90	92%	-0.90	4.0%
V <sub>CCO</sub> + 0.95	92%	-0.95	2.5%

**Notes:**

1. A total of 200 mA per bank should not be exceeded.

Table 7: V<sub>IN</sub> Maximum Allowed AC Voltage Overshoot and Undershoot for HP I/O Banks<sup>(1)(2)</sup>

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
V <sub>CCO</sub> + 0.30	100%	-0.30	100%
V <sub>CCO</sub> + 0.35	100%	-0.35	100%
V <sub>CCO</sub> + 0.40	92%	-0.40	92%
V <sub>CCO</sub> + 0.45	50%	-0.45	50%
V <sub>CCO</sub> + 0.50	20%	-0.50	20%
V <sub>CCO</sub> + 0.55	10%	-0.55	10%
V <sub>CCO</sub> + 0.60	6%	-0.60	6%
V <sub>CCO</sub> + 0.65	2%	-0.65	2%
V <sub>CCO</sub> + 0.70	2%	-0.70	2%

**Notes:**

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20  $\mu$ s.

Table 8:  $V_{PSIN}$  Maximum Allowed AC Voltage Overshoot and Undershoot for PS I/O Banks<sup>(1)</sup>

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
$V_{CCO\_PSIO} + 0.30$	100%	-0.30	100%
$V_{CCO\_PSIO} + 0.35$	100%	-0.35	75%
$V_{CCO\_PSIO} + 0.40$	100%	-0.40	45%
$V_{CCO\_PSIO} + 0.45$	100%	-0.45	40%
$V_{CCO\_PSIO} + 0.50$	75%	-0.50	10%
$V_{CCO\_PSIO} + 0.55$	75%	-0.55	6%
$V_{CCO\_PSIO} + 0.60$	60%	-0.60	2%
$V_{CCO\_PSIO} + 0.65$	30%	-0.65	0%
$V_{CCO\_PSIO} + 0.70$	20%	-0.70	0%
$V_{CCO\_PSIO} + 0.75$	10%	-0.75	0%
$V_{CCO\_PSIO} + 0.80$	10%	-0.80	0%
$V_{CCO\_PSIO} + 0.85$	8%	-0.85	0%
$V_{CCO\_PSIO} + 0.90$	6%	-0.90	0%
$V_{CCO\_PSIO} + 0.95$	6%	-0.95	0%

**Notes:**

1. A total of 200 mA per bank should not be exceeded.

## Quiescent Supply Current

Table 9: Typical Quiescent Supply Current<sup>(1)(2)(3)(4)</sup>

Symbol	Description	Device	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units		
			0.90V		0.85V		0.72V			
			-3	-2	-1	-2	-1			
I <sub>CCINTQ</sub>	Quiescent V <sub>CCINT</sub> supply current.	XCZU2	N/A	393	393	344	344	mA		
		XCZU3	N/A	393	393	344	344	mA		
		XCZU4	719	684	684	601	601	mA		
		XCZU5	719	684	684	601	601	mA		
		XCZU6	1629	1549	1549	1358	1358	mA		
		XCZU7	1263	1201	1201	1055	1055	mA		
		XCZU9	1629	1549	1549	1358	1358	mA		
		XCZU11	1786	1699	1699	1491	1491	mA		
		XCZU15	1987	1890	1890	1660	1660	mA		
		XCZU17	2728	2594	2594	2275	2275	mA		
I <sub>CCINT_IOQ</sub>	Quiescent V <sub>CCINT_IO</sub> supply current.	XCZU19	2728	2594	2594	2275	2275	mA		
		XCZU2	N/A	44	44	44	44	mA		
		XCZU3	N/A	44	44	44	44	mA		
		XCZU4	61	59	59	59	59	mA		
		XCZU5	61	59	59	59	59	mA		
		XCZU6	61	59	59	59	59	mA		
		XCZU7	120	115	115	115	115	mA		
		XCZU9	61	59	59	59	59	mA		
		XCZU11	120	115	115	115	115	mA		
		XCZU15	61	59	59	59	59	mA		
I <sub>CCOQ</sub>	Quiescent V <sub>CCO</sub> supply current.	XCZU17	164	158	158	158	158	mA		
		XCZU19	164	158	158	158	158	mA		
I <sub>CCAUXQ</sub>	Quiescent V <sub>CCAUX</sub> supply current.	All devices	1	1	1	1	1	mA		
		XCZU2	N/A	55	55	55	55	mA		
		XCZU3	N/A	55	55	55	55	mA		
		XCZU4	90	90	90	90	90	mA		
		XCZU5	90	90	90	90	90	mA		
		XCZU6	227	227	227	227	227	mA		
		XCZU7	174	174	174	174	174	mA		
		XCZU9	227	227	227	227	227	mA		
		XCZU11	255	255	255	255	255	mA		
		XCZU15	266	266	266	266	266	mA		
		XCZU17	396	396	396	396	396	mA		
		XCZU19	396	396	396	396	396	mA		

Table 9: Typical Quiescent Supply Current<sup>(1)(2)(3)(4)</sup> (Cont'd)

Symbol	Description	Device	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units		
			0.90V		0.85V		0.72V			
			-3	-2	-1	-2	-1			
I <sub>CCAUX_IOQ</sub>	Quiescent V <sub>CCAUX_IO</sub> supply current.	XCZU2	N/A	26	26	26	26	mA		
		XCZU3	N/A	26	26	26	26	mA		
		XCZU4	32	32	32	32	32	mA		
		XCZU5	32	32	32	32	32	mA		
		XCZU6	33	33	33	33	33	mA		
		XCZU7	56	56	56	56	56	mA		
		XCZU9	33	33	33	33	33	mA		
		XCZU11	56	56	56	56	56	mA		
		XCZU15	33	33	33	33	33	mA		
		XCZU17	74	74	74	74	74	mA		
I <sub>CCBRAMQ</sub>	Quiescent V <sub>CCBRAM</sub> supply current.	XCZU2	N/A	6	6	6	6	mA		
		XCZU3	N/A	6	6	6	6	mA		
		XCZU4	9	9	9	9	9	mA		
		XCZU5	9	9	9	9	9	mA		
		XCZU6	25	24	24	24	24	mA		
		XCZU7	16	15	15	15	15	mA		
		XCZU9	25	24	24	24	24	mA		
		XCZU11	23	22	22	22	22	mA		
		XCZU15	29	28	28	28	28	mA		
		XCZU17	37	35	35	35	35	mA		
		XCZU19	37	35	35	35	35	mA		

**Notes:**

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T<sub>j</sub>) with single-ended SelectIO™ resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at [www.xilinx.com/power](http://www.xilinx.com/power)) to estimate static power consumption for conditions or supplies other than those specified.
4. Typical values depend upon your configuration. To accurately estimate all PS supply currents, use the interactive XPE spreadsheet tool.

# Power Supply Sequencing

## PS Power-On/Off Power Supply Sequencing

The low-power domain (LPD) must operate before the full-power domain (FPD) can function. The low-power and full-power domains can be powered simultaneously. The PS\_POR\_B input must be asserted to GND during the power-on sequence (see [Table 37](#)). The FPD (when used) must be powered before PS\_POR\_B is released.

To achieve minimum current draw and ensure that the I/Os are 3-stated at power-on, the recommended power-on sequence for the low-power domain (LPD) is listed. The recommended power-off sequence is the reverse of the power-on sequence.

1.  $V_{CC\_PSINTLP}$
2.  $V_{CC\_PSAUX}$ ,  $V_{CC\_PSADC}$ , and  $V_{CC\_PSPLL}$  in any order or simultaneously.
3.  $V_{CCO\_PSIO}$

To achieve minimum current draw and ensure that the I/Os are 3-stated at power-on, the recommended power-on sequence for the full-power domain (FPD) is listed. The recommended power-off sequence is the reverse of the power-on sequence.

1.  $V_{CC\_PSINTFP}$  and  $V_{CC\_PSINTFP\_DDR}$  driven from the same supply source.
2.  $V_{PS\_MGTRAVCC}$  and  $V_{CC\_PSDDR\_PLL}$  in any order or simultaneously.
3.  $V_{PS\_MGTRAVTT}$  and  $V_{CCO\_PSDDR}$  in any order or simultaneously.

## PL Power-On/Off Power Supply Sequencing

The recommended power-on sequence is  $V_{CCINT}$ ,  $V_{CCINT\_IO}/V_{CCBRAM}/V_{CCINT\_VCU}$ ,  $V_{CCAUX}/V_{CCAUX\_IO}$ , and  $V_{CCO}$  to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If  $V_{CCINT}$  and  $V_{CCINT\_IO}/V_{CCBRAM}$  have the same recommended voltage levels, they can be powered by the same supply and ramped simultaneously.  $V_{CCINT\_IO}$  must be connected to  $V_{CCBRAM}$ . If  $V_{CCAUX}/V_{CCAUX\_IO}$  and  $V_{CCO}$  have the same recommended voltage levels, they can be powered by the same supply and ramped simultaneously.  $V_{CCAUX}$  and  $V_{CCAUX\_IO}$  must be connected together.  $V_{CCADC}$  and  $V_{REF}$  can be powered at any time and have no power-up sequencing requirements.

The recommended power-on sequence to achieve minimum current draw for the GTH or GTY transceivers is  $V_{CCINT}$ ,  $V_{MGTAVCC}$ ,  $V_{MGTAVTT}$  OR  $V_{MGTAVCC}$ ,  $V_{CCINT}$ ,  $V_{MGTAVTT}$ . There is no recommended sequencing for  $V_{MGTAVCCAUX}$ . Both  $V_{MGTAVCC}$  and  $V_{CCINT}$  can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from  $V_{MGTAVTT}$  can be higher than specifications during power-up and power-down.

## PS-PL Power Sequencing

The PS and PL power supplies are fully independent. All PS power supplies can be powered before or after any PL power supplies. The PS and PL power regions are isolated to prevent damage.

## Power Supply Requirements

[Table 10](#) shows the minimum current, in addition to  $I_{CCQ}$  maximum, required by each Zynq UltraScale+ device for proper power-on and configuration. If the current minimums shown in [Table 10](#) are met, the device powers on after all supplies have passed through their power-on reset threshold voltages. The device must not be configured until after  $V_{CCINT}$  is applied. Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

[Table 10: Power-on Current by Device](#) <sup>(1)</sup>

$I_{CC}$ Min =	$I_{CCQ} +$	XCZU2	XCZU3	XCZU4	XCZU5	XCZU6	XCZU7	XCZU9	XCZU11	XCZU15	XCZU17	XCZU19	Units
$I_{CCINTMIN}$	$I_{CCINTQ} +$	464	464	770	770	1800	1514	1800	1961	2242	3433	3433	mA
$I_{CCINT\_JOMIN} +$ $I_{CCBRAMMIN}$	$I_{CCBRAMQ} +$ $I_{CCINT\_IOQ} +$	155	155	257	257	600	505	600	654	748	1145	1145	mA
$I_{CCOMIN}$	$I_{CCOQ} +$	50	50	50	50	50	50	50	55	63	96	96	mA
$I_{CCAUXMIN} +$ $I_{CCAUX\_IOMIN}$	$I_{CCAUXQ} +$ $I_{CCAUX\_IOQ} +$	111	111	386	386	650	362	650	709	810	1240	1240	mA

### Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at [www.xilinx.com/power](http://www.xilinx.com/power)) to estimate power-on current for all supplies.

[Table 11](#) shows the power supply ramp time.

[Table 11: Power Supply Ramp Time](#)

Symbol	Description	Min	Max	Units
$T_{VCCINT}$	Ramp time from GND to 95% of $V_{CCINT}$ .	0.2	40	ms
$T_{VCCINT\_IO}$	Ramp time from GND to 95% of $V_{CCINT\_IO}$ .	0.2	40	ms
$T_{VCCINT\_VCU}$	Ramp time from GND to 95% of $V_{CCINT\_VCU}$ .	0.2	40	ms
$T_{VCCO}$	Ramp time from GND to 95% of $V_{CCO}$ .	0.2	40	ms
$T_{VCCAUX}$	Ramp time from GND to 95% of $V_{CCAUX}$ .	0.2	40	ms
$T_{VCCBRAM}$	Ramp time from GND to 95% of $V_{CCBRAM}$ .	0.2	40	ms
$T_{MGTAVCC}$	Ramp time from GND to 95% of $V_{MGTAVCC}$ .	0.2	40	ms
$T_{MGTAVTT}$	Ramp time from GND to 95% of $V_{MGTAVTT}$ .	0.2	40	ms
$T_{MGTVCVAUX}$	Ramp time from GND to 95% of $V_{MGTVCVAUX}$ .	0.2	40	ms
$T_{VCC\_PSINTFP}$	Ramp time from GND to 95% of $V_{CC\_PSINTFP}$ .	0.2	40	ms
$T_{VCC\_PSINTLP}$	Ramp time from GND to 95% of $V_{CC\_PSINTLP}$ .	0.2	40	ms
$T_{VCC\_PSAUX}$	Ramp time from GND to 95% of $V_{CC\_PSAUX}$ .	0.2	40	ms
$T_{VCC\_PSINTFP\_DDR}$	Ramp time from GND to 95% of $V_{CC\_PSINTFP\_DDR}$ .	0.2	40	ms
$T_{VCC\_PSADC}$	Ramp time from GND to 95% of $V_{CC\_PSADC}$ .	0.2	40	ms
$T_{VCC\_PSPLL}$	Ramp time from GND to 95% of $V_{CC\_PSPLL}$ .	0.2	40	ms
$T_{PS\_MGTRAVCC}$	Ramp time from GND to 95% of $V_{CC\_MGTRAVCC}$ .	0.2	40	ms
$T_{PS\_MGTRAVTT}$	Ramp time from GND to 95% of $V_{CC\_MGTRAVTT}$ .	0.2	40	ms

Table 11: Power Supply Ramp Time (Cont'd)

Symbol	Description	Min	Max	Units
T <sub>VCCO_PSDDR</sub>	Ramp time from GND to 95% of V <sub>CCO_PSDDR</sub> .	0.2	40	ms
T <sub>VCC_PSDDR_PLL</sub>	Ramp time from GND to 95% of V <sub>CC_PSDDR_PLL</sub> .	0.2	40	ms
T <sub>VCCO_PSIO</sub>	Ramp time from GND to 95% of V <sub>CCO_PSIO</sub> .	0.2	40	ms

## DC Input and Output Levels

Values for V<sub>IL</sub> and V<sub>IH</sub> are recommended input voltages. Values for I<sub>OL</sub> and I<sub>OH</sub> are guaranteed over the recommended operating conditions at the V<sub>OL</sub> and V<sub>OH</sub> test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V<sub>CCO</sub> with the respective V<sub>OL</sub> and V<sub>OH</sub> voltage levels shown. Other standards are sample tested.

## PS I/O Levels

Table 12: PS MIO and CONFIG DC Input and Output Levels<sup>(1)</sup>

I/O Standard	V <sub>IL</sub>		V <sub>IH</sub>		V <sub>OL</sub>	V <sub>OH</sub>	I <sub>OL</sub>	I <sub>OH</sub>
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVCMOS33	-0.300	0.800	2.000	V <sub>CCO_PSIO</sub>	0.40	2.40	12	-12
LVCMOS25	-0.300	0.700	1.700	V <sub>CCO_PSIO</sub> + 0.30	0.70	1.70	12	-12
LVCMOS18	-0.300	35% V <sub>CCO_PSIO</sub>	65% V <sub>CCO_PSIO</sub>	V <sub>CCO_PSIO</sub> + 0.30	0.45	V <sub>CCO_PSIO</sub> - 0.45	12	-12

### Notes:

- Tested according to relevant specifications.

Table 13: PS DDR DC Input and Output Levels<sup>(1)</sup>

DDR Standard	V <sub>IL</sub>		V <sub>IH</sub>		V <sub>OL</sub> <sup>(2)</sup>		V <sub>OH</sub> <sup>(2)</sup>		I <sub>OL</sub>	I <sub>OH</sub>
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA		
DDR4	0.000	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO_PSDDR</sub>	0.8 x V <sub>CCO_PSDDR</sub> - 0.150	0.8 x V <sub>CCO_PSDDR</sub> + 0.150	10	-0.1		
LPDDR4	0.000	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO_PSDDR</sub>	0.3 x V <sub>CCO_PSDDR</sub> - 0.150	0.3 x V <sub>CCO_PSDDR</sub> + 0.150	0.1	-10		
DDR3	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO_PSDDR</sub>	0.5 x V <sub>CCO_PSDDR</sub> - 0.175	0.5 x V <sub>CCO_PSDDR</sub> + 0.175	8	-8		
LPDDR3	0.000	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO_PSDDR</sub>	0.5 x V <sub>CCO_PSDDR</sub> - 0.150	0.5 x V <sub>CCO_PSDDR</sub> + 0.150	8	-8		
DDR3L	-0.300	V <sub>REF</sub> - 0.090	V <sub>REF</sub> + 0.090	V <sub>CCO_PSDDR</sub>	0.5 x V <sub>CCO_PSDDR</sub> - 0.150	0.5 x V <sub>CCO_PSDDR</sub> + 0.150	8	-8		

### Notes:

- Tested according to relevant specifications.
- DDR4 V<sub>OL</sub>/V<sub>OH</sub> specifications are only applicable for DQ/DQS pins.

## PL I/O Levels

Table 14: SelectIO DC Input and Output Levels For HD I/O Banks<sup>(1)(2)(3)</sup>

I/O Standard	V <sub>IL</sub>		V <sub>IH</sub>		V <sub>OL</sub>	V <sub>OH</sub>	I <sub>OL</sub>	I <sub>OH</sub>
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
HSTL_I	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	8.0	-8.0
HSTL_I_18	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	8.0	-8.0
HSUL_12	-0.300	V <sub>REF</sub> - 0.130	V <sub>REF</sub> + 0.130	V <sub>CCO</sub> + 0.300	20% V <sub>CCO</sub>	80% V <sub>CCO</sub>	0.1	-0.1
LVCMOS12	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	Note 4	Note 4
LVCMOS15	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.450	V <sub>CCO</sub> - 0.450	Note 5	Note 5
LVCMOS18	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.450	V <sub>CCO</sub> - 0.450	Note 5	Note 5
LVCMOS25	-0.300	0.700	1.700	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	Note 5	Note 5
LVCMOS33	-0.300	0.800	2.000	3.400	0.400	V <sub>CCO</sub> - 0.400	Note 5	Note 5
LVTTL	-0.300	0.800	2.000	3.400	0.400	2.400	Note 5	Note 5
SSTL12	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.150	V <sub>CCO</sub> /2 + 0.150	14.25	-14.25
SSTL135	-0.300	V <sub>REF</sub> - 0.090	V <sub>REF</sub> + 0.090	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.150	V <sub>CCO</sub> /2 + 0.150	8.9	-8.9
SSTL135_II	-0.300	V <sub>REF</sub> - 0.090	V <sub>REF</sub> + 0.090	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.150	V <sub>CCO</sub> /2 + 0.150	13.0	-13.0
SSTL15	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.175	V <sub>CCO</sub> /2 + 0.175	8.9	-8.9
SSTL15_II	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.175	V <sub>CCO</sub> /2 + 0.175	13.0	-13.0
SSTL18_I	-0.300	V <sub>REF</sub> - 0.125	V <sub>REF</sub> + 0.125	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.470	V <sub>CCO</sub> /2 + 0.470	8.0	-8.0
SSTL18_II	-0.300	V <sub>REF</sub> - 0.125	V <sub>REF</sub> + 0.125	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.600	V <sub>CCO</sub> /2 + 0.600	13.4	-13.4
MIPI_DPHY_DCI_LP <sup>(6)</sup>	-0.300	0.550	0.880	V <sub>CCO</sub> + 0.300	0.050	1.100	0.01	-0.01

### Notes:

- Tested according to relevant specifications.
- Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).
- POD10 and POD12 DC input and output levels are shown in [Table 16](#), [Table 20](#), [Table 21](#), and [Table 22](#).
- Supported drive strengths of 4, 8, or 12 mA in HD I/O banks.
- Supported drive strengths of 4, 8, 12, or 16 mA in HD I/O banks.
- Low-power option for MIPI\_DPHY\_DCI.

Table 15: SelectIO DC Input and Output Levels for HP I/O Banks<sup>(1)(2)(3)</sup>

I/O Standard	V <sub>IL</sub>		V <sub>IH</sub>		V <sub>OL</sub>	V <sub>OH</sub>	I <sub>OL</sub>	I <sub>OH</sub>
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
HSTL_I	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	5.8	-5.8
HSTL_I_12	-0.300	V <sub>REF</sub> - 0.080	V <sub>REF</sub> + 0.080	V <sub>CCO</sub> + 0.300	25% V <sub>CCO</sub>	75% V <sub>CCO</sub>	4.1	-4.1
HSTL_I_18	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	6.2	-6.2
HSUL_12	-0.300	V <sub>REF</sub> - 0.130	V <sub>REF</sub> + 0.130	V <sub>CCO</sub> + 0.300	20% V <sub>CCO</sub>	80% V <sub>CCO</sub>	0.1	-0.1
LVCMOS12	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.400	V <sub>CCO</sub> - 0.400	Note 4	Note 4
LVCMOS15	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.450	V <sub>CCO</sub> - 0.450	Note 5	Note 5
LVCMOS18	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.450	V <sub>CCO</sub> - 0.450	Note 5	Note 5
LVDCI_15	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.450	V <sub>CCO</sub> - 0.450	7.0	-7.0
LVDCI_18	-0.300	35% V <sub>CCO</sub>	65% V <sub>CCO</sub>	V <sub>CCO</sub> + 0.300	0.450	V <sub>CCO</sub> - 0.450	7.0	-7.0
SSTL12	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.150	V <sub>CCO</sub> /2 + 0.150	8.0	-8.0
SSTL135	-0.300	V <sub>REF</sub> - 0.090	V <sub>REF</sub> + 0.090	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.150	V <sub>CCO</sub> /2 + 0.150	9.0	-9.0
SSTL15	-0.300	V <sub>REF</sub> - 0.100	V <sub>REF</sub> + 0.100	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.175	V <sub>CCO</sub> /2 + 0.175	10.0	-10.0
SSTL18_I	-0.300	V <sub>REF</sub> - 0.125	V <sub>REF</sub> + 0.125	V <sub>CCO</sub> + 0.300	V <sub>CCO</sub> /2 - 0.470	V <sub>CCO</sub> /2 + 0.470	7.0	-7.0
MIPI_DPHY_DCI_LP <sup>(6)</sup>	-0.300	0.550	0.880	V <sub>CCO</sub> + 0.300	0.050	1.100	0.01	-0.01

**Notes:**

- Tested according to relevant specifications.
- Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).
- POD10 and POD12 DC input and output levels are shown in [Table 16](#), [Table 20](#), [Table 21](#), and [Table 22](#).
- Supported drive strengths of 2, 4, 6, or 8 mA in HP I/O banks.
- Supported drive strengths of 2, 4, 6, 8, or 12 mA in HP I/O banks.
- Low-power option for MIPI\_DPHY\_DCI.

Table 16: DC Input Levels for Single-ended POD10 and POD12 I/O Standards<sup>(1)(2)</sup>

I/O Standard	V <sub>IL</sub>		V <sub>IH</sub>	
	V, Min	V, Max	V, Min	V, Max
POD10	-0.300	V <sub>REF</sub> - 0.068	V <sub>REF</sub> + 0.068	V <sub>CCO</sub> + 0.300
POD12	-0.300	V <sub>REF</sub> - 0.068	V <sub>REF</sub> + 0.068	V <sub>CCO</sub> + 0.300

**Notes:**

- Tested according to relevant specifications.
- Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 17: Differential SelectIO DC Input and Output Levels

I/O Standard	V <sub>ICM</sub> (V) <sup>(1)</sup>			V <sub>ID</sub> (V) <sup>(2)</sup>			V <sub>ILHS</sub> <sup>(3)</sup>	V <sub>IHHS</sub> <sup>(3)</sup>	V <sub>OCM</sub> (V) <sup>(4)</sup>			V <sub>OD</sub> (V) <sup>(5)</sup>		
	Min	Typ	Max	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max
SUB_LVDS <sup>(8)</sup>	0.500	0.900	1.300	0.070	—	—	—	—	0.700	0.900	1.100	0.100	0.150	0.200
LVPECL	0.300	1.200	1.425	0.100	0.350	0.600	—	—	—	—	—	—	—	—
SLVS_400_18	0.070	0.200	0.330	0.140	—	0.450	—	—	—	—	—	—	—	—
SLVS_400_25	0.070	0.200	0.330	0.140	—	0.450	—	—	—	—	—	—	—	—
MIPI_DPHY_DC1_HS <sup>(9)</sup>	0.070	—	0.330	0.070	—	—	-0.040	0.460	0.150	0.200	0.250	0.140	0.200	0.270

**Notes:**

1. V<sub>ICM</sub> is the input common mode voltage.
2. V<sub>ID</sub> is the input differential voltage ( $Q - \bar{Q}$ ).
3. V<sub>IHHS</sub> and V<sub>ILHS</sub> are the single-ended input high and low voltages, respectively.
4. V<sub>OCM</sub> is the output common mode voltage.
5. V<sub>OD</sub> is the output differential voltage ( $Q - \bar{Q}$ ).
6. LVDS\_25 is specified in Table 23.
7. LVDS is specified in Table 24.
8. Only the SUB\_LVDS receiver is supported in HD I/O banks.
9. High-speed option for MIPI\_DPHY\_DC1. The V<sub>ID</sub> maximum is aligned with the standard's specification. A higher V<sub>ID</sub> is acceptable as long as the V<sub>IN</sub> specification is also met.

Table 18: Complementary Differential SelectIO DC Input and Output Levels for HD I/O Banks

I/O Standard	V <sub>ICM</sub> (V) <sup>(1)</sup>			V <sub>ID</sub> (V) <sup>(2)</sup>		V <sub>OL</sub> (V) <sup>(3)</sup>	V <sub>OH</sub> (V) <sup>(4)</sup>	I <sub>OL</sub>	I <sub>OH</sub>
	Min	Typ	Max	Min	Max	Max	Min	mA	mA
DIFF_HSTL_I	0.300	0.750	1.125	0.100	—	0.400	V <sub>CCO</sub> – 0.400	8.0	-8.0
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	—	0.400	V <sub>CCO</sub> – 0.400	8.0	-8.0
DIFF_HSUL_12	0.300	0.600	0.850	0.100	—	20% V <sub>CCO</sub>	80% V <sub>CCO</sub>	0.1	-0.1
DIFF_SSTL12	0.300	0.600	0.850	0.100	—	(V <sub>CCO</sub> /2) – 0.150	(V <sub>CCO</sub> /2) + 0.150	14.25	-14.25
DIFF_SSTL135	0.300	0.675	1.000	0.100	—	(V <sub>CCO</sub> /2) – 0.150	(V <sub>CCO</sub> /2) + 0.150	8.9	-8.9
DIFF_SSTL135_II	0.300	0.675	1.000	0.100	—	(V <sub>CCO</sub> /2) – 0.150	(V <sub>CCO</sub> /2) + 0.150	13.0	-13.0
DIFF_SSTL15	0.300	0.750	1.125	0.100	—	(V <sub>CCO</sub> /2) – 0.175	(V <sub>CCO</sub> /2) + 0.175	8.9	-8.9
DIFF_SSTL15_II	0.300	0.750	1.125	0.100	—	(V <sub>CCO</sub> /2) – 0.175	(V <sub>CCO</sub> /2) + 0.175	13.0	-13.0
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	—	(V <sub>CCO</sub> /2) – 0.470	(V <sub>CCO</sub> /2) + 0.470	8.0	-8.0
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	—	(V <sub>CCO</sub> /2) – 0.600	(V <sub>CCO</sub> /2) + 0.600	13.4	-13.4

**Notes:**

1. V<sub>ICM</sub> is the input common mode voltage.
2. V<sub>ID</sub> is the input differential voltage.
3. V<sub>OL</sub> is the single-ended low-output voltage.
4. V<sub>OH</sub> is the single-ended high-output voltage.

Table 19: Complementary Differential SelectIO DC Input and Output Levels for HP I/O Banks<sup>(1)</sup>

I/O Standard	V <sub>ICM</sub> (V) <sup>(2)</sup>			V <sub>ID</sub> (V) <sup>(3)</sup>		V <sub>OL</sub> (V) <sup>(4)</sup>	V <sub>OH</sub> (V) <sup>(5)</sup>	I <sub>OL</sub>	I <sub>OH</sub>
	Min	Typ	Max	Min	Max	Max	Min	mA	mA
DIFF_HSTL_I	0.680	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.150	0.100	–	0.400	V <sub>CCO</sub> – 0.400	5.8	-5.8
DIFF_HSTL_I_12	0.400 × V <sub>CCO</sub>	V <sub>CCO</sub> /2	0.600 × V <sub>CCO</sub>	0.100	–	0.250 × V <sub>CCO</sub>	0.750 × V <sub>CCO</sub>	4.1	-4.1
DIFF_HSTL_I_18	(V <sub>CCO</sub> /2) – 0.175	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.175	0.100	–	0.400	V <sub>CCO</sub> – 0.400	6.2	-6.2
DIFF_HSUL_12	(V <sub>CCO</sub> /2) – 0.120	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.120	0.100	–	20% V <sub>CCO</sub>	80% V <sub>CCO</sub>	0.1	-0.1
DIFF_SSTL12	(V <sub>CCO</sub> /2) – 0.150	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.150	0.100	–	(V <sub>CCO</sub> /2) – 0.150	(V <sub>CCO</sub> /2) + 0.150	8.0	-8.0
DIFF_SSTL135	(V <sub>CCO</sub> /2) – 0.150	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.150	0.100	–	(V <sub>CCO</sub> /2) – 0.150	(V <sub>CCO</sub> /2) + 0.150	9.0	-9.0
DIFF_SSTL15	(V <sub>CCO</sub> /2) – 0.175	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.175	0.100	–	(V <sub>CCO</sub> /2) – 0.175	(V <sub>CCO</sub> /2) + 0.175	10.0	-10.0
DIFF_SSTL18_I	(V <sub>CCO</sub> /2) – 0.175	V <sub>CCO</sub> /2	(V <sub>CCO</sub> /2) + 0.175	0.100	–	(V <sub>CCO</sub> /2) – 0.470	(V <sub>CCO</sub> /2) + 0.470	7.0	-7.0

**Notes:**

1. DIFF POD10 and DIFF POD12 HP I/O bank specifications are shown in Table 20, Table 21, and Table 22.
2. V<sub>ICM</sub> is the input common mode voltage.
3. V<sub>ID</sub> is the input differential voltage.
4. V<sub>OL</sub> is the single-ended low-output voltage.
5. V<sub>OH</sub> is the single-ended high-output voltage.

Table 20: DC Input Levels for Differential POD10 and POD12 I/O Standards<sup>(1)(2)</sup>

I/O Standard	V <sub>ICM</sub> (V)			V <sub>ID</sub> (V)	
	Min	Typ	Max	Min	Max
DIFF_POD10	0.63	0.70	0.77	0.14	–
DIFF_POD12	0.76	0.84	0.92	0.16	–

**Notes:**

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 21: DC Output Levels for Single-ended and Differential POD10 and POD12 Standards<sup>(1)(2)</sup>

Symbol	Description	V <sub>OUT</sub>	Min	Typ	Max	Units
R <sub>OL</sub>	Pull-down resistance.	V <sub>OM_DC</sub> (as described in Table 22)	36	40	44	Ω
R <sub>OH</sub>	Pull-up resistance.	V <sub>OM_DC</sub> (as described in Table 22)	36	40	44	Ω

**Notes:**

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 22: Table 21 Definitions for DC Output Levels for POD Standards

Symbol	Description	All Speed Grades	Units
V <sub>OM_DC</sub>	DC output Mid measurement level (for IV curve linearity).	0.8 × V <sub>CCO</sub>	V

## LVDS DC Specifications (LVDS\_25)

The LVDS\_25 standard is available in the HD I/O banks. See the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)) for more information.

*Table 23: LVDS\_25 DC Specifications*

Symbol	DC Parameter	Min	Typ	Max	Units
$V_{CCO}^{(1)}$	Supply voltage.	2.375	2.500	2.625	V
$V_{IDIFF}$	Differential input voltage: $(Q - \bar{Q})$ , $\underline{Q}$ = High $(\bar{Q} - Q)$ , $\bar{Q}$ = High	100	350	600 <sup>(2)</sup>	mV
$V_{ICM}$	Input common-mode voltage.	0.300	1.200	1.425	V

**Notes:**

1. LVDS\_25 in HD I/O banks supports inputs only. LVDS\_25 inputs without internal termination have no  $V_{CCO}$  requirements. Any  $V_{CCO}$  can be chosen as long as the input voltage levels do not violate the *Recommended Operating Condition* ([Table 2](#)) specification for the  $V_{IN}$  I/O pin voltage.
2. Maximum  $V_{IDIFF}$  value is specified for the maximum  $V_{ICM}$  specification. With a lower  $V_{ICM}$ , a higher  $V_{IDIFF}$  is tolerated only when the recommended operating conditions and overshoot/undershoot  $V_{IN}$  specifications are maintained.

## LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks. See the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)) for more information.

*Table 24: LVDS DC Specifications*

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
$V_{CCO}^{(1)}$	Supply voltage.		1.710	1.800	1.890	V
$V_{ODIFF}^{(2)}$	Differential output voltage: $(Q - \bar{Q})$ , $\underline{Q}$ = High $(\bar{Q} - Q)$ , $\bar{Q}$ = High	$R_T = 100\Omega$ across Q and $\bar{Q}$ signals	247	350	454	mV
$V_{OCM}^{(2)}$	Output common-mode voltage.	$R_T = 100\Omega$ across Q and $\bar{Q}$ signals	1.000	1.250	1.425	V
$V_{IDIFF}^{(3)}$	Differential input voltage: $(Q - \bar{Q})$ , $\underline{Q}$ = High $(\bar{Q} - Q)$ , $\bar{Q}$ = High		100	350	600 <sup>(3)</sup>	mV
$V_{ICM\_DC}^{(4)}$	Input common-mode voltage (DC coupling).		0.300	1.200	1.425	V
$V_{ICM\_AC}^{(5)}$	Input common-mode voltage (AC coupling).		0.600	–	1.100	V

**Notes:**

1. In HP I/O banks, when LVDS is used with input-only functionality, it can be placed in a bank where the  $V_{CCO}$  levels are different from the specified level only if internal differential termination is not used. In this scenario,  $V_{CCO}$  must be chosen to ensure the input pin voltage levels do not violate the *Recommended Operating Condition* ([Table 2](#)) specification for the  $V_{IN}$  I/O pin voltage.
2.  $V_{OCM}$  and  $V_{ODIFF}$  values are for  $LVDS\_PRE\_EMPHASIS = FALSE$ .
3. Maximum  $V_{IDIFF}$  value is specified for the maximum  $V_{ICM}$  specification. With a lower  $V_{ICM}$ , a higher  $V_{IDIFF}$  is tolerated only when the recommended operating conditions and overshoot/undershoot  $V_{IN}$  specifications are maintained.
4. Input common mode voltage for DC coupled configurations. EQUALIZATION = EQ\_NONE (Default).
5. External input common mode voltage specification for AC coupled configurations. EQUALIZATION = EQ\_LEVEL0, EQ\_LEVEL1, EQ\_LEVEL2, EQ\_LEVEL3, EQ\_LEVEL4.

# AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in the Vivado® Design Suite as outlined in [Table 25](#).

**Table 25: Speed Specification Version By Device**

2017.1	Device
1.08	XCZU4CG, XCZU4EG, XCZU4EV, XCZU5CG, XCZU5EG, XCZU5EV, XCZU11EG
1.10	XCZU2CG, XCZU2EG, XCZU3CG, XCZU3EG, XCZU6CG, XCZU6EG, XCZU7CG, XCZU7EG, XCZU7EV, XCZU9CG, XCZU9EG, XCZU15EG, XCZU17EG, XCZU19EG

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

## Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

## Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

## Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

# Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Zynq UltraScale+ MPSoC.

## Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 26](#) correlates the current status of the Zynq UltraScale+ MPSoC on a per speed grade basis. See [Table 3](#) for operating voltages listed by speed grade.

*Table 26: Speed Grade Designations by Device*

Device	Speed Grade, Temperature Ranges, and $V_{CCINT}$ Operating Voltages		
	Advance	Preliminary	Production
XCZU2CG	-2LE ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.72V$ )		-2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ) -1I ( $V_{CCINT} = 0.85V$ )
XCZU2EG	-2LE ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.72V$ )		-2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ) -1I ( $V_{CCINT} = 0.85V$ )
XCZU3CG	-2LE ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.72V$ )		-2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ) -1I ( $V_{CCINT} = 0.85V$ )
XCZU3EG	-2LE ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.72V$ )		-2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ) -1I ( $V_{CCINT} = 0.85V$ )
XCZU4CG	-2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ), -2LE ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ), -1I ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ), -1LI ( $V_{CCINT} = 0.72V$ )		
XCZU4EG	-3E ( $V_{CCINT} = 0.90V$ ), -2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ), -2LE ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ), -1I ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ), -1LI ( $V_{CCINT} = 0.72V$ )		
XCZU4EV	-3E ( $V_{CCINT} = 0.90V$ ), -2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ), -2LE ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ), -1I ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ), -1LI ( $V_{CCINT} = 0.72V$ )		
XCZU5CG	-2E ( $V_{CCINT} = 0.85V$ ) -2I ( $V_{CCINT} = 0.85V$ ), -2LE ( $V_{CCINT} = 0.85V$ ) -1E ( $V_{CCINT} = 0.85V$ ), -1I ( $V_{CCINT} = 0.85V$ ) -1LI ( $V_{CCINT} = 0.85V$ ) -2LE ( $V_{CCINT} = 0.72V$ ), -1LI ( $V_{CCINT} = 0.72V$ )		

Table 26: Speed Grade Designations by Device (Cont'd)

Device	Speed Grade, Temperature Ranges, and V <sub>CCINT</sub> Operating Voltages		
	Advance	Preliminary	Production
XCZU5EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU5EV	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU6CG	-2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)
XCZU6EG	-3E (V <sub>CCINT</sub> = 0.90V) -2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)
XCZU7CG	-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU7EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU7EV	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU9CG	-2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)
XCZU9EG	-3E (V <sub>CCINT</sub> = 0.90V) -2LE (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V) -1LI (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.72V)		-2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V) -1I (V <sub>CCINT</sub> = 0.85V)

Table 26: Speed Grade Designations by Device (Cont'd)

Device	Speed Grade, Temperature Ranges, and V <sub>CCINT</sub> Operating Voltages		
	Advance	Preliminary	Production
XCZU11EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU15EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU17EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		
XCZU19EG	-3E (V <sub>CCINT</sub> = 0.90V), -2E (V <sub>CCINT</sub> = 0.85V) -2I (V <sub>CCINT</sub> = 0.85V), -2LE (V <sub>CCINT</sub> = 0.85V) -1E (V <sub>CCINT</sub> = 0.85V), -1I (V <sub>CCINT</sub> = 0.85V) -1LI (V <sub>CCINT</sub> = 0.85V) -2LE (V <sub>CCINT</sub> = 0.72V), -1LI (V <sub>CCINT</sub> = 0.72V)		

**Notes:**

1. The lowest power -1L and -2L devices, where V<sub>CCINT</sub> = 0.72V, are listed in the Vivado Design Suite as -1LV and -2LV respectively.

## Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

**Table 27** lists the production released Zynq UltraScale+ MPSoC, speed grade, and the minimum corresponding supported speed specification version and Vivado software revisions. The Vivado software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

**Table 27: Zynq UltraScale+ MPSoC Device Production Software and Speed Specification Release**

Device	Speed Grade and V <sub>CCINT</sub> Operating Voltages						
	0.90V		0.85V			0.72V	
	-3	-2	-1	-2L	-1L	-2L	-1L
XCZU2CG	N/A	Vivado tools 2017.1 v1.10					
XCZU2EG	N/A	Vivado tools 2017.1 v1.10					
XCZU3CG	N/A	Vivado tools 2017.1 v1.10					
XCZU3EG	N/A	Vivado tools 2017.1 v1.10					
XCZU4CG	N/A						
XCZU4EG							
XCZU4EV							
XCZU5CG	N/A						
XCZU5EG							
XCZU5EV							
XCZU6CG	N/A	Vivado tools 2017.1 v1.10					
XCZU6EG		Vivado tools 2017.1 v1.10					
XCZU7CG	N/A						
XCZU7EG							
XCZU7EV							
XCZU9CG	N/A	Vivado tools 2017.1 v1.10					
XCZU9EG		Vivado tools 2017.1 v1.10					
XCZU11EG							
XCZU15EG							
XCZU17EG							
XCZU19EG							

**Notes:**

1. See [Table 3](#) for the complete list of operating voltages by speed grade.
2. Blank entries indicate a device and/or speed grade in Advance or Preliminary status.

# Processor System (PS) Performance Characteristics

Table 28: Processor Performance

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F <sub>APUMAX</sub>	Maximum APU clock frequency.	1500	1333	1200	MHz
F <sub>RPUMAX</sub>	Maximum RPU clock frequency.	600	533	500	MHz
F <sub>GPUMAX</sub>	Maximum GPU clock frequency.	667	600	600	MHz

Table 29: Configuration and Security Unit Performance

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F <sub>CSUCIBMAX</sub>	Maximum CSU crypto interface block frequency.	400	400	400	MHz

Table 30: PS DDR Performance

Memory Standard	Package	DRAM Type	Speed Grade						Units	
			-3		-2		-1			
			Min	Max	Min	Max	Min	Max		
DDR4	All FFV packages, FBVB900, and SFVC784	Single rank component	664	2400	664	2400	664	2400	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	2133	664	2133	664	2133	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1866	664	1866	664	1866	Mb/s	
	SFVA625	Single rank component	664	2133	664	2133	664	2133	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1866	664	1866	664	1866	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1600	664	1600	664	1600	Mb/s	
	SBVA484	Single rank component	664	1066	664	1066	664	1066	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1066	664	1066	664	1066	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
LPDDR4	All FFV packages, FBVB900 and SFVC784	Single die package <sup>(5)</sup>	664	2400	664	2400	664	2400	Mb/s	
		Dual die package <sup>(4)(5)</sup>	664	2133	664	2133	664	2133	Mb/s	
	SFVA625	Single die package <sup>(5)</sup>	664	2133	664	2133	664	2133	Mb/s	
		Dual die package <sup>(4)(5)</sup>	664	1866	664	1866	664	1866	Mb/s	
	SBVA484	Single die package <sup>(5)</sup>	664	1066	664	1066	664	1066	Mb/s	
		Dual die package <sup>(4)(5)</sup>	664	1066	664	1066	664	1066	Mb/s	

Table 30: PS DDR Performance (Cont'd)

Memory Standard	Package	DRAM Type	Speed Grade						Units	
			-3		-2		-1			
			Min	Max	Min	Max	Min	Max		
DDR3	All FFV packages, FBVB900 and SFVC784	Single rank component	664	2133	664	2133	664	2133	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1866	664	1866	664	1866	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1600	664	1600	664	1600	Mb/s	
	SFVA625	Single rank component	664	1866	664	1866	664	1866	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1600	664	1600	664	1600	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1333	664	1333	664	1333	Mb/s	
	SBVA484	Single rank component	664	1066	664	1066	664	1066	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1066	664	1066	664	1066	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
DDR3L	All FFV packages, FBVB900 and SFVC784	Single rank component	664	1866	664	1866	664	1866	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1600	664	1600	664	1600	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1333	664	1333	664	1333	Mb/s	
	SFVA625	Single rank component	664	1600	664	1600	664	1600	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1333	664	1333	664	1333	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
	SBVA484	Single rank component	664	1066	664	1066	664	1066	Mb/s	
		1 rank DIMM <sup>(1)(2)</sup>	664	1066	664	1066	664	1066	Mb/s	
		2 rank DIMM <sup>(1)(3)</sup>	664	1066	664	1066	664	1066	Mb/s	
LPDDR3	All FFV packages, FBVB900 and SFVC784	Single die package <sup>(6)</sup>	664	1600	664	1600	664	1600	Mb/s	
		Dual die package <sup>(6)</sup>	664	1333	664	1333	664	1333	Mb/s	
	SFVA625	Single die package <sup>(6)</sup>	664	1333	664	1333	664	1333	Mb/s	
		Dual die package <sup>(6)</sup>	664	1066	664	1066	664	1066	Mb/s	
	SBVA484	Single die package <sup>(6)</sup>	664	1066	664	1066	664	1066	Mb/s	
		Dual die package <sup>(6)</sup>	664	1066	664	1066	664	1066	Mb/s	

**Notes:**

1. Dual in-line memory module (DIMM) includes RDIMM, SODIMM, and UDIMM.
2. Includes: 1 rank 1 slot, dual-die package 2 rank.
3. Includes: 2 rank 1 slot.
4. Dual die package includes single die with ECC.
5. LPDDR4 support is only available as a 32-bit interface.
6. 64-bit LPDDR3 interface performance values are defined without ECC support.

Table 31: PS NAND NV-DDR Synchronous Performance

Memory Standard	Mode	Speed Grade			Units
		-3	-2	-1	
		Max	Max	Max	
NV-DDR <sup>(1)</sup>	5	200	200	200	Mb/s
	4	166.6	166.6	166.6	Mb/s
	3	133.3	133.3	133.3	Mb/s
	2	100	100	100	Mb/s
	1	66.6	66.6	66.6	Mb/s
	0	40	40	40	Mb/s

**Notes:**

1. The PS NAND memory controller interface for NV-DDR switching characteristics meets the requirements of the ONFI 3.1 specification.

Table 32: PS NAND SDR Asynchronous Performance

Memory Standard	Mode	Speed Grade			Units
		-3	-2	-1	
		Max	Max	Max	
SDR <sup>(1)(2)</sup>	5	50	50	50	Mb/s
	4	40	40	40	Mb/s
	3	33.3	33.3	33.3	Mb/s
	2	28.5	28.5	28.5	Mb/s
	1	20	20	20	Mb/s
	0	10	10	10	Mb/s

**Notes:**

1. The PS NAND memory controller interface for SDR switching characteristics meets the requirements of the ONFI 3.1 specification.
2. The NAND controller reference clock frequency maximum is 83 MHz.

Table 33: PS-PL Interface Performance

Symbol	Description	Min	Max	Units
FEMIOGEMCLK	EMIO gigabit Ethernet controller maximum frequency.	–	125	MHz
FEMIOSDCLK	EMIO SD controller maximum frequency.	–	25	MHz
FEMIOSPICLK	EMIO SPI controller maximum frequency.	–	25	MHz
FEMIOTRACECLK	EMIO trace controller maximum frequency.	–	125	MHz
FFCIDDMACLK	Flow control interface DMA maximum frequency.	–	333	MHz
FAXICLK	Maximum AXI interface performance.	–	333	MHz
FDPLIVEVIDEO	DisplayPort controller live video interface maximum frequency.	–	300	MHz

# PS Switching Characteristics

## PS Clocks

Table 34: PS Reference Clock Requirements<sup>(1)</sup>

Symbol	Description	Min	Typ	Max	Units
T <sub>RMSJPSCLK</sub>	PS_REF_CLK input RMS clock jitter.	–	–	3	ps
T <sub>PJPSCLK</sub>	PS_REF_CLK input period jitter (peak-to-peak). Number of clock cycles = 10,000	–	–	50	ps
T <sub>DCPSCLK</sub>	PS_REF_CLK duty cycle.	45	–	55	%
T <sub>RFPSCLK</sub>	PS_REF_CLK rise time (20%–80%) and fall time (80%–20%).	–	–	2.22	ns
F <sub>PSCLK</sub>	PS_REF_CLK frequency.	27	–	60	MHz

**Notes:**

1. The values in this table are applicable to alternative PS reference clock inputs ALT\_REF\_CLK, AUX\_REF\_CLK, and VIDEO\_CLK.

Table 35: PS RTC Crystal Requirements<sup>(1)</sup>

Symbol	Description	Min	Typ	Max	Units
F <sub>XTAL</sub>	Parallel resonance crystal frequency.	–	32.8	–	KHz
T <sub>FTXTAL</sub>	Frequency tolerance.	–20	–	20	ppm
C <sub>XTAL</sub>	Load capacitance for crystal parallel resonance.	–	12.5	–	pF
R <sub>ESR</sub>	Crystal ESR (16.8 and 19.2 MHz).	–	70	–	KΩ
C <sub>SHUNT</sub>	Crystal shunt capacitance.	–	1.4	–	pF

**Notes:**

1. Required board components: Feedback resistor = 4.7 MΩ, PCB and pad capacitance = 1.5 pF, C<sub>1</sub> and C<sub>2</sub> capacitance = 21 pF.

Table 36: PS PLL Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F <sub>LOCKPSPLL</sub>	PLL maximum lock time.	100	100	100	μs
F <sub>PSPLLMAX</sub>	PLL maximum output frequency.	1600	1600	1600	MHz
F <sub>PSPLLMIN</sub>	PLL minimum output frequency.	750	750	750	MHz
F <sub>PSPLLVCOMAX</sub>	PLL maximum VCO frequency.	3000	3000	3000	MHz
F <sub>PSPLLVCOMIN</sub>	PLL minimum VCO frequency.	1500	1500	1500	MHz

Table 37: PS Reset Assertion Timing Requirements

Symbol	Description	Min	Typ	Max	Units
T <sub>PSPOR</sub>	Required PS_POR_B assertion time. <sup>(1)</sup>	10	—	—	μs
T <sub>PSRST</sub>	Required PS_SRST_B assertion time.	3	—	—	PS_REF_CLK Clock Cycles

**Notes:**

1. PS\_POR\_B must be asserted Low at power-up and continue to be asserted for a duration of T<sub>PSPOR</sub> after all the PS supply voltages reach minimum levels. PS\_POR\_B must be asserted Low for the duration of T<sub>POR</sub> when the PS and PL power-up at the same time and the application uses both the PS and PL after power-up.

Table 38: PS Clocks Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F <sub>TOPSW_MAINMAX</sub>	TOPSW_MAIN maximum frequency.	600	533	533	MHz
F <sub>TOPSW_LSBUSMAX</sub>	TOPSW_LSBUS maximum frequency.	100	100	100	MHz
F <sub>GDMAMAX</sub>	FPD-DMA maximum frequency.	600	600	600	MHz
F <sub>DPDMAMAX</sub>	DisplayPort DMA maximum frequency.	600	600	600	MHz
F <sub>LPD_SWITCH_CTRLMAX</sub>	LPD_SWITCH_CTRL maximum frequency.	600	500	500	MHz
F <sub>LPD_LSBUS_CTRLMAX</sub>	LPD_LSBUS_CTRL maximum frequency.	100	100	100	MHz
F <sub>ADMAMAX</sub>	LPD-DMA maximum frequency.	600	500	500	MHz
F <sub>APLL_TO_LPDMAX</sub>	APLL_TO_LPD maximum frequency.	533	533	533	MHz
F <sub>DPLL_TO_LPDMAX</sub>	DPLL_TO_LPD maximum frequency.	533	533	533	MHz
F <sub>VPLL_TO_LPDMAX</sub>	VPLL_TO_LPD maximum frequency.	533	533	533	MHz
F <sub>IOPLLU_TO_LPDMAX</sub>	IOPLLU_TO_LPD maximum frequency.	533	533	533	MHz
F <sub>RPLL_TO_FPDMAX</sub>	RPLL_TO_FPD maximum frequency.	533	533	533	MHz

## PS Configuration

Table 39: Processor Configuration Access Port Switching Characteristics

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V	0.72V				
		-3	-2	-1	-2	-1		
F <sub>PCAPCK</sub>	Maximum processor configuration access port (PCAP) frequency.	200	200	200	150	150	MHz	

Table 40: Boundary-Scan Port Switching Characteristics

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V	0.72V				
		-3	-2	-1	-2	-1		
F <sub>TCK</sub>	JTAG clock maximum frequency.	25	25	25	15	15	MHz	
T <sub>TAPTCK/TCKTAP</sub>	TMS and TDI setup and hold.	4.0/2.0	4.0/2.0	4.0/2.0	5.0/2.0	5.0/2.0	ns, Min	
T <sub>TCKTDO</sub>	TCK falling edge to TDO output.	16.1	16.1	16.1	24	24	ns, Max	

**Notes:**

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength.

# PS Interface Specifications

## PS Quad-SPI Controller Interface

Table 41: Generic Quad-SPI Interface<sup>(1)</sup>

Symbol	Description	Load Conditions <sup>(2)</sup>	Min	Max	Units
<b>Quad-SPI device clock frequency operating at 150 MHz. Loopback enabled. LVC MOS 1.8V I/O standard.</b>					
T <sub>DCQSPICLK1</sub>	Quad-SPI clock duty cycle.	15 pF	45	55	%
T <sub>QSPISSSCLK1</sub>	Slave select asserted to next clock edge.	15 pF	5.0	—	ns
T <sub>QSPISCLKS1</sub>	Clock edge to slave select deasserted.	15 pF	5.0	—	ns
T <sub>QSPICKO1</sub>	Clock to output delay, all outputs.	15 pF	2.9	4.5	ns
T <sub>QSPIDCK1</sub>	Setup time, all inputs.	15 pF	0.9	—	ns
T <sub>QSPICKD1</sub>	Hold time, all inputs.	15 pF	1.0	—	ns
F <sub>QSPICLK1</sub>	Quad-SPI device clock frequency.	15 pF	—	150	MHz
F <sub>QSPIREFCLK1</sub>	Quad-SPI reference clock frequency.	15 pF	—	300	MHz
<b>Quad-SPI device clock frequency operating at 100 MHz. Loopback enabled. LVC MOS 1.8V I/O standard.</b>					
T <sub>DCQSPICLK2</sub>	Quad-SPI clock duty cycle.	15 pF	45	55	%
		30 pF	45	55	%
T <sub>QSPISSSCLK2</sub>	Slave select asserted to next clock edge.	15 pF	5.0	—	ns
		30 pF	5.0	—	ns
T <sub>QSPISCLKS2</sub>	Clock edge to slave select deasserted.	15 pF	5.0	—	ns
		30 pF	5.0	—	ns
T <sub>QSPICKO2</sub>	Clock to output delay, all outputs.	15 pF	3.2	7.4	ns
		30 pF	3.2	7.4	ns
T <sub>QSPIDCK2</sub>	Setup time, all inputs.	15 pF	2.3	—	ns
		30 pF	2.3	—	ns
T <sub>QSPICKD2</sub>	Hold time, all inputs.	15 pF	0.0	—	ns
		30 pF	0.0	—	ns
F <sub>QSPICLK2</sub>	Quad-SPI device clock frequency.	15 pF	—	100	MHz
		30 pF	—	100	MHz
F <sub>QSPIREFCLK2</sub>	Quad-SPI reference clock frequency.	15 pF	—	200	MHz
		30 pF	—	200	MHz

**Notes:**

1. The test conditions are configured for the generic Quad-SPI interface at 150/100 MHz with a 12 mA drive strength and fast slew rate.
2. 30 pF loads are for dual-parallel stacked or stacked modes.

Table 42: Linear Quad-SPI Interface<sup>(1)</sup>

Symbol	Description	Load Conditions <sup>(2)</sup>	Min	Max	Units
<b>Quad-SPI device clock frequency operating at 100 MHz. Loopback enabled. LVC MOS 1.8V I/O standard.</b>					
T <sub>DCQSPICLK5</sub>	Quad-SPI clock duty cycle.	15 pF	45	55	%
		30 pF	45	55	%
T <sub>QSPISSSCLK5</sub>	Slave select asserted to next clock edge. <sup>(3)</sup>	15 pF	5.0	—	ns
		30 pF	5.0	—	ns
T <sub>QSPISCLKSS5</sub>	Clock edge to slave select deasserted.	15 pF	5.0	—	ns
		30 pF	5.0	—	ns
T <sub>QSPICKO5</sub>	Clock to output delay, all outputs.	15 pF	3.2	7.4	ns
		30 pF	3.2	7.4	ns
T <sub>QSPIDCK5</sub>	Setup time, all inputs.	15 pF	2.4	—	ns
		30 pF	2.4	—	ns
T <sub>QSPICKD5</sub>	Hold time, all inputs.	15 pF	0.0	—	ns
		30 pF	0.0	—	ns
F <sub>QSPIREFCLK5</sub>	Quad-SPI reference clock frequency.	15 pF	—	200	MHz
		30 pF	—	200	MHz
F <sub>QSPICLK5</sub>	Quad-SPI device clock frequency.	15 pF	—	100	MHz
		30 pF	—	100	MHz

**Notes:**

1. The test conditions are configured for the linear Quad-SPI interface at 100 MHz with a 12 mA drive strength and fast slew rate.
2. 30 pF loads are for stacked modes.
3. T<sub>QSPISSSCLK5</sub> is only valid when two reference clock cycles are programmed between chip select and clock.

## PS USB Interface

Table 43: ULPI Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
T <sub>ULPIDCK</sub>	Input setup to ULPI clock, all inputs.	4.5	—	ns
T <sub>ULPICKD</sub>	Input hold to ULPI clock, all inputs.	0	—	ns
T <sub>ULPICKO</sub>	ULPI clock to output valid, all outputs.	2.0	8.86	ns
F <sub>ULPICLK</sub>	ULPI reference clock frequency.	—	60	MHz

**Notes:**

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

## PS Gigabit Ethernet Controller Interface

Table 44: RGMII Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
T <sub>DGEMTXCLK</sub>	Transmit clock duty cycle.	45	55	%
T <sub>GEMTXCKO</sub>	TXD output clock to out time.	-0.5	0.5	ns
T <sub>GEMRXDCK</sub>	RXD input setup time.	0.8	—	ns
T <sub>GEMRXCKD</sub>	RXD input hold time.	0.8	—	ns
T <sub>MdioCLK</sub>	MDC output clock period.	400	—	ns
T <sub>MdioCKL</sub>	MDC low time.	160	—	ns
T <sub>MdioCKH</sub>	MDC high time.	160	—	ns
T <sub>MdiODCK</sub>	MDIO input data setup time.	80	—	ns
T <sub>MdiOCKD</sub>	MDIO input data hold time.	0.0	—	ns
T <sub>MdiOCKO</sub>	MDIO output data delay time.	-1.0	15	ns
F <sub>GETXCLK</sub>	RGMII_TX_CLK transmit clock frequency.	—	125	MHz
F <sub>GERXCLK</sub>	RGMII_RX_CLK receive clock frequency.	—	125	MHz
F <sub>ENET_REF_CLK</sub>	Ethernet reference clock frequency.	—	125	MHz

**Notes:**

1. The test conditions are configured to the LVCMS 2.5V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

## PS SD/SDIO Controller Interface

Table 45: SD/SDIO Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
<b>SD/SDIO Interface DDR50 Mode</b>				
T <sub>DCDDRCLK</sub>	SD device clock duty cycle.	45	55	%
T <sub>SDDDRCK01</sub>	Clock to output delay, data. <sup>(2)</sup>	1.0	6.8	ns
T <sub>SDDRIVW</sub>	Input valid data window. <sup>(3)</sup>	3.5	—	ns
T <sub>SDDDRDCK2</sub>	Input setup time, command.	4.7	—	ns
T <sub>SDDDRCKD2</sub>	Input hold time, command.	1.5	—	ns
T <sub>SDDDRCK02</sub>	Clock to output delay, command.	1.0	13.8	ns
F <sub>SDDDRCLK</sub>	High-speed mode SD device clock frequency.	—	50	MHz
<b>SD/SDIO Interface SDR104</b>				
T <sub>DCSDHSCLK1</sub>	SD device clock duty cycle.	40	60	%
T <sub>SDSDRCK01</sub>	Clock to output delay, all outputs. <sup>(2)</sup>	1.0	3.2	ns
T <sub>SDSDR1IVW</sub>	Input valid data window. <sup>(3)</sup>	0.5	—	UI
F <sub>SDSDRCLK1</sub>	SDR104 mode device clock frequency.	—	200	MHz
<b>SD/SDIO Interface SDR50/25</b>				
T <sub>DCSDHSCLK2</sub>	SD device clock duty cycle.	40	60	%
T <sub>SDSDRCK02</sub>	Clock to output delay, all outputs. <sup>(2)</sup>	1.0	6.8	ns
T <sub>SDSDR2IVW</sub>	Input valid data window. <sup>(3)</sup>	0.3	—	UI

Table 45: SD/SDIO Interface<sup>(1)</sup> (Cont'd)

Symbol	Description	Min	Max	Units
$F_{SDSDRCLK2}$	SDR50 mode device clock frequency.	–	100	MHz
	SDR25 mode device clock frequency.	–	50	MHz
<b>SD/SDIO Interface SDR12</b>				
$T_{DCSDHSCLK3}$	SD device clock duty cycle.	40	60	%
$T_{SDSDRCKO3}$	Clock to output delay, all outputs.	1.0	36.8	ns
$T_{SDSDRCK3}$	Input setup time, all inputs.	24.0	–	ns
$T_{SDSDRCKD3}$	Input hold time, all inputs.	1.5	–	ns
$F_{SDSDRCLK3}$	SDR12 mode device clock frequency.	–	25	MHz
<b>SD/SDIO Interface High-Speed Mode</b>				
$T_{DCSDHSCLK}$	SD device clock duty cycle.	47	53	%
$T_{SDHSCKO}$	Clock to output delay, all outputs. <sup>(2)</sup>	2.2	13.8	ns
$T_{SDHSDIVW}$	Input valid data window. <sup>(3)</sup>	0.35	–	UI
$F_{SDHSCLK}$	High-speed mode SD device clock frequency.	–	50	MHz
<b>SD/SDIO Interface Standard Mode</b>				
$T_{DCSDSCLK}$	SD device clock duty cycle.	45	55	%
$T_{SDSCKO}$	Clock to output delay, all outputs.	–2.0	4.5	ns
$T_{SDSDCK}$	Input setup time, all inputs.	2.0	–	ns
$T_{SDSCKD}$	Input hold time, all inputs.	2.0	–	ns
$F_{SDIDCLK}$	Clock frequency in identification mode.	–	400	KHz
$F_{SDSCLK}$	Standard SD device clock frequency.	–	19	MHz

**Notes:**

1. The test conditions SD/SDIO standard mode (default speed mode) use an 8 mA drive strength, fast slew rate, and a 30 pF load. For SD/SDIO high-speed mode, the test conditions use a 12 mA drive strength, fast slew rate, and a 30 pF load. For other SD/SDIO modes, the test conditions use a 12 mA drive strength, fast slew rate, and a 15 pF load.
2. This specification is achieved using pre-determined DLL tuning.
3. This specification is required for capturing input data using DLL tuning.

## PS eMMC Standard Interface

Table 46: eMMC Standard Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
<b>eMMC Standard Interface</b>				
T <sub>DCEMMCHSCLK</sub>	eMMC clock duty cycle.	45	55	%
T <sub>E姚MCHSCKO</sub>	Clock to output delay, all outputs.	-2.0	4.5	ns
T <sub>E姚MCHSDCK</sub>	Input setup time, all inputs.	2.0	-	ns
T <sub>E姚MCHSCKD</sub>	Input hold time, all inputs.	2.0	-	ns
F <sub>E姚MCHSCLK</sub>	eMMC clock frequency.	-	25	MHz
<b>eMMC High-Speed SDR Interface</b>				
T <sub>DCEMMCHSCLK</sub>	eMMC high-speed SDR clock duty cycle.	45	55	%
T <sub>E姚MCHSCKO</sub>	Clock to output delay, all outputs. <sup>(2)</sup>	3.2	16.8	ns
T <sub>E姚MCHSDIVW</sub>	Input valid data window. <sup>(3)</sup>	0.4	-	UI
F <sub>E姚MCHSCLK</sub>	eMMC high speed SDR clock frequency.	-	50	MHz
<b>eMMC High-Speed DDR Interface</b>				
T <sub>DCEMMCDRCLK</sub>	eMMC high-speed DDR clock duty cycle.	45	55	%
T <sub>E姚MCDRSCKO1</sub>	Data clock to output delay. <sup>(2)</sup>	2.7	7.3	ns
T <sub>E姚MCSDRIVW</sub>	Input valid data window. <sup>(3)</sup>	3.5	-	ns
T <sub>E姚MCDDRCKO2</sub>	Command clock to output delay.	3.2	16	ns
T <sub>E姚MCDDRCK2</sub>	Command input setup time.	3.9	-	ns
T <sub>E姚MCDDRCKD2</sub>	Command input hold time.	2.5	-	ns
F <sub>E姚MCDDRCLK</sub>	eMMC high-speed DDR clock frequency.	-	50	MHz
<b>eMMC HS200 Interface</b>				
T <sub>DCEMMCHS200CLK</sub>	eMMC HS200 clock duty cycle.	40	60	%
T <sub>E姚MCHS200CKO</sub>	Clock to output delay, all outputs. <sup>(2)</sup>	1.0	3.4	ns
T <sub>E姚MCSDRIVW</sub>	Input valid data window. <sup>(3)</sup>	0.4	-	UI
F <sub>E姚MCHS200CLK</sub>	eMMC HS200 clock frequency.	-	200	MHz

### Notes:

1. The test conditions for eMMC standard mode use an 8 mA drive strength, fast slew rate, and a 30 pF load. For eMMC high-speed mode, the test conditions use a 12 mA drive strength, fast slew rate, and a 30 pF load. For other eMMC modes, the test conditions use a 12 mA drive strength, fast slew rate, and a 15 pF load.
2. This specification is achieved using pre-determined DLL tuning.
3. This specification is required for capturing input data using DLL tuning.

## PS I2C Controller Interface

Table 47: I2C Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
<b>I2C Fast-mode Interface</b>				
T <sub>I2CFCKL</sub>	SCL Low time.	1.3	–	μs
T <sub>I2CFCKH</sub>	SCL High time.	0.6	–	μs
T <sub>I2CFCKO</sub>	SDA clock to out delay.	–	900	ns
T <sub>I2CFDCK</sub>	SDA input setup time.	100	–	ns
F <sub>I2CFCLK</sub>	SCL clock frequency.	–	400	KHz
<b>I2C Standard-mode Interface</b>				
T <sub>I2CSCKL</sub>	SCL Low time.	4.7	–	μs
T <sub>I2CSCKH</sub>	SCL High time.	4.0	–	μs
T <sub>I2CSCKO</sub>	SDA clock to out delay.	–	3450	ns
T <sub>I2CSDCK</sub>	SDA input setup time.	250	–	ns
F <sub>I2CSCLK</sub>	SCL clock frequency.	–	100	KHz

**Notes:**

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

## PS SPI Controller Interface

Table 48: SPI Interfaces<sup>(1)</sup>

Symbol	Description	Min	Max	Units
<b>SPI Master Interface</b>				
T <sub>DCMSPICLK</sub>	SPI master mode clock duty cycle.	45	55	%
T <sub>MSPISSCLK</sub>	Slave select asserted to first active clock edge.	1 <sup>(2)</sup>	–	F <sub>SPI_REF_CLK</sub> cycles
T <sub>MSPISCLKSS</sub>	Last active clock edge to slave select deasserted.	1 <sup>(2)</sup>	–	F <sub>SPI_REF_CLK</sub> cycles
T <sub>MSPIDCK</sub>	Input setup time for MISO.	–2.0	–	ns
T <sub>MSPICKD</sub>	Input hold time for MISO.	0.3	–	F <sub>MSPICLK</sub> cycles
T <sub>MSPICKO</sub>	MOSI and slave select clock to out delay.	–2.0	5.0	ns
F <sub>MSPICLK</sub>	SPI master device clock frequency.	–	50	MHz
F <sub>SPI_REF_CLK</sub>	SPI reference clock frequency.	–	200	MHz
<b>SPI Slave Interface</b>				
T <sub>SPPISSCLK</sub>	Slave select asserted to first active clock edge.	2	–	F <sub>SPI_REF_CLK</sub> cycles
T <sub>SPPISCLKSS</sub>	Last active clock edge to slave select deasserted.	2	–	F <sub>SPI_REF_CLK</sub> cycles
T <sub>SPPIDCK</sub>	Input setup time for MOSI.	5.0	–	ns
T <sub>SPPICKD</sub>	Input hold time for MOSI.	1	–	F <sub>SPI_REF_CLK</sub> cycles
T <sub>SPPICKO</sub>	MISO clock to out delay.	0.0	13.0	ns
F <sub>SPPICLK</sub>	SPI slave mode device clock frequency.	–	25	MHz
F <sub>SPI_REF_CLK</sub>	SPI reference clock frequency.	–	200	MHz

**Notes:**

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 30 pF load.
2. Valid when two SPI\_REF\_CLK delays are programmed between CS and CLK for T<sub>MSPISSCLK</sub>, and between CLK and CS for T<sub>MSPISCLKSS</sub> in the SPI delay\_reg0 register.

## PS CAN Controller Interface

Table 49: CAN Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
T <sub>PWCANRX</sub>	Receive pulse width.	1.0	–	μs
T <sub>PWCANTX</sub>	Transmit pulse width.	1.0	–	μs
F <sub>CAN_REF_CLK</sub>	Internally sourced CAN reference clock frequency.	–	100	MHz
	Externally sourced CAN reference clock frequency.	–	40	MHz

**Notes:**

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

## PS DAP Interface

Table 50: DAP Interface<sup>(1)</sup>

Symbol	Description <sup>(2)</sup>	Min	Max	Units
T <sub>PDAPDCK</sub>	PS DAP input setup time.	3.0	–	ns
T <sub>PDAPCKD</sub>	PS DAP input hold time.	2.0	–	ns
T <sub>PDAPCKO</sub>	PS DAP clock to out delay.	–	10.86	ns
T <sub>PDAPCLK</sub>	PS DAP clock frequency.	–	44	MHz

**Notes:**

1. The test conditions are configured to the LVCMS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.
2. PS DAP interface signals connect to MIO pins.

## PS UART Interface

Table 51: UART Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
BAUD <sub>TXMAX</sub>	Transmit baud rate.	–	6.25	Mb/s
BAUD <sub>RXMAX</sub>	Receive baud rate.	–	6.25	Mb/s
F <sub>UART_REF_CLK</sub>	UART reference clock frequency.	–	100	MHz

**Notes:**

1. The test conditions are configured to the LVCMS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

## PS General Purpose I/O Interface

Table 52: General Purpose I/O (GPIO) Interface

Symbol	Description	Min	Max	Units
T <sub>PWGPIOH</sub>	Input High pulse width.	10 x 1/F <sub>LPD_LSBUS_CTRLMAX</sub>	–	μs
T <sub>PWGPIOL</sub>	Input Low pulse width.	10 x 1/F <sub>LPD_LSBUS_CTRLMAX</sub>	–	μs

## PS Trace Interface

Table 53: Trace Interface<sup>(1)</sup>

Symbol	Description	Min	Max	Units
T <sub>TCECKO</sub>	Trace clock to output delay, all outputs.	–0.5	0.5	ns
T <sub>DCTCECLK</sub>	Trace clock duty cycle.	45	55	%
F <sub>TCECLK</sub>	Trace clock frequency.	–	125	MHz

**Notes:**

1. The test conditions are configured to the LVCMS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

## PS Triple-timer Counter Interface

Table 54: Triple-timer Counter Interface

Symbol	Description	Min	Max	Units
$T_{PWTTCOCLK}$	Triple-timer counter output clock pulse width.	60.4	–	ns
$F_{TTCOCLK}$	Triple-timer counter output clock frequency.	–	16.5	MHz
$T_{TTCICLKL}$	Triple-timer counter input clock high pulse width.	$1.5 \times F_{LPD\_LSBUS\_CTRLMAX}$	–	ns
$T_{TTCICLKH}$	Triple-timer counter input clock low pulse width.	$1.5 \times F_{LPD\_LSBUS\_CTRLMAX}$	–	ns
$F_{TTCICLK}$	Triple-timer counter input clock frequency.	–	$F_{LPD\_LSBUS\_CTRLMAX}/3$	MHz

**Notes:**

1. All timing values assume an ideal external input clock. Your actual timing budget must account for additional external clock jitter.

## PS Watchdog Timer Interface

Table 55: Watchdog Timer Interface

Symbol	Description	Min	Max	Units
$F_{WDTCLK}$	Watchdog timer input clock frequency.	–	100	MHz

# PS-GTR Transceiver

Table 56: PS-GTR Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
D <sub>VPPIN</sub>	Differential peak-to-peak input voltage (external AC coupled).		100	—	1200	mV
V <sub>IN</sub>	Single-ended input voltage. Voltage measured at the pin referenced to GND.		75	—	V <sub>PS_MGTRAVCC</sub>	mV
V <sub>CMIN</sub>	Common mode input voltage.		—	0	—	mV
D <sub>VPPOUT</sub>	Differential peak-to-peak output voltage. <sup>(1)</sup>	Transmitter output swing is set to maximum value.	800	—	—	mV
V <sub>CMOUTAC</sub>	Common mode output voltage: AC coupled (equation based).		V <sub>PS_MGTRAVCC</sub> – D <sub>VPPOUT</sub> /2			mV
R <sub>IN</sub>	Differential input resistance.		—	100	—	Ω
R <sub>OUT</sub>	Differential output resistance.		—	100	—	Ω
R <sub>MGTRREF</sub>	Resistor value between calibration resistor pin to GND.		497.5	500	502.5	Ω
T <sub>OSKEW</sub>	Transmitter output pair (TXP and TXN) intra-pair skew (All packages).		—	—	20	ps
C <sub>EXT</sub>	Recommended external AC coupling capacitor. <sup>(2)</sup>		—	100	—	nF

**Notes:**

1. The output swing and pre-emphasis levels are programmable using the attributes discussed in the *Zynq UltraScale+ MPSoC Technical Reference Manual* (UG1085), and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

Table 57: PS-GTR Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V <sub>IDIFF</sub>	Differential peak-to-peak input voltage.	250	—	2000	mV
R <sub>IN</sub>	Differential input resistance.	—	100	—	Ω
C <sub>EXT</sub>	Required external AC coupling capacitor.	—	10	—	nF

Table 58: PS-GTR Transceiver Performance

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F <sub>GTRMAX</sub>	PS-GTR maximum line rate.	6.0	6.0	6.0	Gb/s
F <sub>GTRMIN</sub>	PS-GTR minimum line rate.	1.25	1.25	1.25	Gb/s

Table 59: PS-GTR Transceiver PLL/Lock Time Adaptation

Symbol	Description	Min	Typ	Max	Units
T <sub>LOCK</sub>	Initial PLL lock.	—	—	0.11	ms
T <sub>DLOCK</sub>	Clock recovery phase acquisition and adaptation time.	—	—	24 × 10 <sup>6</sup>	UI

Table 60: PS-GTR Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
$F_{GCLK}$	Reference clock frequencies supported.	PCI Express	100 MHz			
		SATA	125 MHz or 150 MHz			
		USB 3.0	26 MHz, 52 MHz, or 100 MHz			
		DisplayPort	27 MHz, 108 MHz, or 135 MHz			
		SGMII	125 MHz			
$T_{RCLK}$	Reference clock rise time.	20% – 80%	–	200	–	ps
$T_{FCLK}$	Reference clock fall time.	80% – 20%	–	200	–	ps
$T_{DCREF}$	Reference clock duty cycle.	Transceiver PLL only.	40	–	60	%
		USB 3.0 with reference clock <40 MHz.	47.5	–	52.5	%

Table 61: PS-GTR Transceiver Reference Clock Oscillator Selection Phase Noise Mask

Symbol	Description	Offset Frequency	Min	Typ	Max	Units
PLL <sub>REFCLKMASK</sub>	PLL reference clock select phase noise mask at REFCLK frequency = 25 MHz.	100	–	–	-102	dBc/Hz
		1 KHz	–	–	-124	
		10 KHz	–	–	-132	
		100 KHz	–	–	-139	
		1 MHz	–	–	-152	
		10 MHz	–	–	-154	
	PLL reference clock select phase noise mask at REFCLK frequency = 50 MHz.	100	–	–	-96	dBc/Hz
		1 KHz	–	–	-118	
		10 KHz	–	–	-126	
		100 KHz	–	–	-133	
		1 MHz	–	–	-146	
		10 MHz	–	–	-148	
	PLL reference clock select phase noise mask at REFCLK frequency = 100 MHz.	100	–	–	-90	dBc/Hz
		1 KHz	–	–	-112	
		10 KHz	–	–	-120	
		100 KHz	–	–	-127	
		1 MHz	–	–	-140	
		10 MHz	–	–	-142	
	PLL reference clock select phase noise mask at REFCLK frequency = 125 MHz.	100	–	–	-88	dBc/Hz
		1 KHz	–	–	-110	
		10 KHz	–	–	-118	
		100 KHz	–	–	-125	
		1 MHz	–	–	-138	
		10 MHz	–	–	-140	
	PLL reference clock select phase noise mask at REFCLK frequency = 150 MHz.	100	–	–	-86	dBc/Hz
		1 KHz	–	–	-108	
		10 KHz	–	–	-116	
		100 KHz	–	–	-123	
		1 MHz	–	–	-136	
		10 MHz	–	–	-138	

**Notes:**

- For reference clock frequencies not in this table, use the phase noise mask for the nearest reference clock frequency.

Table 62: PS-GTR Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTRTX</sub>	Serial data rate range.		1.25	–	6.0	Gb/s
T <sub>RTX</sub>	TX rise time.	20%–80%	–	65	–	ps
T <sub>FTX</sub>	TX fall time.	80%–20%	–	65	–	ps

Table 63: PS-GTR Transceiver Receiver Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTRRX</sub>	Serial data rate.		1.25	–	6	Gb/s
RX <sub>SST</sub>	Receiver spread-spectrum tracking.	Modulated at 33 KHz	–5000	–	0	ppm
RX <sub>PPMTOL</sub>	Data/REFCLK PPM offset tolerance.	All data rates	–350	–	350	ppm

Table 64: PCI Express Protocol Characteristics (PS-GTR Transceivers)<sup>(1)</sup>

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>PCI Express Transmitter Jitter Generation</b>					
PCI Express Gen 1	Total transmitter jitter.	2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter.	5000	–	0.25	UI
<b>PCI Express Receiver High Frequency Jitter Tolerance</b>					
PCI Express Gen 1	Total receiver jitter tolerance.	2500	0.65	–	UI
PCI Express Gen 2 <sup>(2)</sup>	Receiver inherent timing error.	5000	0.4	–	UI
	Receiver inherent deterministic timing error.	5000	0.3	–	UI

**Notes:**

1. Tested per card electromechanical (CEM) methodology.
2. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20 dB/decade.

Table 65: Serial ATA (SATA) Protocol Characteristics (PS-GTR Transceivers)

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>Serial ATA Transmitter Jitter Generation</b>					
SATA Gen 1	Total transmitter jitter.	1500	–	0.37	UI
SATA Gen 2	Total transmitter jitter.	3000	–	0.37	UI
SATA Gen 3	Total transmitter jitter.	6000	–	0.52	UI
<b>Serial ATA Receiver High Frequency Jitter Tolerance</b>					
SATA Gen 1	Total receiver jitter tolerance.	1500	0.27	–	UI
SATA Gen 2	Total receiver jitter tolerance.	3000	0.27	–	UI
SATA Gen 2	Total receiver jitter tolerance.	6000	0.16	–	UI

Table 66: DisplayPort Protocol Characteristics (PS-GTR Transceivers)<sup>(1)</sup>

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>DisplayPort Transmitter Jitter Generation</b>					
RBR	Total transmitter jitter.	1620	–	0.42	UI
HBR	Total transmitter jitter.	2700	–	0.42	UI
HBR2 D10.2	Total transmitter jitter.	5400	–	0.40	UI
HBR2 CPAT	Total transmitter jitter.	5400	–	0.58	UI

**Notes:**

1. Only the transmitter is supported.

Table 67: USB 3.0 Protocol Characteristics (PS-GTR Transceivers)

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>USB 3.0 Transmitter Jitter Generation</b>					
USB 3.0	Total transmitter jitter.	5000	–	0.66	UI
<b>USB 3.0 Receiver High Frequency Jitter Tolerance</b>					
USB 3.0	Total receiver jitter tolerance.	5000	0.2	–	UI

Table 68: Serial-GMII Protocol Characteristics (PS-GTR Transceivers)

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>Serial-GMII Transmitter Jitter Generation</b>					
SGMII	Deterministic transmitter jitter.	1250	–	0.25	UI
<b>Serial-GMII Receiver High Frequency Jitter Tolerance</b>					
SGMII	Total receiver jitter tolerance.	1250	0.25	–	UI

## PS System Monitor Specifications

Table 69: PS SYSMON Specifications

Parameter	Comments	Conditions	Min	Typ	Max	Units
$V_{CC\_PSADC} = 1.8V \pm 3\%$ , $T_j = -40^\circ C$ to $100^\circ C$ , typical values at $T_j = 40^\circ C$						
<b>ADC Accuracy (<math>T_j = -55^\circ C</math> to <math>125^\circ C</math>) <sup>(1)</sup></b>						
Resolution		10	–	–	–	Bits
Sample rate		–	–	1	–	MS/s
RMS code noise	On-chip reference	–	1	–	–	LSBs
<b>On-Chip Sensor Accuracy</b>						
Temperature sensor error	$T_j = -55^\circ C$ to $110^\circ C$	–	–	$\pm 3.5$	–	$^\circ C$
	$T_j = 110^\circ C$ to $125^\circ C$	–	–	$\pm 5$	–	$^\circ C$
Supply sensor error <sup>(2)</sup>	Supply voltages less than or electrically connected to $V_{CC\_PSADC}$ .	$T_j = -40^\circ C$ to $125^\circ C$	–	–	$\pm 1$	%
	Supply voltages nominally at 1.8V but with the potential to go above $V_{CC\_PSADC}$ .	$T_j = -40^\circ C$ to $125^\circ C$	–	–	$\pm 1.5$	%
	Supply voltages nominally in the 2.0V to 3.3V range.	$T_j = -40^\circ C$ to $125^\circ C$	–	–	$\pm 2.5$	%

### Notes:

1. ADC offset errors are removed by enabling the ADC automatic offset calibration feature. The values are specified for when this feature is enabled.
2. Supply sensor offset and gain errors are removed by enabling the automatic offset and gain calibration feature. The values are specified for when this feature is enabled.

## Programmable Logic (PL) Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Zynq UltraScale+ MPSoC. These values are subject to the same guidelines as the [AC Switching Characteristics, page 22](#). In each table, the I/O bank type is either high performance (HP) or high density (HD).

*Table 70: LVDS Component Mode Performance*

Description	I/O Bank Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages										Units	
		0.90V		0.85V				0.72V					
		-3		-2		-1		-2		-1			
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
LVDS TX DDR (OSERDES 4:1, 8:1)	HP	0	1250	0	1250	0	1250	0	1250	0	1250	Mb/s	
LVDS TX SDR (OSERDES 2:1, 4:1)	HP	0	625	0	625	0	625	0	625	0	625	Mb/s	
LVDS RX DDR (ISERDES 1:4, 1:8) <sup>(1)</sup>	HP	0	1250	0	1250	0	1250	0	1250	0	1250	Mb/s	
LVDS RX DDR	HD	0	250	0	250	0	250	0	250	0	250	Mb/s	
LVDS RX SDR (ISERDES 1:2, 1:4) <sup>(1)</sup>	HP	0	625	0	625	0	625	0	625	0	625	Mb/s	
LVDS RX SDR	HD	0	125	0	125	0	125	0	125	0	125	Mb/s	

**Notes:**

1. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

*Table 71: LVDS Native Mode Performance<sup>(1)(2)</sup>*

Description	DATA_WIDTH	I/O Bank Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages										Units	
			0.90V		0.85V				0.72V					
			-3 <sup>(3)</sup>		-2 <sup>(3)</sup>		-1		-2 <sup>(3)</sup>		-1			
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
LVDS TX DDR (TX_BITSLICE)	4	HP	375	1600	375	1600	375	1260	375	1400	375	1260	Mb/s	
	8		375	1600	375	1600	375	1260	375	1600	375	1260	Mb/s	
LVDS TX SDR (TX_BITSLICE)	4	HP	187.5	800	187.5	800	187.5	630	187.5	700	187.5	630	Mb/s	
	8		187.5	800	187.5	800	187.5	630	187.5	800	187.5	630	Mb/s	
LVDS RX DDR (RX_BITSLICE) <sup>(4)</sup>	4	HP	375	1600	375	1600	375	1260	375	1400	375	1260	Mb/s	
	8		375	1600	375	1600	375	1260	375	1600	375	1260	Mb/s	
LVDS RX SDR (RX_BITSLICE) <sup>(4)</sup>	4	HP	187.5	800	187.5	800	187.5	630	187.5	700	187.5	630	Mb/s	
	8		187.5	800	187.5	800	187.5	630	187.5	800	187.5	630	Mb/s	

**Notes:**

1. Native mode is supported through the [High-Speed SelectIO Interface Wizard](#) available with the Vivado Design Suite. The performance values assume a source-synchronous interface.
2. PLL settings can restrict the minimum allowable data rate. For example, when using the PLL with CLKOUTPHY\_MODE = VCO\_HALF the minimum frequency is  $\text{PLL\_FVCOMIN}/2$ .
3. In the SBVA484 package, the maximum data rate is 1260 Mb/s for DDR interfaces and 630 Mb/s for SDR interfaces.
4. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 72: MIPI D-PHY Performance

Description	I/O Bank Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3 <sup>(1)</sup>	-2 <sup>(1)</sup>	-1	-2	-1		
MIPI D-PHY transmitter or receiver.	HP	1500	1500	1260	1260	1260	Mb/s	

**Notes:**

1. In the SBVA484 package, the data rate is 1260 Mb/s.

Table 73: LVDS Native-Mode 1000BASE-X Support<sup>(1)</sup>

Description	I/O Bank Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages				
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	-1
1000BASE-X	HP	Yes				

**Notes:**

1. 1000BASE-X support is based on the *IEEE Standard for CSMA/CD Access Method and Physical Layer Specifications* (IEEE Std 802.3-2008).

Table 74 provides the maximum data rates for applicable memory standards using the Zynq UltraScale+ MPSoC memory PHY. Refer to [Memory Interfaces](#) for the complete list of memory interface standards supported and detailed specifications. The final performance of the memory interface is determined through a complete design implemented in the Vivado Design Suite, following guidelines in the *UltraScale Architecture PCB Design Guide* ([UG583](#)), electrical analysis, and characterization of the system.

Table 74: Maximum Physical Interface (PHY) Rate for Memory Interfaces

Memory Standard	Package <sup>(1)</sup>	DRAM Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
DDR4	All FFV packages and FBVB900	Single rank component	2666	2666	2400	2400	2133	Mb/s	
		1 rank DIMM <sup>(2)(3)(4)</sup>	2400	2400	2133	2133	1866	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	2133	2133	1866	1866	1600	Mb/s	
		4 rank DIMM <sup>(2)(6)</sup>	1600	1600	1333	1333	N/A	Mb/s	
	SFVC784	Single rank component	2400	2400	2133	2133	1866	Mb/s	
		1 rank DIMM <sup>(2)(3)</sup>	2133	2133	1866	1866	1600	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	1866	1866	1600	1600	1600	Mb/s	
DDR3	All FFV packages and FBVB900	Single rank component	2133	2133	2133	2133	1866	Mb/s	
		1 rank DIMM <sup>(2)(3)</sup>	1866	1866	1866	1866	1600	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	1600	1600	1600	1600	1333	Mb/s	
		4 rank DIMM <sup>(2)(6)</sup>	1066	1066	1066	1066	800	Mb/s	
	SFVC784	Single rank component	1866	1866	1866	1866	1600	Mb/s	
		1 rank DIMM <sup>(2)(3)</sup>	1600	1600	1600	1600	1600	Mb/s	
		2 rank DIMM <sup>(2)(5)</sup>	1600	1600	1600	1600	1333	Mb/s	
		4 rank DIMM <sup>(2)(6)</sup>	1066	1066	1066	1066	800	Mb/s	

Table 74: Maximum Physical Interface (PHY) Rate for Memory Interfaces (Cont'd)

Memory Standard	Package <sup>(1)</sup>	DRAM Type	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units		
			0.90V		0.85V		0.72V			
			-3	-2	-1	-2	-1			
DDR3L	All FFV packages and FBVB900	Single rank component	1866	1866	1866	1866	1600	Mb/s		
		1 rank DIMM <sup>(2)(3)</sup>	1600	1600	1600	1600	1333	Mb/s		
		2 rank DIMM <sup>(2)(5)</sup>	1333	1333	1333	1333	1066	Mb/s		
		4 rank DIMM <sup>(2)(6)</sup>	800	800	800	800	606	Mb/s		
	SFVC784	Single rank component	1600	1600	1600	1600	1600	Mb/s		
		1 rank DIMM <sup>(2)(3)</sup>	1600	1600	1600	1600	1333	Mb/s		
		2 rank DIMM <sup>(2)(5)</sup>	1333	1333	1333	1333	1066	Mb/s		
		4 rank DIMM <sup>(2)(6)</sup>	800	800	800	800	606	Mb/s		
QDR II+	All	Single rank component <sup>(7)</sup>	633	633	600	600	550	MHz		
RLDRAM 3	All FFV packages and FBVB900	Single rank component	1200	1200	1066	1066	933	MHz		
	SFVC784	Single rank component	1066	1066	933	933	800	MHz		
QDR IV XP	All	Single rank component	1066	1066	1066	933	933	MHz		
LPDDR3	All	Single rank component	1600	1600	1600	1600	1600	Mb/s		

**Notes:**

1. The SBVA484 and SFVA625 packages do not support the PL memory interfaces.
2. Dual in-line memory module (DIMM) includes RDIMM, SODIMM, UDIMM, and LRDIMM.
3. Includes: 1 rank 1 slot, DDP 2 rank, LRDIMM 2 or 4 rank 1 slot.
4. For the DDR4 DDP components at -3 and -2 speed grades and V<sub>CCINT</sub> = 0.85V, the maximum data rate is 2133 Mb/s for six or more DDP devices. For five or less DDP devices, use the single rank DIMM data rates for the -3 and -2 speed grades at 0.85V.
5. Includes: 2 rank 1 slot, 1 rank 2 slot, LRDIMM 2 rank 2 slot.
6. Includes: 2 rank 2 slot, 4 rank 1 slot.
7. The QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations.

# Programmable Logic (PL) Switching Characteristics

**Table 75** (high-density IOB (HD)) and **Table 76** (high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- $T_{INBUF\_DELAY\_PAD\_I}$  is the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- $T_{OUTBUF\_DELAY\_O\_PAD}$  is the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- $T_{OUTBUF\_DELAY\_TD\_PAD}$  is the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than  $T_{OUTBUF\_DELAY\_TD\_PAD}$  when the DCITERMDISABLE pin is used. In HD I/O banks, the on-die termination turn-on time is always faster than  $T_{OUTBUF\_DELAY\_TD\_PAD}$  when the INTERMDISABLE pin is used.

## IOB High Density (HD) Switching Characteristics

Table 75: IOB High Density (HD) Switching Characteristics

I/O Standards	$T_{INBUF\_DELAY\_PAD\_I}$					$T_{OUTBUF\_DELAY\_O\_PAD}$					$T_{OUTBUF\_DELAY\_TD\_PAD}$					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
DIFF_HSTL_I_18_F	0.978	0.978	1.058	0.978	1.058	1.574	1.574	1.718	1.574	1.718	1.160	1.160	1.271	1.160	1.271	ns
DIFF_HSTL_I_18_S	0.978	0.978	1.058	0.978	1.058	1.805	1.805	1.950	1.805	1.950	1.748	1.748	1.867	1.748	1.867	ns
DIFF_HSTL_I_F	0.978	0.978	1.058	0.978	1.058	1.611	1.611	1.762	1.611	1.762	1.313	1.313	1.417	1.313	1.417	ns
DIFF_HSTL_I_S	0.978	0.978	1.058	0.978	1.058	1.798	1.798	1.913	1.798	1.913	1.630	1.630	1.780	1.630	1.780	ns
DIFF_HSUL_12_F	0.911	0.911	0.977	0.911	0.977	1.573	1.573	1.703	1.573	1.703	1.222	1.222	1.335	1.222	1.335	ns
DIFF_HSUL_12_S	0.911	0.911	0.977	0.911	0.977	1.711	1.711	1.864	1.711	1.864	1.536	1.536	1.665	1.536	1.665	ns
DIFF_SSTL12_F	0.906	0.906	0.977	0.906	0.977	1.643	1.643	1.792	1.643	1.792	1.285	1.285	1.423	1.285	1.423	ns
DIFF_SSTL12_S	0.906	0.906	0.977	0.906	0.977	1.784	1.784	1.948	1.784	1.948	1.567	1.567	1.706	1.567	1.706	ns
DIFF_SSTL135_F	0.927	0.927	0.995	0.927	0.995	1.625	1.625	1.765	1.625	1.765	1.341	1.341	1.458	1.341	1.458	ns
DIFF_SSTL135_II_F	0.927	0.927	0.995	0.927	0.995	1.623	1.623	1.770	1.623	1.770	1.325	1.325	1.470	1.325	1.470	ns
DIFF_SSTL135_II_S	0.927	0.927	0.995	0.927	0.995	1.768	1.768	1.916	1.768	1.916	1.722	1.722	1.911	1.722	1.911	ns
DIFF_SSTL135_S	0.927	0.927	0.995	0.927	0.995	1.869	1.869	2.025	1.869	2.025	1.814	1.814	1.976	1.814	1.976	ns
DIFF_SSTL15_F	0.928	0.928	1.020	0.928	1.020	1.628	1.628	1.771	1.628	1.771	1.374	1.374	1.483	1.374	1.483	ns
DIFF_SSTL15_II_F	0.928	0.928	1.020	0.928	1.020	1.622	1.622	1.778	1.622	1.778	1.356	1.356	1.442	1.356	1.442	ns
DIFF_SSTL15_II_S	0.928	0.928	1.020	0.928	1.020	1.821	1.821	1.987	1.821	1.987	1.895	1.895	2.047	1.895	2.047	ns
DIFF_SSTL15_S	0.928	0.928	1.020	0.928	1.020	1.824	1.824	1.977	1.824	1.977	1.743	1.743	1.907	1.743	1.907	ns
DIFF_SSTL18_II_F	0.961	0.961	1.038	0.961	1.038	1.729	1.729	1.880	1.729	1.880	1.377	1.377	1.492	1.377	1.492	ns
DIFF_SSTL18_II_S	0.961	0.961	1.038	0.961	1.038	1.796	1.796	1.965	1.796	1.965	1.616	1.616	1.800	1.616	1.800	ns
DIFF_SSTL18_I_F	0.961	0.961	1.038	0.961	1.038	1.609	1.609	1.755	1.609	1.755	1.220	1.220	1.313	1.220	1.313	ns
DIFF_SSTL18_I_S	0.961	0.961	1.038	0.961	1.038	1.786	1.786	1.942	1.786	1.942	1.677	1.677	1.836	1.677	1.836	ns
HSTL_I_18_F	0.947	0.947	1.021	0.947	1.021	1.574	1.574	1.718	1.574	1.718	1.160	1.160	1.271	1.160	1.271	ns
HSTL_I_18_S	0.947	0.947	1.021	0.947	1.021	1.805	1.805	1.950	1.805	1.950	1.748	1.748	1.867	1.748	1.867	ns



Table 75: IOB High Density (HD) Switching Characteristics (Cont'd)

I/O Standards	T <sub>INBUF_DELAY_PAD_I</sub>					T <sub>OUTBUF_DELAY_O_PAD</sub>					T <sub>OUTBUF_DELAY_TD_PAD</sub>					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
LVCMOS33_S_8	1.154	1.154	1.213	1.154	1.213	2.929	2.929	3.260	2.929	3.260	2.260	2.260	2.532	2.260	2.532	ns
LVDS_25	1.003	1.003	1.116	1.003	1.116	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	ns
LVPECL	1.003	1.003	1.116	1.003	1.116	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	ns
LVTTL_F_12	1.164	1.164	1.223	1.164	1.223	2.415	2.415	2.651	2.415	2.651	1.754	1.754	1.915	1.754	1.915	ns
LVTTL_F_16	1.164	1.164	1.223	1.164	1.223	2.464	2.464	2.732	2.464	2.732	1.750	1.750	1.986	1.750	1.986	ns
LVTTL_F_4	1.164	1.164	1.223	1.164	1.223	2.541	2.541	2.765	2.541	2.765	1.932	1.932	2.135	1.932	2.135	ns
LVTTL_F_8	1.164	1.164	1.223	1.164	1.223	2.582	2.582	2.787	2.582	2.787	1.910	1.910	2.063	1.910	2.063	ns
LVTTL_S_12	1.164	1.164	1.223	1.164	1.223	2.731	2.731	3.075	2.731	3.075	2.072	2.072	2.343	2.072	2.343	ns
LVTTL_S_16	1.164	1.164	1.223	1.164	1.223	2.714	2.714	3.024	2.714	3.024	2.028	2.028	2.232	2.028	2.232	ns
LVTTL_S_4	1.164	1.164	1.223	1.164	1.223	2.999	2.999	3.340	2.999	3.340	2.320	2.320	2.610	2.320	2.610	ns
LVTTL_S_8	1.164	1.164	1.223	1.164	1.223	2.929	2.929	3.260	2.929	3.260	2.260	2.260	2.532	2.260	2.532	ns
SLVS_400_25	1.020	1.020	1.136	1.020	1.136	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	ns
SSTL12_F	0.780	0.780	0.867	0.780	0.867	1.643	1.643	1.792	1.643	1.792	1.285	1.285	1.423	1.285	1.423	ns
SSTL12_S	0.780	0.780	0.867	0.780	0.867	1.784	1.784	1.948	1.784	1.948	1.567	1.567	1.706	1.567	1.706	ns
SSTL135_F	0.798	0.798	0.881	0.798	0.881	1.625	1.625	1.765	1.625	1.765	1.341	1.341	1.458	1.341	1.458	ns
SSTL135_II_F	0.798	0.798	0.881	0.798	0.881	1.623	1.623	1.770	1.623	1.770	1.325	1.325	1.470	1.325	1.470	ns
SSTL135_II_S	0.798	0.798	0.881	0.798	0.881	1.768	1.768	1.916	1.768	1.916	1.722	1.722	1.911	1.722	1.911	ns
SSTL135_S	0.798	0.798	0.881	0.798	0.881	1.869	1.869	2.025	1.869	2.025	1.814	1.814	1.976	1.814	1.976	ns
SSTL15_F	0.838	0.838	0.880	0.838	0.880	1.612	1.612	1.754	1.612	1.754	1.357	1.357	1.464	1.357	1.464	ns
SSTL15_II_F	0.838	0.838	0.880	0.838	0.880	1.622	1.622	1.778	1.622	1.778	1.356	1.356	1.442	1.356	1.442	ns
SSTL15_II_S	0.838	0.838	0.880	0.838	0.880	1.821	1.821	1.987	1.821	1.987	1.895	1.895	2.047	1.895	2.047	ns
SSTL15_S	0.838	0.838	0.880	0.838	0.880	1.824	1.824	1.977	1.824	1.977	1.743	1.743	1.907	1.743	1.907	ns
SSTL18_II_F	0.947	0.947	1.021	0.947	1.021	1.729	1.729	1.880	1.729	1.880	1.377	1.377	1.492	1.377	1.492	ns
SSTL18_II_S	0.947	0.947	1.021	0.947	1.021	1.796	1.796	1.965	1.796	1.965	1.616	1.616	1.800	1.616	1.800	ns
SSTL18_I_F	0.947	0.947	1.021	0.947	1.021	1.609	1.609	1.755	1.609	1.755	1.220	1.220	1.313	1.220	1.313	ns
SSTL18_I_S	0.947	0.947	1.021	0.947	1.021	1.786	1.786	1.942	1.786	1.942	1.677	1.677	1.836	1.677	1.836	ns
SUB_LVDS	1.002	1.002	1.036	1.002	1.036	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	ns









Table 76: IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standards	T <sub>INBUF_DELAY_PAD_I</sub>					T <sub>OUTBUF_DELAY_O_PAD</sub>					T <sub>OUTBUF_DELAY_TD_PAD</sub>					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
SSTL135_DCI_S	0.366	0.366	0.399	0.366	0.399	0.746	0.746	0.799	0.746	0.799	0.829	0.829	0.893	0.829	0.893	ns
SSTL135_F	0.378	0.378	0.399	0.378	0.399	0.408	0.408	0.428	0.408	0.428	0.528	0.528	0.561	0.528	0.561	ns
SSTL135_M	0.378	0.378	0.399	0.378	0.399	0.555	0.555	0.585	0.555	0.585	0.641	0.641	0.679	0.641	0.679	ns
SSTL135_S	0.378	0.378	0.399	0.378	0.399	0.772	0.772	0.823	0.772	0.823	0.827	0.827	0.878	0.827	0.878	ns
SSTL15_DCI_F	0.402	0.402	0.417	0.402	0.417	0.412	0.412	0.429	0.412	0.429	0.531	0.531	0.563	0.531	0.563	ns
SSTL15_DCI_M	0.402	0.402	0.417	0.402	0.417	0.553	0.553	0.583	0.553	0.583	0.645	0.645	0.685	0.645	0.685	ns
SSTL15_DCI_S	0.402	0.402	0.417	0.402	0.417	0.768	0.768	0.822	0.768	0.822	0.847	0.847	0.912	0.847	0.912	ns
SSTL15_F	0.371	0.371	0.400	0.371	0.400	0.408	0.408	0.428	0.408	0.428	0.530	0.530	0.556	0.530	0.556	ns
SSTL15_M	0.371	0.371	0.400	0.371	0.400	0.554	0.554	0.585	0.554	0.585	0.639	0.639	0.677	0.639	0.677	ns
SSTL15_S	0.371	0.371	0.400	0.371	0.400	0.767	0.767	0.817	0.767	0.817	0.813	0.813	0.867	0.813	0.867	ns
SSTL18_I_DCI_F	0.329	0.329	0.336	0.329	0.336	0.445	0.445	0.461	0.445	0.461	0.566	0.566	0.595	0.566	0.595	ns
SSTL18_I_DCI_M	0.329	0.329	0.336	0.329	0.336	0.554	0.554	0.585	0.554	0.585	0.644	0.644	0.683	0.644	0.683	ns
SSTL18_I_DCI_S	0.329	0.329	0.336	0.329	0.336	0.762	0.762	0.818	0.762	0.818	0.837	0.837	0.899	0.837	0.899	ns
SSTL18_I_F	0.316	0.316	0.337	0.316	0.337	0.454	0.454	0.476	0.454	0.476	0.578	0.578	0.608	0.578	0.608	ns
SSTL18_I_M	0.316	0.316	0.337	0.316	0.337	0.571	0.571	0.603	0.571	0.603	0.652	0.652	0.692	0.652	0.692	ns
SSTL18_I_S	0.316	0.316	0.337	0.316	0.337	0.782	0.782	0.835	0.782	0.835	0.816	0.816	0.870	0.816	0.870	ns
SUB_LVDS	0.539	0.539	0.620	0.539	0.620	0.660	0.660	0.692	0.660	0.692	969.863	969.863	969.863	969.863	969.863	ns

## IOB 3-state Output Switching Characteristics

Table 77 specifies the values of T<sub>OUTBUF\_DELAY\_TE\_PAD</sub> and T<sub>INBUF\_DELAY\_IBUFDIS\_O</sub>. T<sub>OUTBUF\_DELAY\_TE\_PAD</sub> is the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). T<sub>INBUF\_DELAY\_IBUFDIS\_O</sub> is the IOB delay from IBUFDISABLE to O output. In HP I/O banks, the internal DCI termination turn-off time is always faster than T<sub>OUTBUF\_DELAY\_TE\_PAD</sub> when the DCITERMDISABLE pin is used. In HD I/O banks, the internal IN\_TERM termination turn-off time is always faster than T<sub>OUTBUF\_DELAY\_TE\_PAD</sub> when the INTERMDISABLE pin is used.

Table 77: IOB 3-state Output Switching Characteristics

Symbol	Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units
		0.90V		0.85V		0.72V	
		-3	-2	-1	-2	-1	
T <sub>OUTBUF_DELAY_TE_PAD</sub>	T input to pad high-impedance for HD I/O banks	6.318	6.318	6.369	6.318	6.369	ns
	T input to pad high-impedance for HP I/O banks	5.330	5.330	5.341	5.330	5.341	ns
T <sub>INBUF_DELAY_IBUFDIS_O</sub>	IBUF turn-on time from IBUFDISABLE to O output for HD I/O banks	2.266	2.266	2.430	2.266	2.430	ns
	IBUF turn-on time from IBUFDISABLE to O output for HP I/O banks	0.936	0.936	1.037	0.936	1.037	ns

## Input Delay Measurement Methodology

Table 78 shows the test setup parameters used for measuring input delay.

Table 78: Input Delay Measurement Methodology

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(6)}$	$V_{REF}^{(1)(3)(5)}$
LVCMS, 1.2V	LVCMS12	0.1	1.1	0.6	—
LVCMS, LVDCI, HSLVDCI, 1.5V	LVCMS15, LVDCI_15, HSLVDCI_15	0.1	1.4	0.75	—
LVCMS, LVDCI, HSLVDCI, 1.8V	LVCMS18, LVDCI_18, HSLVDCI_18	0.1	1.7	0.9	—
LVCMS, 2.5V	LVCMS25	0.1	2.4	1.25	—
LVCMS, 3.3V	LVCMS33	0.1	3.2	1.65	—
LVTTL, 3.3V	LVTTL	0.1	3.2	1.65	—
HSTL (high-speed transceiver logic), class I, 1.2V	HSTL_I_12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	$V_{REF}$	0.6
HSTL, class I, 1.5V	HSTL_I	$V_{REF} - 0.325$	$V_{REF} + 0.325$	$V_{REF}$	0.75
HSTL, class I, 1.8V	HSTL_I_18	$V_{REF} - 0.4$	$V_{REF} + 0.4$	$V_{REF}$	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	$V_{REF}$	0.6
SSTL12 (stub series terminated logic), 1.2V	SSTL12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	$V_{REF}$	0.6
SSTL135 and SSTL135 class II, 1.35V	SSTL135, SSTL135_II	$V_{REF} - 0.2875$	$V_{REF} + 0.2875$	$V_{REF}$	0.675
SSTL15 and SSTL15 class II, 1.5V	SSTL15, SSTL15_II	$V_{REF} - 0.325$	$V_{REF} + 0.325$	$V_{REF}$	0.75
SSTL18, class I and II, 1.8V	SSTL18_I, SSTL18_II	$V_{REF} - 0.4$	$V_{REF} + 0.4$	$V_{REF}$	0.9
POD10, 1.0V	POD10	$V_{REF} - 0.2$	$V_{REF} + 0.2$	$V_{REF}$	0.7
POD12, 1.2V	POD12	$V_{REF} - 0.24$	$V_{REF} + 0.24$	$V_{REF}$	0.84
DIFF_HSTL, class I, 1.2V	DIFF_HSTL_I_12	0.6 – 0.25	0.6 + 0.25	0 <sup>(6)</sup>	—
DIFF_HSTL, class I, 1.5V	DIFF_HSTL_I	0.75 – 0.325	0.75 + 0.325	0 <sup>(6)</sup>	—
DIFF_HSTL, class I, 1.8V	DIFF_HSTL_I_18	0.9 – 0.4	0.9 + 0.4	0 <sup>(6)</sup>	—
DIFF_HSUL, 1.2V	DIFF_HSUL_12	0.6 – 0.25	0.6 + 0.25	0 <sup>(6)</sup>	—
DIFF_SSTL, 1.2V	DIFF_SSTL12	0.6 – 0.25	0.6 + 0.25	0 <sup>(6)</sup>	—
DIFF_SSTL135 and DIFF_SSTL135 class II, 1.35V	DIFF_SSTL135, DIFF_SSTL135_II	0.675 – 0.2875	0.675 + 0.2875	0 <sup>(6)</sup>	—
DIFF_SSTL15 and DIFF_SSTL15 class II, 1.5V	DIFF_SSTL15, DIFF_SSTL15_II	0.75 – 0.325	0.75 + 0.325	0 <sup>(6)</sup>	—
DIFF_SSTL18_I, DIFF_SSTL18_II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	0.9 – 0.4	0.9 + 0.4	0 <sup>(6)</sup>	—
DIFF_POD10, 1.0V	DIFF_POD10	0.5 – 0.2	0.5 + 0.2	0 <sup>(6)</sup>	—
DIFF_POD12, 1.2V	DIFF_POD12	0.6 – 0.25	0.6 + 0.25	0 <sup>(6)</sup>	—
LVDS (low-voltage differential signaling), 1.8V	LVDS	0.9 – 0.125	0.9 + 0.125	0 <sup>(6)</sup>	—
LVDS_25, 2.5V	LVDS_25	1.25 – 0.125	1.25 + 0.125	0 <sup>(6)</sup>	—

Table 78: Input Delay Measurement Methodology (Cont'd)

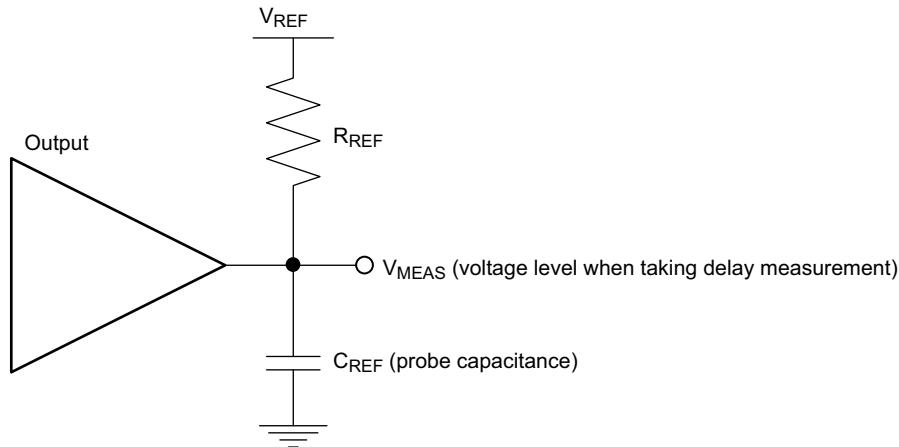
Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(6)}$	$V_{REF}^{(1)(3)(5)}$
SUB_LVDS, 1.8V	SUB_LVDS	0.9 – 0.125	0.9 + 0.125	0 <sup>(6)</sup>	–
SLVS, 1.8V	SLVS_400_18	0.9 – 0.125	0.9 + 0.125	0 <sup>(6)</sup>	–
SLVS, 2.5V	SLVS_400_25	1.25 – 0.125	1.25 + 0.125	0 <sup>(6)</sup>	–
LVPECL, 2.5V	LVPECL	1.25 – 0.125	1.25 + 0.125	0 <sup>(6)</sup>	–
MIPI D-PHY (high speed) 1.2V	MIPI_DPHY_DCI_HS	0.2 – 0.125	0.2 + 0.125	0 <sup>(6)</sup>	–
MIPI D-PHY (low power) 1.2V	MIPI_DPHY_DCI_LP	0.715 – 0.2	0.715 + 0.2	0 <sup>(6)</sup>	–

**Notes:**

1. The input delay measurement methodology parameters for LVDCI/HSLVDCI are the same for LVCMS standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between  $V_L$  and  $V_H$ .
3. Measurements are made at typical, minimum, and maximum  $V_{REF}$  values. Reported delays reflect worst case of these measurements.  $V_{REF}$  values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the  $V_{REF}/V_{MEAS}$  parameters found in IBIS models and/or noted in Figure 1.
6. The value given is the differential input voltage.

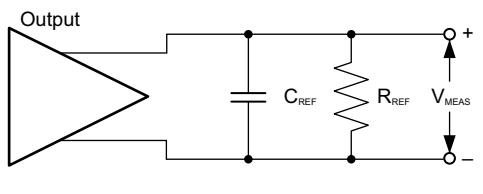
## Output Delay Measurement Methodology

Output delays are measured with short output traces. Standard termination was used for all testing. The propagation delay of the trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in [Figure 1](#) and [Figure 2](#).



X16654-101316

**Figure 1: Single-Ended Test Setup**



X16640-101316

**Figure 2: Differential Test Setup**

Parameters  $V_{REF}$ ,  $R_{REF}$ ,  $C_{REF}$ , and  $V_{MEAS}$  fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using this method:

1. Simulate the output driver of choice into the generalized test setup using values from [Table 79](#).
2. Record the time to  $V_{MEAS}$ .
3. Simulate the output driver of choice into the actual PCB trace and load using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to  $V_{MEAS}$ .
5. Compare the results of [step 2](#) and [step 4](#). The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 79: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R <sub>REF</sub> (Ω)	C <sub>REF</sub> <sup>(1)</sup> (pF)	V <sub>MEAS</sub> (V)	V <sub>REF</sub> (V)
LVC MOS, 1.2V	LVC MOS12	1M	0	0.6	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 3.3V	LVC MOS33	1M	0	1.65	0
LV TTL, 3.3V	LV TTL	1M	0	1.65	0
LVDCI, HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	50	0	V <sub>REF</sub>	0.75
LVDCI, HSLVDCI, 1.8V	LVDCI_15, HSLVDCI_18	50	0	V <sub>REF</sub>	0.9
HSTL (high-speed transceiver logic), class I, 1.2V	HSTL_I_12	50	0	V <sub>REF</sub>	0.6
HSTL, class I, 1.5V	HSTL_I	50	0	V <sub>REF</sub>	0.75
HSTL, class I, 1.8V	HSTL_I_18	50	0	V <sub>REF</sub>	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	50	0	V <sub>REF</sub>	0.6
SSTL12 (stub series terminated logic), 1.2V	SSTL12	50	0	V <sub>REF</sub>	0.6
SSTL135 and SSTL135 class II, 1.35V	SSTL135, SSTL135_II	50	0	V <sub>REF</sub>	0.675
SSTL15 and SSTL15 class II, 1.5V	SSTL15, SSTL15_II	50	0	V <sub>REF</sub>	0.75
SSTL18, class I and class II, 1.8V	SSTL18_I, SSTL18_II	50	0	V <sub>REF</sub>	0.9
POD10, 1.0V	POD10	50	0	V <sub>REF</sub>	1.0
POD12, 1.2V	POD12	50	0	V <sub>REF</sub>	1.2
DIFF_HSTL, class I, 1.2V	DIFF_HSTL_I_12	50	0	V <sub>REF</sub>	0.6
DIFF_HSTL, class I, 1.5V	DIFF_HSTL_I	50	0	V <sub>REF</sub>	0.75
DIFF_HSTL, class I, 1.8V	DIFF_HSTL_I_18	50	0	V <sub>REF</sub>	0.9
DIFF_HSUL, 1.2V	DIFF_HSUL_12	50	0	V <sub>REF</sub>	0.6
DIFF_SSTL12, 1.2V	DIFF_SSTL12	50	0	V <sub>REF</sub>	0.6
DIFF_SSTL135 and DIFF_SSTL135 class II, 1.35V	DIFF_SSTL135, DIFF_SSTL135_II	50	0	V <sub>REF</sub>	0.675
DIFF_SSTL15 and DIFF_SSTL15 class II, 1.5V	DIFF_SSTL15, DIFF_SSTL15_II	50	0	V <sub>REF</sub>	0.75
DIFF_SSTL18, class I and II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	50	0	V <sub>REF</sub>	0.9
DIFF_POD10, 1.0V	DIFF_POD10	50	0	V <sub>REF</sub>	1.0
DIFF_POD12, 1.2V	DIFF_POD12	50	0	V <sub>REF</sub>	1.2
LVDS (low-voltage differential signaling), 1.8V	LVDS	100	0	0 <sup>(2)</sup>	0
SUB_LVDS, 1.8V	SUB_LVDS	100	0	0 <sup>(2)</sup>	0
MIPI D-PHY (high speed) 1.2V	MIPI_DPHY_DCI_HS	100	0	0 <sup>(2)</sup>	0
MIPI D-PHY (low power) 1.2V	MIPI_DPHY_DCI_LP	1M	0	0.6	0

**Notes:**

1. C<sub>REF</sub> is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

## Block RAM and FIFO Switching Characteristics

Table 80: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3	-2	-1	-2	-1		
<b>Maximum Frequency</b>								
$F_{MAX\_WF\_NC}$	Block RAM (WRITE_FIRST and NO_CHANGE modes).	825	738	645	585	516	MHz	
$F_{MAX\_RF}$	Block RAM (READ_FIRST mode).	718	637	575	510	460	MHz	
$F_{MAX\_FIFO}$	FIFO in all modes without ECC.	825	738	645	585	516	MHz	
$F_{MAX\_ECC}$	Block RAM and FIFO in ECC configuration without PIPELINE.	718	637	575	510	460	MHz	
	Block RAM and FIFO in ECC configuration with PIPELINE and Block RAM in WRITE_FIRST or NO_CHANGE mode.	825	738	645	585	516	MHz	
$T_{PW}^{(1)}$	Minimum pulse width.	495	542	543	577	578	ps	
<b>Block RAM and FIFO Clock-to-Out Delays</b>								
$T_{RCKO\_DO}$	Clock CLK to DOUT output (without output register).	0.91	1.02	1.11	1.46	1.53	ns, Max	
$T_{RCKO\_DO\_REG}$	Clock CLK to DOUT output (with output register).	0.27	0.29	0.30	0.42	0.44	ns, Max	

**Notes:**

1. The MMCM and PLL DUTY\_CYCLE attribute should be set to 50% to meet the pulse-width requirements at the higher frequencies.

## UltraRAM Switching Characteristics

The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoC that include this memory.

*Table 81: UltraRAM Switching Characteristics*

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3	-2	-1	-2	-1		
<b>Maximum Frequency</b>								
$F_{MAX}$	UltraRAM maximum frequency with OREG_B = True.	650	600	575	500	481	MHz	
$F_{MAX\_ECC}$	UltraRAM maximum frequency with OREG_B = False and EN_ECC_RD_B = True.	450	400	386	325	315	MHz	
$F_{MAX\_NORPIPELINE}$	UltraRAM maximum frequency with OREG_B = False and EN_ECC_RD_B = False.	550	500	478	425	408	MHz	
$T_{PW}^{(1)}$	Minimum pulse width.	650	700	730	800	832	ps	
$T_{RSTPW}$	Asynchronous reset minimum pulse width. One cycle required.	1 clock cycle						

**Notes:**

1. The MMCM and PLL DUTY\_CYCLE attribute should be set to 50% to meet the pulse-width requirements at the higher frequencies.

## Input/Output Delay Switching Characteristics

*Table 82: Input/Output Delay Switching Characteristics*

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3	-2	-1	-2	-1		
$F_{REFCLK}$	REFCLK frequency for IDELAYCTRL (component mode).	300 to 800					MHz	
	REFCLK frequency for BITSLICE_CONTROL (native mode). <sup>(1)</sup>	300 to 2666.67	300 to 2666.67	300 to 2400	300 to 2400	300 to 2133	MHz	
$T_{MINPER\_CLK}$	Minimum period for IODELAY clock.	3.195	3.195	3.195	3.195	3.195	ns	
$T_{MINPER\_RST}$	Minimum reset pulse width.	52.00					ns	
$T_{IDELAY\_RESOLUTION}/T_{ODELAY\_RESOLUTION}$	IDELAY/ODELAY chain resolution.	2.1 to 12					ps	

**Notes:**

1. PLL settings could restrict the minimum allowable data rate. For example, when using a PLL with CLKOUTPHY\_MODE = VCO\_HALF, the minimum frequency is PLL\_FVCOMIN/2.

## DSP48 Slice Switching Characteristics

Table 83: DSP48 Slice Switching Characteristics

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3	-2	-1	-2	-1		
<b>Maximum Frequency</b>								
$F_{MAX}$	With all registers used.	891	775	645	644	600	MHz	
$F_{MAX\_PATDET}$	With pattern detector.	794	687	571	562	524	MHz	
$F_{MAX\_MULT\_NOMREG}$	Two register multiply without MREG.	635	544	456	440	413	MHz	
$F_{MAX\_MULT\_NOMREG\_PATDET}$	Two register multiply without MREG with pattern detect.	577	492	410	395	371	MHz	
$F_{MAX\_PREADD\_NOADREG}$	Without ADREG.	655	565	468	453	423	MHz	
$F_{MAX\_NOPIPELINEREG}$	Without pipeline registers (MREG, ADREG).	483	410	338	323	304	MHz	
$F_{MAX\_NOPIPELINEREG\_PATDET}$	Without pipeline registers (MREG, ADREG) with pattern detect.	448	379	314	299	280	MHz	

## Clock Buffers and Networks

Table 84: Clock Buffers Switching Characteristics

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3	-2	-1	-2	-1		
<b>Global Clock Switching Characteristics (Including BUFGCTRL)</b>								
$F_{MAX}$	Maximum frequency of a global clock tree (BUFG).	891	775	667	725	667	MHz	
<b>Global Clock Buffer with Input Divide Capability (BUFGCE_DIV)</b>								
$F_{MAX}$	Maximum frequency of a global clock buffer with input divide capability (BUFGCE_DIV).	891	775	667	725	667	MHz	
<b>Global Clock Buffer with Clock Enable (BUFGE)</b>								
$F_{MAX}$	Maximum frequency of a global clock buffer with clock enable (BUFGE).	891	775	667	725	667	MHz	
<b>Leaf Clock Buffer with Clock Enable (BUFCE_LEAF)</b>								
$F_{MAX}$	Maximum frequency of a leaf clock buffer with clock enable (BUFCE_LEAF).	891	775	667	725	667	MHz	
<b>GTH or GTY Clock Buffer with Clock Enable and Clock Input Divide Capability (BUFG_GT)</b>								
$F_{MAX}$	Maximum frequency of a serial transceiver clock buffer with clock enable and clock input divide capability.	512	512	512	512	512	MHz	

## MMCM Switching Characteristics

Table 85: MMCM Specification

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V		0.85V		0.72V		
		-3	-2	-1	-2	-1		
MMCM_F <sub>INMAX</sub>	Maximum input clock frequency.	1066	933	800	933	800	MHz	
MMCM_F <sub>INMIN</sub>	Minimum input clock frequency.	10	10	10	10	10	MHz	
MMCM_F <sub>INJITTER</sub>	Maximum input clock period jitter.	< 20% of clock input period or 1 ns Max						
MMCM_F <sub>INDUTY</sub>	Input duty cycle range: 10–49 MHz.	25–75					%	
	Input duty cycle range: 50–199 MHz.	30–70					%	
	Input duty cycle range: 200–399 MHz.	35–65					%	
	Input duty cycle range: 400–499 MHz.	40–60					%	
	Input duty cycle range: >500 MHz.	45–55					%	
MMCM_F <sub>MIN_PSCLK</sub>	Minimum dynamic phase shift clock frequency.	0.01	0.01	0.01	0.01	0.01	MHz	
MMCM_F <sub>MAX_PSCLK</sub>	Maximum dynamic phase shift clock frequency.	550	500	450	500	450	MHz	
MMCM_F <sub>VCOMIN</sub>	Minimum MMCM VCO frequency.	800	800	800	800	800	MHz	
MMCM_F <sub>VCOMAX</sub>	Maximum MMCM VCO frequency.	1600	1600	1600	1600	1600	MHz	
MMCM_F <sub>BANDWIDTH</sub>	Low MMCM bandwidth at typical. <sup>(1)</sup>	1.00	1.00	1.00	1.00	1.00	MHz	
	High MMCM bandwidth at typical. <sup>(1)</sup>	4.00	4.00	4.00	4.00	4.00	MHz	
MMCM_T <sub>STATPHAOFFSET</sub>	Static phase offset of the MMCM outputs. <sup>(2)</sup>	0.12	0.12	0.12	0.12	0.12	ns	
MMCM_T <sub>OUTJITTER</sub>	MMCM output jitter.	Note 3						
MMCM_T <sub>OUTDUTY</sub>	MMCM output clock duty cycle precision. <sup>(4)</sup>	0.165	0.20	0.20	0.20	0.20	ns	
MMCM_T <sub>LOCKMAX</sub>	MMCM maximum lock time for MMCM_F <sub>PFDMIN</sub> .	100	100	100	100	100	μs	
MMCM_F <sub>OUTMAX</sub>	MMCM maximum output frequency.	891	775	667	725	667	MHz	
MMCM_F <sub>OUTMIN</sub>	MMCM minimum output frequency. <sup>(4)(5)</sup>	6.25	6.25	6.25	6.25	6.25	MHz	
MMCM_T <sub>EXTFDVAR</sub>	External clock feedback variation.	< 20% of clock input period or 1 ns Max						
MMCM_RST <sub>MINPULSE</sub>	Minimum reset pulse width.	5.00	5.00	5.00	5.00	5.00	ns	
MMCM_F <sub>PFDMAX</sub>	Maximum frequency at the phase frequency detector.	550	500	450	500	450	MHz	
MMCM_F <sub>PFDMIN</sub>	Minimum frequency at the phase frequency detector.	10	10	10	10	10	MHz	
MMCM_T <sub>FBDELAY</sub>	Maximum delay in the feedback path.	5 ns Max or one clock cycle						

Table 85: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
		0.90V	0.85V		0.72V			
		-3	-2	-1	-2	-1		
MMCM_F <sub>DPRCLK_MAX</sub>	Maximum DRP clock frequency	250	250	250	250	250	MHz	

**Notes:**

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
4. Includes global clock buffer.
5. Calculated as F<sub>VCO</sub>/128 assuming output duty cycle is 50%.

## PLL Switching Characteristics

Table 86: PLL Specification<sup>(1)</sup>

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V	0.85V	0.72V				
		-3	-2	-1	-2	-1		
PLL_F <sub>INMAX</sub>	Maximum input clock frequency.	1066	933	800	933	800	MHz	
PLL_F <sub>INMIN</sub>	Minimum input clock frequency.	70	70	70	70	70	MHz	
PLL_F <sub>INJITTER</sub>	Maximum input clock period jitter.	< 20% of clock input period or 1 ns Max						
PLL_F <sub>INDUTY</sub>	Input duty cycle range: 70–399 MHz.	35–65					%	
	Input duty cycle range: 400–499 MHz.	40–60					%	
	Input duty cycle range: >500 MHz.	45–55					%	
PLL_F <sub>VCOMIN</sub>	Minimum PLL VCO frequency.	750	750	750	750	750	MHz	
PLL_F <sub>VCOMAX</sub>	Maximum PLL VCO frequency.	1500	1500	1500	1500	1500	MHz	
PLL_T <sub>STATPHAOFFSET</sub>	Static phase offset of the PLL outputs. <sup>(2)</sup>	0.12	0.12	0.12	0.12	0.12	ns	
PLL_T <sub>OUTJITTER</sub>	PLL output jitter.	Note 3						
PLL_T <sub>OUTDUTY</sub>	PLL CLKOUT0, CLKOUT0B, CLKOUT1, CLKOUT1B duty-cycle precision. <sup>(4)</sup>	0.165	0.20	0.20	0.20	0.20	ns	
PLL_T <sub>LOCKMAX</sub>	PLL maximum lock time.	100					μs	
PLL_F <sub>OUTMAX</sub>	PLL maximum output frequency at CLKOUT0, CLKOUT0B, CLKOUT1, CLKOUT1B.	891	775	667	725	667	MHz	
	PLL maximum output frequency at CLKOUTPHY.	2667	2667	2400	2400	2133	MHz	
PLL_F <sub>OUTMIN</sub>	PLL minimum output frequency at CLKOUT0, CLKOUT0B, CLKOUT1, CLKOUT1B. <sup>(5)</sup>	5.86	5.86	5.86	5.86	5.86	MHz	
	PLL minimum output frequency at CLKOUTPHY.	2 x VCO mode: 1500, 1 x VCO mode: 750 0.5 x VCO mode: 375					MHz	
PLL_RST <sub>MINPULSE</sub>	Minimum reset pulse width.	5.00	5.00	5.00	5.00	5.00	ns	
PLL_F <sub>PFDMAX</sub>	Maximum frequency at the phase frequency detector.	667.5	667.5	667.5	667.5	667.5	MHz	
PLL_F <sub>PFDMIN</sub>	Minimum frequency at the phase frequency detector.	70	70	70	70	70	MHz	
PLL_F <sub>BANDWIDTH</sub>	PLL bandwidth at typical.	14	14	14	14	14	MHz	
PLL_F <sub>DPRCLK_MAX</sub>	Maximum DRP clock frequency	250	250	250	250	250	MHz	

### Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the loop filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
4. Includes global clock buffer.
5. Calculated as  $F_{VCO}/128$  assuming output duty cycle is 50%.

## Device Pin-to-Pin Output Parameter Guidelines

The pin-to-pin numbers in [Table 87](#) through [Table 89](#) are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

**Table 87: Global Clock Input to Output Delay Without MMCM (Near Clock Region)**

Symbol	Description	Device	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
<b>SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, without MMCM.</b>									
TICKOF	Global clock input and output flip-flop <i>without</i> MMCM (near clock region).	XCZU2	N/A	4.90	5.28	5.35	5.61	ns	
		XCZU3	N/A	4.90	5.28	5.35	5.61	ns	
		XCZU4	4.89	5.83	6.36	6.00	6.79	ns	
		XCZU5	4.89	5.83	6.36	6.00	6.79	ns	
		XCZU6	5.00	5.91	6.35	6.66	7.09	ns	
		XCZU7	5.39	6.54	7.01	7.16	7.62	ns	
		XCZU9	5.00	5.91	6.35	6.66	7.09	ns	
		XCZU11	5.82	6.96	7.61	7.19	8.36	ns	
		XCZU15	5.15	6.09	6.55	6.90	7.38	ns	
		XCZU17	5.72	6.90	7.40	7.62	8.07	ns	
		XCZU19	5.72	6.90	7.40	7.62	8.07	ns	

**Notes:**

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.

Table 88: Global Clock Input to Output Delay Without MMCM (Far Clock Region)

Symbol	Description	Device	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
<b>SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, without MMCM.</b>									
TICKOF_FAR	Global clock input and output flip-flop without MMCM (far clock region).	XCZU2	N/A	5.27	5.68	5.80	6.13	ns	
		XCZU3	N/A	5.27	5.68	5.80	6.13	ns	
		XCZU4	5.07	6.06	6.61	6.23	7.10	ns	
		XCZU5	5.07	6.06	6.61	6.23	7.10	ns	
		XCZU6	5.38	6.49	6.97	7.14	7.59	ns	
		XCZU7	5.39	6.54	7.01	7.16	7.62	ns	
		XCZU9	5.38	6.49	6.97	7.14	7.59	ns	
		XCZU11	6.18	7.41	8.11	7.66	8.99	ns	
		XCZU15	5.38	6.49	6.96	7.19	7.71	ns	
		XCZU17	6.21	7.53	8.07	8.36	8.90	ns	
		XCZU19	6.21	7.53	8.07	8.36	8.90	ns	

**Notes:**

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.

Table 89: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
<b>SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, with MMCM.</b>									
TICKOFMMCMCC	Global clock input and output flip-flop with MMCM.	XCZU2	N/A	2.22	2.43	2.96	2.94	ns	
		XCZU3	N/A	2.22	2.43	2.96	2.94	ns	
		XCZU4	2.47	2.47	2.78	3.04	3.35	ns	
		XCZU5	2.47	2.47	2.78	3.04	3.35	ns	
		XCZU6	2.15	2.15	2.36	2.86	2.86	ns	
		XCZU7	2.32	2.32	2.57	3.06	3.13	ns	
		XCZU9	2.15	2.15	2.36	2.86	2.86	ns	
		XCZU11	2.64	2.64	2.96	3.25	3.55	ns	
		XCZU15	2.18	2.18	2.38	2.88	2.90	ns	
		XCZU17	2.44	2.44	2.66	3.19	3.17	ns	
		XCZU19	2.44	2.44	2.66	3.19	3.17	ns	

**Notes:**

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

## Device Pin-to-Pin Input Parameter Guidelines

The pin-to-pin numbers in [Table 90](#) and [Table 91](#) are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

**Table 90: Global Clock Input Setup and Hold With 3.3V HD I/O without MMCM**

Symbol	Description	Device	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
			0.90V	0.85V	0.72V	-3	-2		
			-3	-2	-1	-2	-1		
<b>Input Setup and Hold Time Relative to Global Clock Input Signal using SSTL15 Standard. <a href="#">(1)</a><a href="#">(2)</a><a href="#">(3)</a></b>									
$T_{PSFD\_ZU2}$	Global clock input and input flip-flop (or latch) without MMCM.	Setup	XCZU2	N/A	2.27	2.37	2.55	2.64	ns
$T_{PHFD\_ZU2}$		Hold			-0.36	-0.36	-0.14	-0.14	ns
$T_{PSFD\_ZU3}$		Setup	XCZU3	N/A	2.27	2.37	2.55	2.64	ns
$T_{PHFD\_ZU3}$		Hold			-0.36	-0.36	-0.14	-0.14	ns
$T_{PSFD\_ZU4}$		Setup	XCZU4	1.28	2.01	2.07	2.59	2.59	ns
$T_{PHFD\_ZU4}$		Hold			-0.28	-0.28	-0.09	-0.09	ns
$T_{PSFD\_ZU5}$		Setup	XCZU5	1.28	2.01	2.07	2.59	2.59	ns
$T_{PHFD\_ZU5}$		Hold			-0.28	-0.28	-0.09	-0.09	ns
$T_{PSFD\_ZU6}$		Setup	XCZU6	0.96	1.79	1.86	1.93	2.02	ns
$T_{PHFD\_ZU6}$		Hold			-0.05	-0.05	-0.05	0.27	0.42
$T_{PSFD\_ZU7}$		Setup	XCZU7	1.43	2.32	2.42	2.60	2.69	ns
$T_{PHFD\_ZU7}$		Hold			-0.40	-0.40	-0.21	-0.21	ns
$T_{PSFD\_ZU9}$		Setup	XCZU9	0.96	1.79	1.86	1.93	2.02	ns
$T_{PHFD\_ZU9}$		Hold			-0.05	-0.05	-0.05	0.27	0.42
$T_{PSFD\_ZU11}$		Setup	XCZU11	1.28	2.01	2.07	2.59	2.59	ns
$T_{PHFD\_ZU11}$		Hold			-0.29	-0.29	-0.09	0.19	ns
$T_{PSFD\_ZU15}$		Setup	XCZU15	0.96	1.79	1.85	1.92	2.01	ns
$T_{PHFD\_ZU15}$		Hold			-0.04	-0.04	-0.04	0.27	0.43
$T_{PSFD\_ZU17}$		Setup	XCZU17	1.41	2.29	2.38	2.57	2.65	ns
$T_{PHFD\_ZU17}$		Hold			-0.38	-0.38	-0.19	-0.19	ns
$T_{PSFD\_ZU19}$		Setup	XCZU19	1.41	2.29	2.38	2.57	2.65	ns
$T_{PHFD\_ZU19}$		Hold			-0.38	-0.38	-0.19	-0.19	ns

### Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, slowest temperature, and slowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, fastest temperature, and fastest voltage.
2. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 91: Global Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
<b>Input Setup and Hold Time Relative to Global Clock Input Signal using SSTL15 Standard.<sup>(1)(2)(3)</sup></b>									
$T_{PSMMCMCC\_ZU2}$	Global clock input and input flip-flop (or latch) with MMCM.	Setup Hold	XCZU2	N/A	1.83	1.96	2.29	2.48	ns
$T_{PHMMCMCC\_ZU2}$					-0.19	-0.19	0.13	0.13	ns
$T_{PSMMCMCC\_ZU3}$		Setup Hold	XCZU3	N/A	1.83	1.96	2.29	2.48	ns
$T_{PHMMCMCC\_ZU3}$					-0.19	-0.19	0.13	0.13	ns
$T_{PSMMCMCC\_ZU4}$		Setup Hold	XCZU4	1.96	1.96	2.10	2.49	2.59	ns
$T_{PHMMCMCC\_ZU4}$					-0.12	-0.12	-0.12	0.27	0.48
$T_{PSMMCMCC\_ZU5}$		Setup Hold	XCZU5	1.96	1.96	2.10	2.49	2.59	ns
$T_{PHMMCMCC\_ZU5}$					-0.12	-0.12	-0.12	0.27	0.48
$T_{PSMMCMCC\_ZU6}$		Setup Hold	XCZU6	1.97	2.00	2.12	2.26	2.44	ns
$T_{PHMMCMCC\_ZU6}$					-0.11	-0.11	-0.11	0.16	0.18
$T_{PSMMCMCC\_ZU7}$		Setup Hold	XCZU7	1.91	1.91	2.02	2.45	2.70	ns
$T_{PHMMCMCC\_ZU7}$					-0.14	-0.14	-0.14	0.37	0.38
$T_{PSMMCMCC\_ZU9}$		Setup Hold	XCZU9	1.97	2.00	2.12	2.26	2.44	ns
$T_{PHMMCMCC\_ZU9}$					-0.11	-0.11	-0.11	0.16	0.18
$T_{PSMMCMCC\_ZU11}$		Setup Hold	XCZU11	2.08	2.08	2.23	2.59	2.75	ns
$T_{PHMMCMCC\_ZU11}$					-0.08	-0.08	0.04	0.35	0.74
$T_{PSMMCMCC\_ZU15}$		Setup Hold	XCZU15	1.96	1.99	2.12	2.26	2.44	ns
$T_{PHMMCMCC\_ZU15}$					-0.10	-0.10	-0.10	0.17	0.19
$T_{PSMMCMCC\_ZU17}$		Setup Hold	XCZU17	1.89	1.89	2.03	2.36	2.55	ns
$T_{PHMMCMCC\_ZU17}$					-0.16	-0.16	-0.16	0.31	0.34
$T_{PSMMCMCC\_ZU19}$		Setup Hold	XCZU19	1.89	1.89	2.03	2.36	2.55	ns
$T_{PHMMCMCC\_ZU19}$					-0.16	-0.16	-0.16	0.31	0.34

**Notes:**

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, slowest temperature, and slowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, fastest temperature, and fastest voltage.
2. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 92: Sampling Window

Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
	0.90V		0.85V		0.72V		
	-3	-2	-1	-2	-1		
T <sub>SAMP_BUFG</sub> <sup>(1)</sup>	510	610	610	610	610	ps	
T <sub>SAMP_NATIVE_DPA</sub>	100	100	125	125	150	ps	
T <sub>SAMP_NATIVE_BISC</sub>	60	60	85	85	110	ps	

**Notes:**

1. This parameter indicates the total sampling error of the Zynq UltraScale+ MPSoC DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include: CLK0 MMCM jitter, MMCM accuracy (phase offset), and MMCM phase shift resolution. These measurements do not include package or clock tree skew.

## Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for clock transmitter and receiver data-valid windows.

Table 93: Package Skew

Symbol	Description	Device	Package	Value	Units
PKGSKEW	Package Skew	XCZU2	SBVA484	105	ps
			SFVA625	108	ps
			SFVC784	93	ps
		XCZU3	SBVA484	105	ps
			SFVA625	108	ps
			SFVC784	93	ps
		XCZU4	SFVC784		ps
			FBVB900		ps
		XCZU5	SFVC784		ps
			FBVB900		ps
		XCZU6	FFVC900	119	ps
			FFVB1156	134	ps
		XCZU7	FBVB900	141	ps
			FFVC1156	175	ps
			FFVF1517	305	ps
		XCZU9	FFVC900	119	ps
			FFVB1156	134	ps
		XCZU11	FFVC1156		ps
			FFVB1517		ps
			FFVF1517		ps
			FFVC1760	215	ps
		XCZU15	FFVC900	118	ps
			FFVB1156	132	ps
		XCZU17	FFVB1517	221	ps
			FFVC1760	226	ps
			FFVD1760	178	ps
			FFVE1924	174	ps
		XCZU19	FFVB1517	221	ps
			FFVC1760	226	ps
			FFVD1760	178	ps
			FFVE1924	174	ps

**Notes:**

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
- Package delay information is available for these device/package combinations. This information can be used to deskew the package.

# GTH Transceiver Specifications

The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoCs that include the GTH transceivers.

## GTH Transceiver DC Input and Output Levels

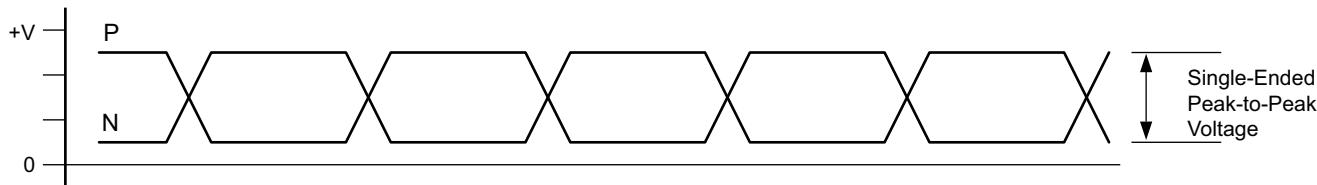
**Table 94** summarizes the DC specifications of the GTH transceivers in Zynq UltraScale+ MPSoC. Consult the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) for further details.

Table 94: GTH Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV <sub>PPIN</sub>	Differential peak-to-peak input voltage (external AC coupled).	> 10.3125 Gb/s	150	—	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	—	1250	mV
		≤ 6.6 Gb/s	150	—	2000	mV
V <sub>IN</sub>	Single-ended input voltage. Voltage measured at the pin referenced to GND.	DC coupled V <sub>MGTAVTT</sub> = 1.2V	-400	—	V <sub>MGTAVTT</sub>	mV
V <sub>CMIN</sub>	Common mode input voltage.	DC coupled V <sub>MGTAVTT</sub> = 1.2V	—	2/3 V <sub>MGTAVTT</sub>	—	mV
D <sub>VPPOUT</sub>	Differential peak-to-peak output voltage. <sup>(1)</sup>	Transmitter output swing is set to 11111	800	—	—	mV
V <sub>CMOUTDC</sub>	Common mode output voltage: DC coupled (equation based).	When remote RX is terminated to GND	V <sub>MGTAVTT</sub> /2 - D <sub>VPPOUT</sub> /4			mV
		When remote RX termination is floating	V <sub>MGTAVTT</sub> - D <sub>VPPOUT</sub> /2			mV
		When remote RX is terminated to V <sub>RX_TERM</sub> <sup>(2)</sup>	V <sub>MGTAVTT</sub> - $\frac{D_{VPPOUT}}{4} - \left( \frac{V_{MGTAVTT} - V_{RX\_TERM}}{2} \right)$			mV
V <sub>CMOUTAC</sub>	Common mode output voltage: AC coupled (equation based).	V <sub>MGTAVTT</sub> - D <sub>VPPOUT</sub> /2			—	mV
R <sub>IN</sub>	Differential input resistance.	—	100	—	—	Ω
R <sub>OUT</sub>	Differential output resistance.	—	100	—	—	Ω
T <sub>OSKEW</sub>	Transmitter output pair (TXP and TXN) intra-pair skew (all packages).	—	—	10	—	ps
C <sub>EXT</sub>	Recommended external AC coupling capacitor. <sup>(3)</sup>	—	100	—	—	nF

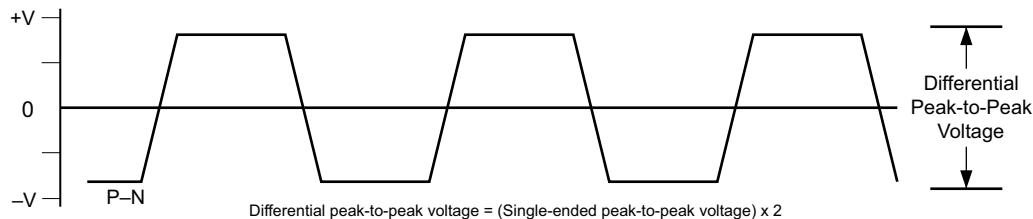
**Notes:**

1. The output swing and pre-emphasis levels are programmable using the attributes discussed in the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)), and can result in values lower than reported in this table.
2. V<sub>RX\_TERM</sub> is the remote RX termination voltage.
3. Other values can be used as appropriate to conform to specific protocols and standards.



X16653-101316

Figure 3: Single-Ended Peak-to-Peak Voltage



X16639-101316

Figure 4: Differential Peak-to-Peak Voltage

[Table 95](#) and [Table 96](#) summarize the DC specifications of the GTH transceivers input and output clocks in Zynq UltraScale+ MPSoC. Consult the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) for further details.

Table 95: GTH Transceiver Clock Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
$V_{IDIFF}$	Differential peak-to-peak input voltage.	250	—	2000	mV
$R_{IN}$	Differential input resistance.	—	100	—	$\Omega$
$C_{EXT}$	Required external AC coupling capacitor.	—	10	—	nF

Table 96: GTH Transceiver Clock Output Level Specification

Symbol	Description	Conditions	Min	Typ	Max	Units
$V_{OL}$	Output Low voltage for P and N.	$R_T = 100\Omega$ across P and N signals	100	—	330	mV
$V_{OH}$	Output High voltage for P and N.	$R_T = 100\Omega$ across P and N signals	500	—	700	mV
$V_{DDOUT}$	Differential output voltage. (P-N), P = High (N-P), N = High	$R_T = 100\Omega$ across P and N signals	300	—	430	mV
$V_{CMOUT}$	Common mode voltage.	$R_T = 100\Omega$ across P and N signals	300	—	500	mV

## GTH Transceiver Switching Characteristics

Consult the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) for further information.

*Table 97: GTH Transceiver Performance*

Symbol	Description	Output Divider	Speed Grade and V <sub>CCINT</sub> Operating Voltages								Units	
			0.90V		0.85V			0.72V				
			-3	-2	-1	-2	-1					
F <sub>GTHMAX</sub>	GTH maximum line rate.		16.375 <sup>(1)</sup>	16.375 <sup>(1)</sup>	12.5	12.5	10.3125	Gb/s				
F <sub>GTHMIN</sub>	GTH minimum line rate.		0.5	0.5	0.5	0.5	0.5	Gb/s				
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>GTHCRANGE</sub>	CPLL line rate range <sup>(2)</sup> .	1	4	12.5	4	12.5	4	8.5	4	8.5	Gb/s	
		2	2	6.25	2	6.25	2	4.25	2	4.25	Gb/s	
		4	1	3.125	1	3.125	1	2.125	1	2.125	Gb/s	
		8	0.5	1.5625	0.5	1.5625	0.5	1.0625	0.5	1.0625	Gb/s	
		16					N/A				Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>GTHQRANGE1</sub>	QPLL0 line rate range <sup>(3)</sup> .	1	9.8	16.375	9.8	16.375	9.8	12.5	9.8	12.5	10.3125 Gb/s	
		2	4.9	8.1875	4.9	8.1875	4.9	8.15	4.9	8.1875	4.9 8.15 Gb/s	
		4	2.45	4.0938	2.45	4.0938	2.45	4.075	2.45	4.0938	2.45 4.075 Gb/s	
		8	1.225	2.0469	1.225	2.0469	1.225	2.0375	1.225	2.0469	1.225 2.0375 Gb/s	
		16	0.6125	1.0234	0.6125	1.0234	0.6125	1.0188	0.6125	1.0234	0.6125 1.0188 Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>GTHQRANGE2</sub>	QPLL1 line rate range <sup>(4)</sup> .	1	8.0	13.0	8.0	13.0	8.0	12.5	8.0	12.5	10.3125 Gb/s	
		2	4.0	6.5	4.0	6.5	4.0	6.5	4.0	6.5	4.0 6.5 Gb/s	
		4	2.0	3.25	2.0	3.25	2.0	3.25	2.0	3.25	2.0 3.25 Gb/s	
		8	1.0	1.625	1.0	1.625	1.0	1.625	1.0	1.625	1.0 1.625 Gb/s	
		16	0.5	0.8125	0.5	0.8125	0.5	0.8125	0.5	0.8125	0.5 0.8125 Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>CPLL RANGE</sub>	CPLL frequency range.	2	6.25	2	6.25	2	4.25	2	4.25	2	4.25 GHz	
F <sub>QPLL0 RANGE</sub>	QPLL0 frequency range.	9.8	16.375	9.8	16.375	9.8	16.375	9.8	16.375	9.8	16.375 GHz	
F <sub>QPLL1 RANGE</sub>	QPLL1 frequency range.	8	13	8	13	8	13	8	13	8	13 GHz	

**Notes:**

1. GTH transceiver line rates in the SFVC784 package support data rates up to 12.5 Gb/s.
2. The values listed are the rounded results of the calculated equation (2 x CPLL\_Frequency)/Output\_Divider.
3. The values listed are the rounded results of the calculated equation (QPLL0\_Frequency)/Output\_Divider.
4. The values listed are the rounded results of the calculated equation (QPLL1\_Frequency)/Output\_Divider.

*Table 98: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics*

Symbol	Description	All Speed Grades	Units
F <sub>GTHDRPCLK</sub>	GTHDRPCLK maximum frequency.	250	MHz

Table 99: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F <sub>GCLK</sub>	Reference clock frequency range.		60	—	820	MHz
T <sub>RCLK</sub>	Reference clock rise time.	20% – 80%	—	200	—	ps
T <sub>FCLK</sub>	Reference clock fall time.	80% – 20%	—	200	—	ps
T <sub>DCREF</sub>	Reference clock duty cycle.	Transceiver PLL only	40	50	60	%

Table 100: GTH Transceiver Reference Clock Oscillator Selection Phase Noise Mask

Symbol	Description	Offset Frequency	Min	Typ	Max	Units
QPLL <sub>REFCLKMASK</sub> <sup>(1)(2)</sup>	QPLL0/QPLL1 reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	—	—	-105	dBc/Hz
		100 kHz	—	—	-124	
		1 MHz	—	—	-130	
CPLL <sub>REFCLKMASK</sub> <sup>(1)(2)</sup>	CPLL reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	—	—	-105	dBc/Hz
		100 kHz	—	—	-124	
		1 MHz	—	—	-130	
		50 MHz	—	—	-140	

**Notes:**

- For reference clock frequencies other than 312.5 MHz, adjust the phase-noise mask values by  $20 \times \log(N/312.5)$  where N is the new reference clock frequency in MHz.
- This reference clock phase-noise mask is superseded by any reference clock phase-noise mask that is specified in a supported protocol, e.g., PCIe.

Table 101: GTH Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T <sub>LOCK</sub>	Initial PLL lock.		—	—	1	ms
T <sub>DLOCK</sub>	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	$37 \times 10^6$	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		—	50,000	$2.3 \times 10^6$	UI

Table 102: GTH Transceiver User Clock Switching Characteristics<sup>(1)</sup>

Symbol	Description	Data Width Conditions (Bit)		Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units
				0.90V	0.85V		0.72V		
		Internal Logic	Interconnect Logic	-3 <sup>(2)</sup>	-2 <sup>(2)(3)</sup>	-1 <sup>(4)(5)</sup>	-2 <sup>(3)</sup>	-1 <sup>(5)</sup>	
F <sub>TXOUTPMA</sub>	TXOUTCLK maximum frequency sourced from OUTCLKPMA			511.719	511.719	390.625	390.625	322.266	MHz
F <sub>RXOUTPMA</sub>	RXOUTCLK maximum frequency sourced from OUTCLKPMA			511.719	511.719	390.625	390.625	322.266	MHz

Table 102: GTH Transceiver User Clock Switching Characteristics<sup>(1)</sup> (Cont'd)

Symbol	Description	Data Width Conditions (Bit)		Speed Grade and $V_{CCINT}$ Operating Voltages					Units
				0.90V	0.85V		0.72V		
		Internal Logic	Interconnect Logic	-3 <sup>(2)</sup>	-2 <sup>(2)(3)</sup>	-1 <sup>(4)(5)</sup>	-2 <sup>(3)</sup>	-1 <sup>(5)</sup>	
$F_{TXOUTPROGDIV}$	TXOUTCLK maximum frequency sourced from TXPROGDIVCLK			511.719	511.719	511.719	511.719	511.719	MHz
$F_{RXOUTPROGDIV}$	RXOUTCLK maximum frequency sourced from RXPROGDIVCLK			511.719	511.719	511.719	511.719	511.719	MHz
$F_{TXIN}$	TXUSRCLK <sup>(6)</sup> maximum frequency	16	16, 32	511.719	511.719	390.625	390.625	322.266	MHz
		32	32, 64	511.719	511.719	390.625	390.625	322.266	MHz
		20	20, 40	409.375	409.375	312.500	312.500	257.813	MHz
		40	40, 80	409.375	409.375	312.500	312.500	257.813	MHz
$F_{RXIN}$	RXUSRCLK <sup>(6)</sup> maximum frequency	16	16, 32	511.719	511.719	390.625	390.625	322.266	MHz
		32	32, 64	511.719	511.719	390.625	390.625	322.266	MHz
		20	20, 40	409.375	409.375	312.500	312.500	257.813	MHz
		40	40, 80	409.375	409.375	312.500	312.500	257.813	MHz
$F_{TXIN2}$	TXUSRCLK2 <sup>(6)</sup> maximum frequency	16	16	511.719	511.719	390.625	390.625	322.266	MHz
		16	32	255.859	255.859	195.313	195.313	161.133	MHz
		32	32	511.719	511.719	390.625	390.625	322.266	MHz
		32	64	255.859	255.859	195.313	195.313	161.133	MHz
		20	20	409.375	409.375	312.500	312.500	257.813	MHz
		20	40	204.688	204.688	156.250	156.250	128.906	MHz
		40	40	409.375	409.375	312.500	312.500	257.813	MHz
		40	80	204.688	204.688	156.250	156.250	128.906	MHz
$F_{RXIN2}$	RXUSRCLK2 <sup>(6)</sup> maximum frequency	16	16	511.719	511.719	390.625	390.625	322.266	MHz
		16	32	255.859	255.859	195.313	195.313	161.133	MHz
		32	32	511.719	511.719	390.625	390.625	322.266	MHz
		32	64	255.859	255.859	195.313	195.313	161.133	MHz
		20	20	409.375	409.375	312.500	312.500	257.813	MHz
		20	40	204.688	204.688	156.250	156.250	128.906	MHz
		40	40	409.375	409.375	312.500	312.500	257.813	MHz
		40	80	204.688	204.688	156.250	156.250	128.906	MHz

**Notes:**

- Clocking must be implemented as described in *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)).
- For speed grades -3E, -2E, and -2I, a 16-bit and 20-bit internal data path can only be used for line rates less than 8.1875 Gb/s.
- For speed grade -2LE, a 16-bit and 20-bit internal data path can only be used for line rates less than 8.1875 Gb/s when  $V_{CCINT} = 0.85V$  or 6.25 Gb/s when  $V_{CCINT} = 0.72V$ .
- For speed grades -1E and -1I, a 16-bit and 20-bit internal data path can only be used for line rates less than 6.25 Gb/s.
- For speed grade -1LI, a 16-bit and 20-bit internal data path can only be used for line rates less than 6.25 Gb/s when  $V_{CCINT} = 0.85V$  or 5.15625 Gb/s when  $V_{CCINT} = 0.72V$ .
- When the gearbox is used, these maximums refer to the XCLK. For more information, see the *Valid Data Width Combinations for TX Asynchronous Gearbox* table in the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)).

Table 103: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTHTX</sub>	Serial data rate range		0.500	–	F <sub>GTHMAX</sub>	Gb/s
T <sub>RTX</sub>	TX rise time	20%–80%	–	21	–	ps
T <sub>FTX</sub>	TX fall time	80%–20%	–	21	–	ps
T <sub>LLSKEW</sub>	TX lane-to-lane skew <sup>(1)</sup>		–	–	500.00	ps
T <sub>J16.375</sub>	Total jitter <sup>(2)(4)</sup>	16.375 Gb/s	–	–	0.28	UI
D <sub>J16.375</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J15.0</sub>	Total jitter <sup>(2)(4)</sup>	15.0 Gb/s	–	–	0.28	UI
D <sub>J15.0</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J14.1</sub>	Total jitter <sup>(2)(4)</sup>	14.1 Gb/s	–	–	0.28	UI
D <sub>J14.1</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J14.1</sub>	Total jitter <sup>(2)(4)</sup>	14.025 Gb/s	–	–	0.28	UI
D <sub>J14.1</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J13.1</sub>	Total jitter <sup>(2)(4)</sup>	13.1 Gb/s	–	–	0.28	UI
D <sub>J13.1</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J12.5_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	12.5 Gb/s	–	–	0.28	UI
D <sub>J12.5_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J12.5_CPLL</sub>	Total jitter <sup>(3)(4)</sup>	12.5 Gb/s	–	–	0.33	UI
D <sub>J12.5_CPLL</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J11.3_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	11.3 Gb/s	–	–	0.28	UI
D <sub>J11.3_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J10.3125_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	10.3125 Gb/s	–	–	0.28	UI
D <sub>J10.3125_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J10.3125_CPLL</sub>	Total jitter <sup>(3)(4)</sup>	10.3125 Gb/s	–	–	0.33	UI
D <sub>J10.3125_CPLL</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J9.953_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	9.953 Gb/s	–	–	0.28	UI
D <sub>J9.953_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J9.953_CPLL</sub>	Total jitter <sup>(3)(4)</sup>	9.953 Gb/s	–	–	0.33	UI
D <sub>J9.953_CPLL</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J8.0</sub>	Total jitter <sup>(3)(4)</sup>	8.0 Gb/s	–	–	0.32	UI
D <sub>J8.0</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J6.6</sub>	Total jitter <sup>(3)(4)</sup>	6.6 Gb/s	–	–	0.30	UI
D <sub>J6.6</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.15	UI
T <sub>J5.0</sub>	Total jitter <sup>(3)(4)</sup>	5.0 Gb/s	–	–	0.30	UI
D <sub>J5.0</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.15	UI
T <sub>J4.25</sub>	Total jitter <sup>(3)(4)</sup>	4.25 Gb/s	–	–	0.30	UI
D <sub>J4.25</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.15	UI
T <sub>J4.0</sub>	Total jitter <sup>(3)(4)</sup>	4.0 Gb/s	–	–	0.32	UI
D <sub>J4.0</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.16	UI
T <sub>J3.20</sub>	Total jitter <sup>(3)(4)</sup>	3.20 Gb/s <sup>(5)</sup>	–	–	0.20	UI
D <sub>J3.20</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.10	UI

Table 103: GTH Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
T <sub>J2.5</sub>	Total jitter <sup>(3)(4)</sup>	2.5 Gb/s <sup>(6)</sup>	–	–	0.20	UI
D <sub>J2.5</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.10	UI
T <sub>J1.25</sub>	Total jitter <sup>(3)(4)</sup>	1.25 Gb/s <sup>(7)</sup>	–	–	0.15	UI
D <sub>J1.25</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.06	UI
T <sub>J500</sub>	Total jitter <sup>(3)(4)</sup>	500 Mb/s <sup>(8)</sup>	–	–	0.10	UI
D <sub>J500</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.03	UI

**Notes:**

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTH Quad) at the maximum line rate.
2. Using QPLL\_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL\_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of 10<sup>-12</sup>.
5. CPLL frequency at 3.2 GHz and TXOUT\_DIV = 2.
6. CPLL frequency at 2.5 GHz and TXOUT\_DIV = 2.
7. CPLL frequency at 2.5 GHz and TXOUT\_DIV = 4.
8. CPLL frequency at 2.0 GHz and TXOUT\_DIV = 8.

Table 104: GTH Transceiver Receiver Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTHR</sub> X	Serial data rate		0.500	–	F <sub>GTHMAX</sub>	Gb/s
R <sub>XSST</sub>	Receiver spread-spectrum tracking <sup>(1)</sup>	Modulated at 33 kHz	–5000	–	0	ppm
R <sub>XRL</sub>	Run length (CID)		–	–	256	UI
R <sub>XPPMTOL</sub>	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm

**SJ Jitter Tolerance<sup>(2)</sup>**

J <sub>T_SJ16.375</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	16.375 Gb/s	0.30	–	–	UI
J <sub>T_SJ15.0</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	15.0 Gb/s	0.30	–	–	UI
J <sub>T_SJ14.1</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	14.1 Gb/s	0.30	–	–	UI
J <sub>T_SJ13.1</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	13.1 Gb/s	0.30	–	–	UI
J <sub>T_SJ12.5</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	12.5 Gb/s	0.30	–	–	UI
J <sub>T_SJ11.3</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	11.3 Gb/s	0.30	–	–	UI
J <sub>T_SJ10.32_QPLL</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	10.32 Gb/s	0.30	–	–	UI
J <sub>T_SJ10.32_CPLL</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	10.32 Gb/s	0.30	–	–	UI
J <sub>T_SJ9.953_QPLL</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	9.953 Gb/s	0.30	–	–	UI
J <sub>T_SJ9.953_CPLL</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	9.953 Gb/s	0.30	–	–	UI
J <sub>T_SJ8.0</sub>	Sinusoidal jitter (QPLL) <sup>(3)</sup>	8.0 Gb/s	0.42	–	–	UI
J <sub>T_SJ6.6_CPLL</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	6.6 Gb/s	0.44	–	–	UI
J <sub>T_SJ5.0</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	5.0 Gb/s	0.44	–	–	UI
J <sub>T_SJ4.25</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	4.25 Gb/s	0.44	–	–	UI
J <sub>T_SJ3.2</sub>	Sinusoidal jitter (CPLL) <sup>(3)</sup>	3.2 Gb/s <sup>(4)</sup>	0.45	–	–	UI

Table 104: GTH Transceiver Receiver Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
J <sub>T</sub> _SJ2.5	Sinusoidal jitter (CPLL) <sup>(3)</sup>	2.5 Gb/s <sup>(5)</sup>	0.30	—	—	UI
J <sub>T</sub> _SJ1.25	Sinusoidal jitter (CPLL) <sup>(3)</sup>	1.25 Gb/s <sup>(6)</sup>	0.30	—	—	UI
J <sub>T</sub> _SJ500	Sinusoidal jitter (CPLL) <sup>(3)</sup>	500 Mb/s <sup>(7)</sup>	0.30	—	—	UI
<b>SJ Jitter Tolerance with Stressed Eye<sup>(2)</sup></b>						
J <sub>T</sub> _TJSE3.2	Total jitter with stressed eye <sup>(8)</sup>	3.2 Gb/s	0.70	—	—	UI
J <sub>T</sub> _TJSE6.6		6.6 Gb/s	0.70	—	—	UI
J <sub>T</sub> _SJSE3.2	Sinusoidal jitter with stressed eye <sup>(8)</sup>	3.2 Gb/s	0.10	—	—	UI
J <sub>T</sub> _SJSE6.6		6.6 Gb/s	0.10	—	—	UI

**Notes:**

1. Using RXOUT\_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of  $10^{-12}$ .
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT\_DIV = 2.
5. CPLL frequency at 2.5 GHz and RXOUT\_DIV = 2.
6. CPLL frequency at 2.5 GHz and RXOUT\_DIV = 4.
7. CPLL frequency at 2.0 GHz and RXOUT\_DIV = 8.
8. Composite jitter with RX equalizer enabled. DFE disabled.

## GTH Transceiver Electrical Compliance

The *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) contains recommended use modes that ensure compliance for the protocols listed in [Table 105](#). The transceiver wizard provides the recommended settings for those use cases and for protocol specific characteristics.

Table 105: GTH Transceiver Protocol List

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
CAUI-10	IEEE 802.3-2012	10.3125	Compliant
nPPI	IEEE 802.3-2012	10.3125	Compliant
10GBASE-KR <sup>(1)</sup>	IEEE 802.3-2012	10.3125	Compliant
40GBASE-KR	IEEE 802.3-2012	10.3125	Compliant
SFP+	SFF-8431 (SR and LR)	9.95328–11.10	Compliant
XFP	INF-8077i, revision 4.5	10.3125	Compliant
RXAUI	CEI-6G-SR	6.25	Compliant
XAUI	IEEE 802.3-2012	3.125	Compliant
1000BASE-X	IEEE 802.3-2012	1.25	Compliant
5.0G Ethernet	IEEE 802.3bx (PAR)	5	Compliant
2.5G Ethernet	IEEE 802.3bx (PAR)	2.5	Compliant
HiGig, HiGig+, HiGig2	IEEE 802.3-2012	3.74, 6.6	Compliant
OTU2	ITU G.8251	10.709225	Compliant
OTU4 (OTL4.10)	OIF-CEI-11G-SR	11.180997	Compliant
OC-3/12/48/192	GR-253-CORE	0.1555–9.956	Compliant
TFI-5	OIF-TFI5-0.1.0	2.488	Compliant
Interlaken	OIF-CEI-6G, OIF-CEI-11G-SR	4.25–12.5	Compliant
PCIe Gen1, 2, 3	PCI Express base 3.0	2.5, 5.0, and 8.0	Compliant
SDI <sup>(2)</sup>	SMPTE 424M-2006	0.27–2.97	Compliant
UHD-SDI <sup>(2)</sup>	SMPTE ST-2081 6G, SMPTE ST-2082 12G	6 and 12	Compliant
Hybrid memory cube (HMC)	HMC-15G-SR	10, 12.5, and 15.0	Compliant
MoSys Bandwidth Engine	CEI-11-SR and CEI-11-SR (overclocked)	10.3125, 15.5	Compliant
CPRI	CPRI_v_6_1_2014-07-01	0.6144–12.165	Compliant
HDMI <sup>(2)</sup>	HDMI 2.0	All	Compliant
Passive optical network (PON)	10G-EAPON, 1G-EAPON, NG-PON2, XG-PON, and 2.5G-PON	0.155–10.3125	Compliant
JESD204a/b	OIF-CEI-6G, OIF-CEI-11G	3.125–12.5	Compliant
Serial RapidIO	RapidIO specification 3.1	1.25–10.3125	Compliant
DisplayPort <sup>(2)</sup>	DP 1.2B CTS	1.62–5.4	Compliant
Fibre channel	FC-PI-4	1.0625–14.025	Compliant
SATA Gen1, 2, 3	Serial ATA revision 3.0 specification	1.5, 3.0, and 6.0	Compliant
SAS Gen1, 2, 3	T10/BSR INCITS 519	3.0, 6.0, and 12.0	Compliant
SFI-5	OIF-SFI5-01.0	0.625–12.5	Compliant
Aurora	CEI-6G, CEI-11G-LR	up to 11.180997	Compliant

**Notes:**

1. The transition time of the transmitter is faster than the IEEE Std 802.3-2012 specification.
2. This protocol requires external circuitry to achieve compliance.

# GTy Transceiver Specifications

The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoCs that include the GTy transceivers.

## GTy Transceiver DC Input and Output Levels

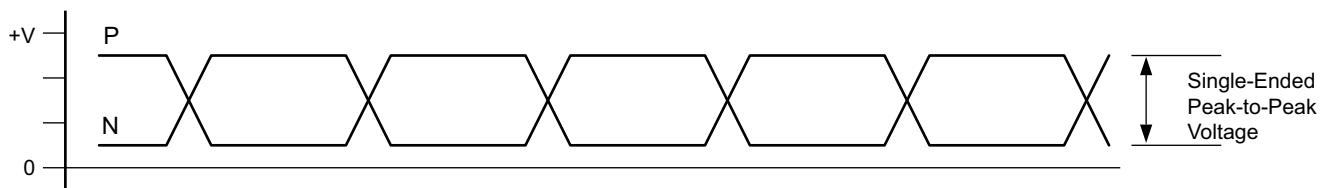
[Table 106](#) and [Table 107](#) summarize the DC specifications of the GTy transceivers in Zynq UltraScale+ MPSoCs. Consult the *UltraScale Architecture GTy Transceiver User Guide* ([UG578](#)) for further details.

*Table 106: GTy Transceiver DC Specifications*

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV <sub>PPIN</sub>	Differential peak-to-peak input voltage (external AC coupled)	> 10.3125 Gb/s	150	—	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	—	1250	mV
		≤ 6.6 Gb/s	150	—	2000	mV
V <sub>IN</sub>	Single-ended input voltage. Voltage measured at the pin referenced to GND.	DC coupled V <sub>MGTAVTT</sub> = 1.2V	-400	—	V <sub>MGTAVTT</sub>	mV
V <sub>CMIN</sub>	Common mode input voltage	DC coupled V <sub>MGTAVTT</sub> = 1.2V	—	2/3 V <sub>MGTAVTT</sub>	—	mV
D <sub>VPPOUT</sub>	Differential peak-to-peak output voltage <sup>(1)</sup>	Transmitter output swing is set to 11111	800	—	—	mV
V <sub>CMOUTDC</sub>	Common mode output voltage: DC coupled (equation based)	When remote RX is terminated to GND	V <sub>MGTAVTT</sub> /2 - D <sub>VPPOUT</sub> /4			mV
		When remote RX termination is floating	V <sub>MGTAVTT</sub> - D <sub>VPPOUT</sub> /2			mV
		When remote RX is terminated to V <sub>RX_TERM</sub> <sup>(2)</sup>	V <sub>MGTAVTT</sub> - $\frac{D_{VPPOUT}}{4} - \left( \frac{V_{MGTAVTT} - V_{RX\_TERM}}{2} \right)$			mV
V <sub>CMOUTAC</sub>	Common mode output voltage: AC coupled	Equation based	V <sub>MGTAVTT</sub> - D <sub>VPPOUT</sub> /2			mV
R <sub>IN</sub>	Differential input resistance	—	100	—	—	Ω
R <sub>OUT</sub>	Differential output resistance	—	100	—	—	Ω
T <sub>OSKEW</sub>	Transmitter output pair (TXP and TXN) intra-pair skew	—	—	10	ps	
C <sub>EXT</sub>	Recommended external AC coupling capacitor <sup>(3)</sup>	—	100	—	—	nF

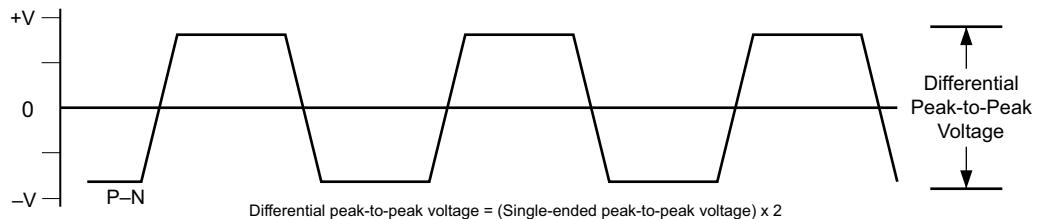
**Notes:**

1. The output swing and pre-emphasis levels are programmable using the GTy transceiver attributes discussed in the *UltraScale Architecture GTy Transceiver User Guide* ([UG578](#)) and can result in values lower than reported in this table.
2. V<sub>RX\_TERM</sub> is the remote RX termination voltage.
3. Other values can be used as appropriate to conform to specific protocols and standards.



X16653-101316

Figure 5: Single-Ended Peak-to-Peak Voltage



X16639-101316

Figure 6: Differential Peak-to-Peak Voltage

[Table 107](#) and [Table 108](#) summarize the DC specifications of the clock input of the GTY transceivers in Zynq UltraScale+ MPSoCs. Consult the *UltraScale Architecture GTY Transceiver User Guide (UG578)* for further details.

Table 107: GTY Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
$V_{IDIFF}$	Differential peak-to-peak input voltage	250	—	2000	mV
$R_{IN}$	Differential input resistance	—	100	—	$\Omega$
$C_{EXT}$	Required external AC coupling capacitor	—	10	—	nF

Table 108: GTY Transceiver Clock Output Level Specification

Symbol	Description	Conditions	Min	Typ	Max	Units
$V_{OL}$	Output Low voltage for P and N	$R_T = 100\Omega$ across P and N signals	100	—	330	mV
$V_{OH}$	Output High voltage for P and N	$R_T = 100\Omega$ across P and N signals	500	—	700	mV
$V_{DDOUT}$	Differential output voltage (P-N), P = High (N-P), N = High	$R_T = 100\Omega$ across P and N signals	300	—	430	mV
$V_{CMOUT}$	Common mode voltage	$R_T = 100\Omega$ across P and N signals	300	—	500	mV

## GTY Transceiver Switching Characteristics

Consult the *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)) for further information.

*Table 109: GTY Transceiver Performance*

Symbol	Description	Output Divider	Speed Grade and V <sub>CCINT</sub> Operating Voltages								Units	
			0.90V		0.85V			0.72V				
			-3	-2	-1	-2	-1					
F <sub>GTYMAX</sub>	GTY maximum line rate		32.75		28.21		25.7813		28.21		12.5 Gb/s	
F <sub>GTYMIN</sub>	GTY minimum line rate		0.5		0.5		0.5		0.5		0.5 Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>GTYCRANGE</sub>	CPLL line rate range <sup>(1)</sup>	1	4.0	12.5	4.0	12.5	4.0	8.5	4.0	12.5	4.0 Gb/s	
		2	2.0	6.25	2.0	6.25	2.0	4.25	2.0	6.25	2.0 Gb/s	
		4	1.0	3.125	1.0	3.125	1.0	2.125	1.0	3.125	1.0 Gb/s	
		8	0.5	1.5625	0.5	1.5625	0.5	1.0625	0.5	1.5625	0.5 Gb/s	
		16	N/A								Gb/s	
		32	N/A								Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>GTYQRANGE1</sub>	QPLL0 line rate range <sup>(2)</sup>	1	19.6	32.75	19.6	28.21	19.6	25.7813	19.6	28.21	N/A Gb/s	
		1	9.8	16.375	9.8	16.375	9.8	12.5	9.8	16.375	9.8 Gb/s	
		2	4.9	8.1875	4.9	8.1875	4.9	8.1875	4.9	8.1875	4.9 Gb/s	
		4	2.45	4.0938	2.45	4.0938	2.45	4.0938	2.45	4.0938	2.45 Gb/s	
		8	1.225	2.0469	1.225	2.0469	1.225	2.0469	1.225	2.0469	1.225 Gb/s	
		16	0.6125	1.0234	0.6125	1.0234	0.6125	1.0234	0.6125	1.0234	0.6125 Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>GTYQRANGE2</sub>	QPLL1 line rate range <sup>(3)</sup>	1	16.0	26.0	16.0	26.0	19.6	25.7813	16.0	26.0	N/A Gb/s	
		1	8.0	13.0	8.0	13.0	8.0	12.5	8.0	13.0	8.0 Gb/s	
		2	4.0	6.5	4.0	6.5	4.0	6.5	4.0	6.5	4.0 Gb/s	
		4	2.0	3.25	2.0	3.25	2.0	3.25	2.0	3.25	2.0 Gb/s	
		8	1.0	1.625	1.0	1.625	1.0	1.625	1.0	1.625	1.0 Gb/s	
		16	0.5	0.8125	0.5	0.8125	0.5	0.8125	0.5	0.8125	0.5 Gb/s	
			Min	Max	Min	Max	Min	Max	Min	Max		
F <sub>CPLL RANGE</sub>	CPLL frequency range	2.0	6.25	2.0	6.25	2.0	4.25	2.0	6.25	2.0	4.25 GHz	
F <sub>QPLL0 RANGE</sub>	QPLL0 frequency range	9.8	16.375	9.8	16.375	9.8	16.375	9.8	16.375	9.8	16.375 GHz	
F <sub>QPLL1 RANGE</sub>	QPLL1 frequency range	8.0	13.0	8.0	13.0	8.0	13.0	8.0	13.0	8.0	13.0 GHz	

**Notes:**

1. The values listed are the rounded results of the calculated equation (2 x CPLL\_Frequency)/Output\_Divider.
2. The values listed are the rounded results of the calculated equation (2 x QPLL0\_Frequency)/Output\_Divider.
3. The values listed are the rounded results of the calculated equation (2 x QPLL1\_Frequency)/Output\_Divider.

Table 110: GTY Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	All Speed Grades			Units
$F_{GTYDRPCLK}$	GTYDRPCLK maximum frequency.	250			MHz

Table 111: GTY Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
$F_{GCLK}$	Reference clock frequency range.		60	—	820	MHz
$T_{RCLK}$	Reference clock rise time.	20% – 80%	—	200	—	ps
$T_{FCLK}$	Reference clock fall time.	80% – 20%	—	200	—	ps
$T_{DCREF}$	Reference clock duty cycle.	Transceiver PLL only	40	50	60	%

Table 112: GTY Transceiver Reference Clock Oscillator Selection Phase Noise Mask<sup>(1)</sup>

Symbol	Description	Offset Frequency	Min	Typ	Max	Units
$QPLL_{REFCLKMASK}$	QPLL0/QPLL1 reference clock select phase noise mask at REFCLK frequency = 156.25 MHz.	10 kHz	—	—	-112	dBc/Hz
		100 kHz	—	—	-128	
		1 MHz	—	—	-145	
	QPLL0/QPLL1 reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	—	—	-103	dBc/Hz
		100 kHz	—	—	-123	
		1 MHz	—	—	-143	
	QPLL0/QPLL1 reference clock select phase noise mask at REFCLK frequency = 625 MHz.	10 kHz	—	—	-98	dBc/Hz
		100 kHz	—	—	-117	
		1 MHz	—	—	-140	
$CPLL_{REFCLKMASK}$	CPLL reference clock select phase noise mask at REFCLK frequency = 156.25 MHz.	10 kHz	—	—	-112	dBc/Hz
		100 kHz	—	—	-128	
		1 MHz	—	—	-145	
		50 MHz	—	—	-145	
	CPLL reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	—	—	-103	dBc/Hz
		100 kHz	—	—	-123	
		1 MHz	—	—	-143	
		50 MHz	—	—	-145	
	CPLL reference clock select phase noise mask at REFCLK frequency = 625 MHz.	10 kHz	—	—	-98	dBc/Hz
		100 kHz	—	—	-117	
		1 MHz	—	—	-140	
		50 MHz	—	—	-144	

**Notes:**

- For reference clock frequencies not in this table, use the phase-noise mask for the nearest reference clock frequency.
- This reference clock phase-noise mask is superseded by any reference clock phase-noise mask that is specified in a supported protocol, e.g., PCIe.

Table 113: GTY Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T <sub>LOCK</sub>	Initial PLL lock.		—	—	1	ms
T <sub>DLOCK</sub>	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	37 x 10 <sup>6</sup>	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		—	50,000	2.3 x 10 <sup>6</sup>	UI

Table 114: GTY Transceiver User Clock Switching Characteristics<sup>(1)</sup>

Symbol	Description	Data Width Conditions (Bit)		Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units
				0.90V	0.85V		0.72V		
		Internal Logic	Interconnect Logic	-3 <sup>(2)</sup>	-2 <sup>(2)(3)</sup>	-1 <sup>(4)(5)</sup>	-2 <sup>(3)</sup>	-1 <sup>(5)</sup>	
F <sub>TXOUTPMA</sub>	TXOUTCLK maximum frequency sourced from OUTCLKPMA	511.719	511.719	402.833	402.833	322.266	322.266	MHz	
F <sub>RXOUTPMA</sub>	RXOUTCLK maximum frequency sourced from OUTCLKPMA	511.719	511.719	402.833	402.833	322.266	322.266	MHz	
F <sub>TXOUTPROGDIV</sub>	TXOUTCLK maximum frequency sourced from TXPROGDIVCLK	511.719	511.719	511.719	511.719	511.719	511.719	MHz	
F <sub>RXOUTPROGDIV</sub>	RXOUTCLK maximum frequency sourced from RXPROGDIVCLK	511.719	511.719	511.719	511.719	511.719	511.719	MHz	
F <sub>TXIN</sub>	TXUSRCLK <sup>(6)</sup> maximum frequency	16	16, 32	511.719	511.719	390.625	390.625	322.266	MHz
		32	32, 64	511.719	511.719	390.625	390.625	322.266	MHz
		64	64, 128	511.719	440.781	402.832	402.832	195.313	MHz
		20	20, 40	409.375	409.375	312.500	312.500	257.813	MHz
		40	40, 80	409.375	409.375	312.500	350.000	257.813	MHz
		80	80, 160	409.375	352.625	322.266	352.625	156.250	MHz
F <sub>RXIN</sub>	RXUSRCLK <sup>(6)</sup> maximum frequency	16	16, 32	511.719	511.719	390.625	390.625	322.266	MHz
		32	32, 64	511.719	511.719	390.625	390.625	322.266	MHz
		64	64, 128	511.719	440.781	402.832	402.832	195.313	MHz
		20	20, 40	409.375	409.375	312.500	312.500	257.813	MHz
		40	40, 80	409.375	409.375	312.500	350.000	257.813	MHz
		80	80, 160	409.375	352.625	322.266	352.625	156.250	MHz

Table 114: GTY Transceiver User Clock Switching Characteristics<sup>(1)</sup> (Cont'd)

Symbol	Description	Data Width Conditions (Bit)		Speed Grade and $V_{CCINT}$ Operating Voltages					Units
				0.90V	0.85V		0.72V		
		Internal Logic	Interconnect Logic	-3 <sup>(2)</sup>	-2 <sup>(2)(3)</sup>	-1 <sup>(4)(5)</sup>	-2 <sup>(3)</sup>	-1 <sup>(5)</sup>	
$F_{TXIN2}$	$TXUSRCLK2^{(6)}$ maximum frequency	16	16	511.719	511.719	390.625	390.625	322.266	MHz
		16	32	255.859	255.859	195.313	195.313	161.133	MHz
		32	32	511.719	511.719	390.625	390.625	322.266	MHz
		32	64	255.859	255.859	195.313	195.313	161.133	MHz
		64	64	511.719	440.781	402.832	402.832	195.313	MHz
		64	128	255.859	220.391	201.416	201.416	97.656	MHz
		20	20	409.375	409.375	312.500	312.500	257.813	MHz
		20	40	204.688	204.688	156.250	156.250	128.906	MHz
		40	40	409.375	409.375	312.500	350.000	257.813	MHz
		40	80	204.688	204.688	156.250	175.000	128.906	MHz
		80	80	409.375	352.625	322.266	352.625	156.250	MHz
		80	160	204.688	176.313	161.133	176.313	78.125	MHz
$F_{RXIN2}$	$RXUSRCLK2^{(6)}$ maximum frequency	16	16	511.719	511.719	390.625	390.625	322.266	MHz
		16	32	255.859	255.859	195.313	195.313	161.133	MHz
		32	32	511.719	511.719	390.625	390.625	322.266	MHz
		32	64	255.859	255.859	195.313	195.313	161.133	MHz
		64	64	511.719	440.781	402.832	402.832	195.313	MHz
		64	128	255.859	220.391	201.416	201.416	97.656	MHz
		20	20	409.375	409.375	312.500	312.500	257.813	MHz
		20	40	204.688	204.688	156.250	156.250	128.906	MHz
		40	40	409.375	409.375	312.500	350.000	257.813	MHz
		40	80	204.688	204.688	156.250	175.000	128.906	MHz
		80	80	409.375	352.625	322.266	352.625	156.250	MHz
		80	160	204.688	176.313	161.133	176.313	78.125	MHz

**Notes:**

1. Clocking must be implemented as described in the *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)).
2. For speed grades -3E, -2E, and -2I, a 16-bit and 20-bit internal data path can only be used for line rates less than 8.1875 Gb/s.
3. For speed grade -2LE, a 16-bit and 20-bit internal data path can only be used for line rates less than 8.1875 Gb/s when  $V_{CCINT} = 0.85V$  or 6.25 Gb/s when  $V_{CCINT} = 0.72V$ .
4. For speed grades -1E and -1I, a 16-bit and 20-bit internal data path can only be used for line rates less than 6.25 Gb/s.
5. For speed grade -1LI, a 16-bit and 20-bit internal data path can only be used for line rates less than 6.25 Gb/s when  $V_{CCINT} = 0.85V$  or 5.15625 Gb/s when  $V_{CCINT} = 0.72V$ .
6. When the gearbox is used, these maximums refer to the XCLK. For more information, see the *Valid Data Width Combinations for TX Asynchronous Gearbox* table in the *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)).

Table 115: GTY Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTYTX</sub>	Serial data rate range		0.500	–	F <sub>GTYMAX</sub>	Gb/s
T <sub>RTX</sub>	TX rise time	20%–80%	–	21	–	ps
T <sub>FTX</sub>	TX fall time	80%–20%	–	21	–	ps
T <sub>LSSKEW</sub>	TX lane-to-lane skew <sup>(1)</sup>		–	–	500.00	ps
T <sub>J32.75</sub>	Total jitter <sup>(2)(4)</sup>	32.75 Gb/s	–	–	0.35	UI
D <sub>J32.75</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.19	UI
T <sub>J28.21</sub>	Total jitter <sup>(2)(4)</sup>	28.21 Gb/s	–	–	0.28	UI
D <sub>J28.21</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J16.375</sub>	Total jitter <sup>(2)(4)</sup>	16.375 Gb/s	–	–	0.28	UI
D <sub>J16.375</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J15.0</sub>	Total jitter <sup>(2)(4)</sup>	15.0 Gb/s	–	–	0.28	UI
D <sub>J15.0</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J14.1</sub>	Total jitter <sup>(2)(4)</sup>	14.1 Gb/s	–	–	0.28	UI
D <sub>J14.1</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J14.1</sub>	Total jitter <sup>(2)(4)</sup>	14.025 Gb/s	–	–	0.28	UI
D <sub>J14.1</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J13.1</sub>	Total jitter <sup>(2)(4)</sup>	13.1 Gb/s	–	–	0.28	UI
D <sub>J13.1</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J12.5_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	12.5 Gb/s	–	–	0.28	UI
D <sub>J12.5_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J12.5_CPLL</sub>	Total jitter <sup>(3)(4)</sup>	12.5 Gb/s	–	–	0.33	UI
D <sub>J12.5_CPLL</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J11.3_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	11.3 Gb/s	–	–	0.28	UI
D <sub>J11.3_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J10.3125_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	10.3125 Gb/s	–	–	0.28	UI
D <sub>J10.3125_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J10.3125_CPLL</sub>	Total jitter <sup>(3)(4)</sup>	10.3125 Gb/s	–	–	0.33	UI
D <sub>J10.3125_CPLL</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J9.953_QPLL</sub>	Total jitter <sup>(2)(4)</sup>	9.953 Gb/s	–	–	0.28	UI
D <sub>J9.953_QPLL</sub>	Deterministic jitter <sup>(2)(4)</sup>		–	–	0.17	UI
T <sub>J9.953_CPLL</sub>	Total jitter <sup>(3)(4)</sup>	9.953 Gb/s	–	–	0.33	UI
D <sub>J9.953_CPLL</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J8.0</sub>	Total jitter <sup>(3)(4)</sup>	8.0 Gb/s	–	–	0.32	UI
D <sub>J8.0</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.17	UI
T <sub>J6.6</sub>	Total jitter <sup>(3)(4)</sup>	6.6 Gb/s	–	–	0.30	UI
D <sub>J6.6</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.15	UI
T <sub>J5.0</sub>	Total jitter <sup>(3)(4)</sup>	5.0 Gb/s	–	–	0.30	UI
D <sub>J5.0</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.15	UI
T <sub>J4.25</sub>	Total jitter <sup>(3)(4)</sup>	4.25 Gb/s	–	–	0.30	UI
D <sub>J4.25</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.15	UI

Table 115: GTY Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
T <sub>J3.20</sub>	Total jitter <sup>(3)(4)</sup>	3.20 Gb/s <sup>(5)</sup>	–	–	0.20	UI
D <sub>J3.20</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.10	UI
T <sub>J2.5</sub>	Total jitter <sup>(3)(4)</sup>	2.5 Gb/s <sup>(6)</sup>	–	–	0.20	UI
D <sub>J2.5</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.10	UI
T <sub>J1.25</sub>	Total jitter <sup>(3)(4)</sup>	1.25 Gb/s <sup>(7)</sup>	–	–	0.15	UI
D <sub>J1.25</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.06	UI
T <sub>J500</sub>	Total jitter <sup>(3)(4)</sup>	500 Mb/s <sup>(8)</sup>	–	–	0.10	UI
D <sub>J500</sub>	Deterministic jitter <sup>(3)(4)</sup>		–	–	0.03	UI

**Notes:**

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTY Quad) at maximum line rate.
2. Using QPLL\_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL\_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of  $10^{-12}$ .
5. CPLL frequency at 3.2 GHz and TXOUT\_DIV = 2.
6. CPLL frequency at 2.5 GHz and TXOUT\_DIV = 2.
7. CPLL frequency at 2.5 GHz and TXOUT\_DIV = 4.
8. CPLL frequency at 2.0 GHz and TXOUT\_DIV = 8.

Table 116: GTY Transceiver Receiver Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
$F_{GTYRX}$	Serial data rate		0.500	–	$F_{GTYMAX}$	Gb/s
$R_{XSST}$	Receiver spread-spectrum tracking <sup>(1)</sup>	Modulated at 33 kHz	-5000	–	0	ppm
$R_{XRL}$	Run length (CID)		–	–	256	UI
$R_{XPMMTOL}$	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	-1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	-700	–	700	ppm
		Bit rates > 8.0 Gb/s	-200	–	200	ppm
<b>SJ Jitter Tolerance<sup>(2)</sup></b>						
$J_{T\_SJ32.75}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	32.75 Gb/s	0.25	–	–	UI
$J_{T\_SJ28.21}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	28.21 Gb/s	0.30	–	–	UI
$J_{T\_SJ16.375}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	16.375 Gb/s	0.30	–	–	UI
$J_{T\_SJ15.0}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	15.0 Gb/s	0.30	–	–	UI
$J_{T\_SJ14.1}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	14.1 Gb/s	0.30	–	–	UI
$J_{T\_SJ13.1}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	13.1 Gb/s	0.30	–	–	UI
$J_{T\_SJ12.5}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	12.5 Gb/s	0.30	–	–	UI
$J_{T\_SJ11.3}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	11.3 Gb/s	0.30	–	–	UI
$J_{T\_SJ10.32\_QPLL}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	10.32 Gb/s	0.30	–	–	UI
$J_{T\_SJ10.32\_CPLL}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	10.32 Gb/s	0.30	–	–	UI
$J_{T\_SJ9.953\_QPLL}$	Sinusoidal jitter (QPLL) <sup>(3)</sup>	9.953 Gb/s	0.30	–	–	UI
$J_{T\_SJ9.953\_CPLL}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	9.953 Gb/s	0.30	–	–	UI
$J_{T\_SJ8.0}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	8.0 Gb/s	0.42	–	–	UI
$J_{T\_SJ6.6}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	6.6 Gb/s	0.44	–	–	UI
$J_{T\_SJ5.0}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	5.0 Gb/s	0.44	–	–	UI
$J_{T\_SJ4.25}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	4.25 Gb/s	0.44	–	–	UI
$J_{T\_SJ3.2}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	3.2 Gb/s <sup>(4)</sup>	0.45	–	–	UI
$J_{T\_SJ2.5}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	2.5 Gb/s <sup>(5)</sup>	0.30	–	–	UI
$J_{T\_SJ1.25}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	1.25 Gb/s <sup>(6)</sup>	0.30	–	–	UI
$J_{T\_SJ500}$	Sinusoidal jitter (CPLL) <sup>(3)</sup>	500 Mb/s <sup>(7)</sup>	0.30	–	–	UI
<b>SJ Jitter Tolerance with Stressed Eye<sup>(2)</sup></b>						
$J_{T\_TJSE3.2}$	Total jitter with stressed eye <sup>(8)</sup>	3.2 Gb/s	0.70	–	–	UI
		6.6 Gb/s	0.70	–	–	UI
$J_{T\_TJSE6.6}$	Sinusoidal jitter with stressed eye <sup>(8)</sup>	3.2 Gb/s	0.10	–	–	UI
		6.6 Gb/s	0.10	–	–	UI

**Notes:**

1. Using RXOUT\_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of  $10^{-12}$ .
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT\_DIV = 2.
5. CPLL frequency at 2.5 GHz and RXOUT\_DIV = 2.
6. CPLL frequency at 2.5 GHz and RXOUT\_DIV = 4.
7. CPLL frequency at 2.0 GHz and RXOUT\_DIV = 8.
8. Composite jitter with RX equalizer enabled. DFE disabled.

## GTY Transceiver Electrical Compliance

The *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)) contains recommended use modes that ensure compliance for the protocols listed in [Table 117](#). The transceiver wizard provides the recommended settings for those use cases and for protocol specific characteristics.

*Table 117: GTY Transceiver Protocol List*

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
CAUI-4	IEEE 802.3-2012	25.78125	Compliant
28 Gb/s backplane	CEI-25G-LR	25–28.05	Compliant
Interlaken	OIF-CEI-6G, OIF-CEI-11GSR, OIF-CEI-28G-MR	4.25–25.78125	Compliant
100GBASE-KR4	IEEE 802.3bj-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
100GBASE-CR4	IEEE 802.3bj-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
50GBASE-KR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
50GBASE-CR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
25GBASE-KR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
25GBASE-CR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant <sup>(1)</sup>
OTU4 (OTL4.4) CFP2	OIF-CEI-28G-VSR	27.952493–32.75	Compliant
OTU4 (OTL4.4) CFP	OIF-CEI-11G-MR	11.18–13.1	Compliant
CAUI-10	IEEE 802.3-2012	10.3125	Compliant
nPPI	IEEE 802.3-2012	10.3125	Compliant
10GBASE-KR <sup>(2)</sup>	IEEE 802.3-2012	10.3125	Compliant
SFP+	SFF-8431 (SR and LR)	9.95328–11.10	Compliant
XFP	INF-8077i, revision 4.5	10.3125	Compliant
RXAUI	CEI-6G-SR	6.25	Compliant
XAUI	IEEE 802.3-2012	3.125	Compliant
1000BASE-X	IEEE 802.3-2012	1.25	Compliant
5.0G Ethernet	IEEE 802.3bx (PAR)	5	Compliant
2.5G Ethernet	IEEE 802.3bx (PAR)	2.5	Compliant
HiGig, HiGig+, HiGig2	IEEE 802.3-2012	3.74, 6.6	Compliant
QSGMII	QSGMII v1.2 (Cisco System, ENG-46158)	5	Compliant
OTU2	ITU G.8251	10.709225	Compliant
OTU4 (OTL4.10)	OIF-CEI-11G-SR	11.180997	Compliant
OC-3/12/48/192	GR-253-CORE	0.1555–9.956	Compliant
PCIe Gen1, 2, 3	PCI Express base 3.0	2.5, 5.0, and 8.0	Compliant
SDI <sup>(3)</sup>	SMPTE 424M-2006	0.27–2.97	Compliant
UHD-SDI <sup>(3)</sup>	SMPTE ST-2081 6G, SMPTE ST-2082 12G	6 and 12	Compliant
Hybrid memory cube (HMC)	HMC-15G-SR	10, 12.5, and 15.0	Compliant
MoSys bandwidth engine	CEI-11-SR and CEI-11-SR (overclocked)	10.3125, 15.5	Compliant
CPRI	CPRI_v_6_1_2014-07-01	0.6144–12.165	Compliant
Passive optical network (PON)	10G-EPON, 1G-EPON, NG-PON2, XG-PON, and 2.5G-PON	0.155–10.3125	Compliant
JESD204a/b	OIF-CEI-6G, OIF-CEI-11G	3.125–12.5	Compliant

Table 117: GTY Transceiver Protocol List (Cont'd)

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
Serial RapidIO	RapidIO specification 3.1	1.25–10.3125	Compliant
DisplayPort	DP 1.2B CTS	1.62–5.4	Compliant <sup>(3)</sup>
Fibre channel	FC-PI-4	1.0625–14.025	Compliant
SATA Gen1, 2, 3	Serial ATA revision 3.0 specification	1.5, 3.0, and 6.0	Compliant
SAS Gen1, 2, 3	T10/BSR INCITS 519	3.0, 6.0, and 12.0	Compliant
SFI-5	OIF-SFI5-01.0	0.625 - 12.5	Compliant
Aurora	CEI-6G, CEI-11G-LR	All rates	Compliant

**Notes:**

1. 25 dB loss at Nyquist without FEC.
2. The transition time of the transmitter is faster than the IEEE Std 802.3-2012 specification.
3. This protocol requires external circuitry to achieve compliance.

## Integrated Interface Block for Interlaken

More information and documentation on solutions using the integrated interface block for Interlaken can be found at [UltraScale+ Interlaken](#). The *UltraScale Architecture and Product Overview* ([DS890](#)) lists how many blocks are in each Zynq UltraScale+ MPSoC. This section describes the following Interlaken configurations.

- 12 x 12.5 Gb/s protocol and lane logic mode ([Table 118](#)).
- 6 x 25.78125 Gb/s and 6 x 28.21 Gb/s protocol and lane logic mode ([Table 119](#)).
- 12 x 25.78125 Gb/s lane logic only mode ([Table 120](#)).

Zynq UltraScale+ MPSoCs in the SFVB784, FFVA676, and FFVA1156 packages are only supported using the 12 x 12.5 Gb/s Interlaken configuration. See [Table 109](#) for the  $F_{GTYMAX}$  description.

**Table 118: Maximum Performance for Interlaken 12 x 12.5 Gb/s Protocol and Lane Logic Mode Designs**

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages						Units
		0.90V		0.85V		0.72V		
		-3	-2	-1	-2	-1		
$F_{RX\_SERDES\_CLK}$	Receive serializer/deserializer clock	195.32	195.32	195.32	195.32	195.32	195.32	MHz
$F_{TX\_SERDES\_CLK}$	Transmit serializer/deserializer clock	195.32	195.32	195.32	195.32	195.32	195.32	MHz
$F_{DRP\_CLK}$	Dynamic reconfiguration port clock	250.00	250.00	250.00	250.00	250.00	250.00	MHz
		Min <sup>(1)</sup>	Max	Min <sup>(1)</sup>	Max	Min <sup>(1)</sup>	Max	Min <sup>(1)</sup>
$F_{CORE\_CLK}$	Interlaken core clock	300.00	322.27	300.00	322.27	300.00	322.27	300.00
$F_{LBUS\_CLK}$	Interlaken local bus clock	300.00	322.27	300.00	322.27	300.00	322.27	300.00

**Notes:**

1. These are the minimum clock frequencies at the maximum lane performance.

**Table 119: Maximum Performance for Interlaken 6 x 25.78125 Gb/s and 6 x 28.21 Gb/s Protocol and Lane Logic Mode Designs**

Symbol	Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages								Units	
		0.90V		0.85V			0.72V				
		-3 <sup>(1)</sup>	-2 <sup>(1)</sup>	-1	-2	-1					
F <sub>RX_SERDES_CLK</sub>	Receive serializer/deserializer clock	440.79	440.79	N/A	402.84	N/A				MHz	
F <sub>TX_SERDES_CLK</sub>	Transmit serializer/deserializer clock	440.79	440.79	N/A	402.84	N/A				MHz	
F <sub>DRP_CLK</sub>	Dynamic reconfiguration port clock	250.00	250.00	N/A	250.00	N/A				MHz	
		Min <sup>(2)</sup>	Max	Min <sup>(2)</sup>	Max	Min	Max	Min <sup>(2)</sup>	Max	Min Max	
F <sub>CORE_CLK</sub>	Interlaken core clock	412.50 <sup>(3)</sup>	479.20	412.50 <sup>(3)</sup>	479.20	N/A	412.50	429.69	N/A	MHz	
F <sub>LBUS_CLK</sub>	Interlaken local bus clock	300.00 <sup>(4)</sup>	349.52	300.00 <sup>(4)</sup>	349.52	N/A	300.00	349.52	N/A	MHz	

**Notes:**

1. 6 x 28.21 mode is only supported in the -2 (V<sub>CCINT</sub>=0.85V) and -3 (V<sub>CCINT</sub>=0.90V) speed grades.
2. These are the minimum clock frequencies at the maximum lane performance.
3. The minimum value for CORE\_CLK is 451.36 MHz for the 6 x 28.21 Gb/s protocol.
4. The minimum value for LBUS\_CLK is 330.00 MHz for the 6 x 28.21 Gb/s protocol.

**Table 120: Maximum Performance for Interlaken 12 x 25.78125 Gb/s Lane Logic Only Mode Designs**

Symbol	Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages						Units		
		0.90V		0.85V			0.72V			
		-3	-2	-1	-2	-1				
F <sub>RX_SERDES_CLK</sub>	Receive serializer/deserializer clock	402.84	402.84	N/A	N/A	N/A	N/A	MHz		
F <sub>TX_SERDES_CLK</sub>	Transmit serializer/deserializer clock	402.84	402.84	N/A	N/A	N/A	N/A	MHz		
F <sub>DRP_CLK</sub>	Dynamic reconfiguration port clock	250.00	250.00	N/A	N/A	N/A	N/A	MHz		
F <sub>CORE_CLK</sub>	Interlaken core clock	412.50	412.50	N/A	N/A	N/A	N/A	MHz		
F <sub>LBUS_CLK</sub>	Interlaken local bus clock	349.52	349.52	N/A	N/A	N/A	N/A	MHz		

## Integrated Interface Block for 100G Ethernet MAC and PCS

More information and documentation on solutions using the integrated 100 Gb/s Ethernet block can be found at [UltraScale+ Integrated 100G Ethernet MAC/PCS](#). The *UltraScale Architecture and Product Overview* ([DS890](#)) lists how many blocks are in each Zynq UltraScale+ MPSoC.

**Table 121: Maximum Performance for 100G Ethernet Designs**

Symbol	Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
		0.90V		0.85V		0.72V		
		-3	-2 <sup>(1)</sup>	-1	-2	-1 <sup>(2)</sup>		
F <sub>TX_CLK</sub>	Transmit clock	390.625	390.625	322.223	322.223	322.223	MHz	
F <sub>RX_CLK</sub>	Receive clock	390.625	390.625	322.223	322.223	322.223	MHz	
F <sub>RX_SERDES_CLK</sub>	Receive serializer/deserializer clock	390.625	390.625	322.223	322.223	322.223	MHz	
F <sub>DRP_CLK</sub>	Dynamic reconfiguration port clock	250.00	250.00	250.00	250.00	250.00	MHz	

**Notes:**

1. The maximum clock frequency of 390.625 MHz only applies to the CAUI-10 interface. The maximum clock frequency for the CAUI-4 interface is 322.223 MHz.
2. The CAUI-4 interface is not supported by -1L speed grade devices where V<sub>CCINT</sub>=0.72V.

## Integrated Interface Block for PCI Express Designs

More information and documentation on solutions for PCI Express designs can be found at [PCI Express](#). The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoCs that include this block.

**Table 122: Maximum Performance for PCI Express Designs<sup>(1)(2)</sup>**

Symbol	Description	Speed Grade and V <sub>CCINT</sub> Operating Voltages					Units	
		0.90V		0.85V		0.72V		
		-3	-2	-1	-2	-1		
F <sub>PIPECLK</sub>	Pipe clock maximum frequency.	250.00	250.00	250.00	250.00	250.00	MHz	
F <sub>CORECLK</sub>	Core clock maximum frequency.	500.00	500.00	500.00	250.00	250.00	MHz	
F <sub>DRPCLK</sub>	DRP clock maximum frequency.	250.00	250.00	250.00	250.00	250.00	MHz	
F <sub>MCAPCLK</sub>	MCAP clock maximum frequency.	125.00	125.00	125.00	125.00	125.00	MHz	

**Notes:**

1. PCI Express Gen4 operation is supported for x1, x2, x4, and x8 widths.
2. PCI Express Gen4 operation is supported in -3E, -2E, and -2I speed grades.

## Video Codec Performance

The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoC EV devices that include the Video Codec unit (VCU).

*Table 123: VCU Performance*

Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
	0.90V	0.85V		0.72V			
	-3	-2	-1	-2	-1		
Video Codec decoder block maximum frequency (H.264/5 10-bit 4:2:2)	667	667	667	667	667	MHz	

## PL System Monitor Specifications

*Table 124: PL SYSMON Specifications*

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$V_{CCADC} = 1.8V \pm 3\%$ , $V_{REFP} = 1.25V$ , $V_{REFN} = 0V$ , $ADCCLK = 5.2$ MHz, $T_j = -40^{\circ}C$ to $100^{\circ}C$ , typical values at $T_j = 40^{\circ}C$						
<b>ADC Accuracy<sup>(1)</sup></b>						
Resolution			10	–	–	Bits
Integral nonlinearity <sup>(2)</sup>	INL		–	–	$\pm 1.5$	LSBs
Differential nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	$\pm 1$	LSBs
Offset error		Offset calibration enabled	–	–	$\pm 2$	LSBs
Gain error			–	–	$\pm 0.4$	%
Sample rate			–	–	0.2	MS/s
RMS code noise		External 1.25V reference	–	–	1	LSBs
		On-chip reference	–	1	–	LSBs
<b>ADC Accuracy at Extended Temperatures</b>						
Resolution		$T_j = -55^{\circ}C$ to $125^{\circ}C$	10	–	–	Bits
Integral nonlinearity <sup>(2)</sup>	INL	$T_j = -55^{\circ}C$ to $125^{\circ}C$	–	–	$\pm 1.5$	LSBs
Differential nonlinearity	DNL	No missing codes, guaranteed monotonic ( $T_j = -55^{\circ}C$ to $125^{\circ}C$ )	–	–	$\pm 1$	
<b>Analog Inputs<sup>(2)</sup></b>						
ADC input ranges		Unipolar operation	0	–	1	V
		Bipolar operation	-0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum external channel input ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	-0.1	–	$V_{CCADC}$	V

Table 124: PL SYSMON Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
<b>On-Chip Sensor Accuracy</b>						
Temperature sensor error <sup>(1)(3)</sup>		T <sub>j</sub> = -55°C to 125°C (with external REF)	-	-	±3	°C
		T <sub>j</sub> = -55°C to 110°C (with internal REF)	-	-	±3.5	°C
		T <sub>j</sub> = 110°C to 125°C (with internal REF)	-	-	±5	°C
Supply sensor error <sup>(4)</sup>		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -40°C to 100°C (with external REF)	-	-	±0.5	%
		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -55°C to 125°C (with external REF)	-	-	±1.0	%
		All other supply voltages, T <sub>j</sub> = -40°C to 100°C (with external REF)	-	-	±1.0	%
		All other supply voltages, T <sub>j</sub> = -55°C to 125°C (with external REF)	-	-	±2.0	%
		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -40°C to 100°C (with internal REF)	-	-	±1.0	%
		Supply voltages 0.72V to 1.2V, T <sub>j</sub> = -55°C to 125°C (with internal REF)	-	-	±2.0	%
		All other supply voltages, T <sub>j</sub> = -40°C to 100°C (with internal REF)	-	-	±1.5	%
		All other supply voltages, T <sub>j</sub> = -55°C to 125°C (with internal REF)	-	-	±2.5	%
<b>Conversion Rate<sup>(5)</sup></b>						
Conversion time—continuous	t <sub>CONV</sub>	Number of ADCCLK cycles	26	-	32	Cycles
Conversion time—event	t <sub>CONV</sub>	Number of ADCCLK cycles	-	-	21	Cycles
DRP clock frequency	DCLK	DRP clock frequency	8	-	250	MHz
ADC clock frequency	ADCCLK	Derived from DCLK	1	-	5.2	MHz
DCLK duty cycle			40	-	60	%
<b>SYSMON Reference<sup>(6)</sup></b>						
External reference	V <sub>REFP</sub>	Externally supplied reference voltage	1.20	1.25	1.30	V
On-chip reference		Ground V <sub>REFP</sub> pin to AGND, T <sub>j</sub> = -40°C to 100°C	1.2375	1.25	1.2625	V
		Ground V <sub>REFP</sub> pin to AGND, T <sub>j</sub> = -55°C to 125°C	1.225	1.25	1.275	V

**Notes:**

1. ADC offset errors are removed by enabling the ADC automatic offset calibration feature. The values are specified for when this feature is enabled.
2. See the *Analog Input* section in the *UltraScale Architecture System Monitor User Guide* ([UG580](#)).
3. When reading temperature values directly from the PMBus interface, the SYSMON has a +4°C offset due to the transfer function used by the PMBus application. For example, the external REF temperature sensor error's range of ±3°C becomes +1°C to +7°C when the temperature is read through the PMBus interface.
4. Supply sensor offset and gain errors are removed by enabling the automatic offset and gain calibration feature. The values are specified for when this feature is enabled.
5. See the *Adjusting the Acquisition Settling Time* section in the *UltraScale Architecture System Monitor User Guide* ([UG580](#)).
6. Any variation in the reference voltage from the nominal V<sub>REFP</sub> = 1.25V and V<sub>REFN</sub> = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by ±4% is permitted.

## PL SYSMON I2C/PMBus Interfaces

Table 125: PL SYSMON I2C Fast Mode Interface Switching Characteristics<sup>(1)</sup>

Symbol	Description	Min	Max	Units
$T_{SMFCKL}$	SCL Low time	1.3	–	μs
$T_{SMFCKH}$	SCL High time	0.6	–	μs
$T_{SMFCKO}$	SDAO clock-to-out delay	–	900	ns
$T_{SMFDCK}$	SDAI setup time	100	–	ns
$F_{SMFCLK}$	SCL clock frequency	–	400	kHz

**Notes:**

1. The test conditions are configured to the LVC MOS 1.8V I/O standard.

Table 126: PL SYSMON I2C Standard Mode Interface Switching Characteristics<sup>(1)</sup>

Symbol	Description	Min	Max	Units
$T_{SMSCKL}$	SCL Low time	4.7	–	μs
$T_{SMSCKH}$	SCL High time	4.0	–	μs
$T_{SMSCKO}$	SDAO clock-to-out delay	–	3450	ns
$T_{SMSDCK}$	SDAI setup time	250	–	ns
$F_{SMSCLK}$	SCL clock frequency	–	100	kHz

**Notes:**

1. The test conditions are configured to the LVC MOS 1.8V I/O standard.

# Configuration Switching Characteristics

Table 127: Configuration Switching Characteristics

Symbol	Description	Speed Grade and $V_{CCINT}$ Operating Voltages					Units	
		0.90V		0.85V		0.72V		
		-3	-2	-1	-2	-1		
<b>PL Power-up Timing Characteristics</b>								
T <sub>PL</sub>	PS_PROG_B PL latency.	7.5	7.5	7.5	7.5	7.5	ms, Max	
T <sub>POR</sub>	Power-on reset from PL power-on to PL ready to configure (40 ms maximum ramp rate).	65	65	65	65	65	ms, Max	
		0	0	0	0	0	ms, Min	
T <sub>PS_PROG_B</sub>	Power-on reset from PL power-on to PL ready to configure with POR override (2 ms maximum ramp rate).	15	15	15	15	15	ms, Max	
		5	5	5	5	5	ms, Min	
T <sub>PS_PROG_B</sub>	PL program pulse width.	250	250	250	250	250	ns, Min	
<b>Internal Configuration Access Port</b>								
F <sub>ICAPCK</sub>	Internal configuration access port (ICAPE3).	200	200	200	150	150	MHz, Max	
<b>DNA Port Switching</b>								
F <sub>DNACK</sub>	DNA port frequency (DNA_PORT).	200	200	200	175	175	MHz, Max	
<b>STARTUPE3 Ports</b>								
F <sub>CFGMCLK</sub>	STARTUPE3 CFGMCLK output frequency.	50.00	50.00	50.00	50.00	50.00	MHz, Typ	
F <sub>CFGMCLKTOL</sub>	STARTUPE3 CFGMCLK output frequency tolerance.	±15	±15	±15	±15	±15	%, Max	
T <sub>DCI_MATCH</sub>	Specifies a stall in the startup cycle until the digitally controlled impedance (DCI) match signals are asserted.	4	4	4	4	4	ms, Max	

## Revision History

The following table shows the revision history for this document.

Date	Version	Description of Revisions
04/20/2017	1.3	<p>Updated <a href="#">Table 25</a>, <a href="#">Table 26</a>, and <a href="#">Table 27</a> to production release for the following devices/speed/temperature grades in Vivado Design Suite 2017.1.</p> <p>XCZU2CG and XCZU2EG: -2E, -2I, -1E, -1I      XCZU3CG and XCZU3EG: -2E, -2I, -1E, -1I      XCZU6CG and XCZU6EG: -2E, -2I, -1E, -1I      XCZU9CG and XCZU9EG: -2E, -2I, -1E, -1I</p> <p>Added -2E (<math>V_{CCINT} = 0.85V</math>) speed grade where applicable. Removed -3E speed grade from the XCZU2 and XCZU3 devices in <a href="#">Table 26</a> and where applicable.</p> <p>In <a href="#">Table 1</a>, updated values and <a href="#">Note 2</a>. In <a href="#">Table 2</a>, added or updated many of the notes. Updated <a href="#">Table 4</a> including the notes and added <a href="#">Note 6</a>. Moved and updated <a href="#">Table 5</a>. Added <a href="#">Table 8</a>. Updated <a href="#">Table 9</a> and added <a href="#">Note 4</a>. Updated <a href="#">Table 10</a> and added <a href="#">Note 1</a>.</p> <p>Revised <math>V_{ICM}</math> in <a href="#">Table 23</a>. Updated <a href="#">Table 30</a> and removed Note 1. Added <a href="#">Table 31</a> and <a href="#">Table 32</a>. Updated <a href="#">Table 33</a> and removed <math>F_{FTMCLK}</math>. Updated <math>T_{RFPSCLK}</math> in <a href="#">Table 34</a>. Updated <a href="#">Note 1</a> in <a href="#">Table 37</a>. Updated <a href="#">Table 39</a>. Removed the <i>PS NAND Memory Controller Interface</i> section. Significant changes to <a href="#">Table 41</a> and removed Note 3. Significant changes to <a href="#">Table 42</a> and updated <a href="#">Note 1</a>. Removed <math>F_{TSU\_REF\_CLK}</math> from <a href="#">Table 44</a>. Revised <a href="#">Table 45</a> and added <a href="#">Note 2</a> and <a href="#">Note 3</a>. Revised <a href="#">Table 46</a> and added <a href="#">Note 2</a> and <a href="#">Note 3</a>. Updated <a href="#">Table 48</a>. Updated <a href="#">Table 51</a> and removed Note 2. Revised <a href="#">Table 52</a>. Revised many of the tables in the <i>PS-GTR Transceiver</i> section. Revised <a href="#">Table 70</a> and <a href="#">Table 71</a>. Removed Note 8 from <a href="#">Table 74</a>.</p> <p>Updated the values in <a href="#">Table 75</a>, <a href="#">Table 76</a>, <a href="#">Table 77</a>, <a href="#">Table 80</a>, <a href="#">Table 87</a>, <a href="#">Table 88</a>, <a href="#">Table 89</a>, <a href="#">Table 90</a>, and <a href="#">Table 91</a> to the Vivado Design Suite 2017.1 speed specifications.</p> <p>Updated the values in <a href="#">Table 81</a> and <a href="#">Table 82</a>. Added values to <a href="#">Table 92</a>. Updated <a href="#">Table 93</a>. Revised <math>D_{VPPOUT}</math> in <a href="#">Table 94</a>. Update the values in <a href="#">Table 96</a>. Added <a href="#">Note 6</a> to <a href="#">Table 102</a>. Updated <a href="#">Table 103</a> and <a href="#">Table 104</a>. Revised <math>D_{VPPOUT}</math> in <a href="#">Table 106</a>. Updated the values in <a href="#">Table 108</a>. In <a href="#">Table 109</a> updated the -1 (0.85V) specifications and removed Note 1. In <a href="#">Table 114</a> updated the -1 (0.85V) specifications and added <a href="#">Note 6</a>. In <a href="#">Table 115</a> and <a href="#">Table 116</a>, added the 28.21 jitter tolerance values and revised the notes. Revised the <i>Integrated Interface Block for Interlaken</i> and <i>Integrated Interface Block for 100G Ethernet MAC and PCS</i> sections. Revised the <i>Configuration Switching Characteristics</i> section. Removed the <i>eFUSE Programming Conditions</i> table and added the specifications to <a href="#">Table 2</a> and <a href="#">Table 3</a>.</p>

Date	Version	Description of Revisions
02/10/2017	1.2	<p>Updated some of the maximum voltages in the <a href="#">Processor System (PS)</a> section and other specifications in the <a href="#">Programmable Logic (PL)</a> and <a href="#">GTH or GTY Transceiver</a> sections of <a href="#">Table 1</a>. Updated <a href="#">Table 2</a>, <a href="#">Table 4</a>, <a href="#">Table 6</a>, <a href="#">Table 7</a>, and <a href="#">Table 9</a>. Revised the <a href="#">Power Supply Sequencing</a> section including <a href="#">Table 10</a>. Added PS and VCU ramp times to <a href="#">Table 11</a>. Revised <math>V_{ODIFF}</math> in <a href="#">Table 24</a>. Updated <a href="#">Table 25</a>. Added <a href="#">Note 1</a> to <a href="#">Table 26</a>. <a href="#">Table 30</a> replaces the previous three PS memory performance tables. Added values to <a href="#">Table 34</a>, <a href="#">Table 37</a>, and <a href="#">Table 38</a>. Deleted the waveforms in the PS Switching Characteristics section (Figures 1-16 and Figures 25-26). Revised values in the <a href="#">PS NAND Memory Controller Interface</a> section. Added and updated data in <a href="#">Table 40</a>. Added Note 3 to <a href="#">Table 41</a>. Added Note 3 to <a href="#">Table 42</a>. Added <a href="#">Note 1</a> to <a href="#">Table 45</a>. Updated <a href="#">Table 48</a> and removed Note 3. Added data to <a href="#">Table 56</a>. Updated <a href="#">Table 60</a>. Added <a href="#">Table 61</a>. Updated <a href="#">Table 63</a>. Revised <a href="#">Table 69</a>. Added data to <a href="#">Table 70</a>. Added <a href="#">Note 2</a> to <a href="#">Table 71</a>. Updated <a href="#">Table 74</a> and added <a href="#">Note 4</a>. Updated <math>V_L</math> and <math>V_H</math> values in <a href="#">Table 78</a>. Added <math>T_{MINPER\_CLK}</math>, revised <math>F_{REFCLK}</math>, and <a href="#">Note 1</a> to <a href="#">Table 82</a>. Added <math>MMCM\_F_{DPRCLK\_MAX}</math> to <a href="#">Table 85</a> and <math>PLL\_F_{DPRCLK\_MAX}</math> to <a href="#">Table 86</a>. Added data to <a href="#">Table 94</a>, <a href="#">Table 96</a>, <a href="#">Table 98</a>, <a href="#">Table 101</a>, and updated the note references in <a href="#">Table 102</a>. Updated <a href="#">Table 103</a> and added Note 8. Updated <a href="#">Table 104</a> and added <a href="#">Note 7</a>. Added more protocols, <a href="#">Note 1</a> and <a href="#">Note 2</a> to <a href="#">Table 105</a>. Removed the <a href="#">GTH Transceiver Protocol Jitter Characteristics</a> section because it is covered in <a href="#">Table 105</a>. Added <a href="#">Note 1</a> to <a href="#">Table 109</a>. Added data to <a href="#">Table 106</a>, <a href="#">Table 108</a>, <a href="#">Table 110</a>, <a href="#">Table 113</a>. Added <a href="#">Note 2</a> to <a href="#">Table 112</a>. Added note references in <a href="#">Table 114</a>. Updated <a href="#">Table 115</a> and added <a href="#">Note 8</a>. Updated <a href="#">Table 116</a> and added <a href="#">Note 7</a>. Added more protocols and <a href="#">Note 3</a> to <a href="#">Table 117</a>. Removed the <a href="#">GTY Transceiver Protocol Jitter Characteristics</a> section because it is covered in <a href="#">Table 117</a>. Revised <a href="#">Table 124</a>. Added <math>T_{POR}</math> and updated <math>F_{ICAPCK}</math> in <a href="#">Table 127</a>. Updated the <a href="#">Automotive Applications Disclaimer</a>.</p>
06/20/2016	1.1	<p>Updated the <a href="#">Summary</a> description. In <a href="#">Table 1</a>, revised <math>V_{IN}</math> for HP I/O banks and added clarifications to some descriptions and symbols. Added <math>I_{RPU}</math>, <math>I_{RPD}</math>, and <a href="#">Note 4</a> to <a href="#">Table 2</a> and updated <math>V_{PS\_MGTRAVCC}</math>, the <a href="#">PL System Monitor</a> section, and <a href="#">Note 3</a> and <a href="#">Note 5</a>. Updated <a href="#">Note 5</a> in <a href="#">Table 4</a>. Updated the <a href="#">PS Power-On/Off Power Supply Sequencing</a> section including all the voltage supply names. Added <a href="#">MIPI_DPHY_DCI</a> to <a href="#">Table 14</a>, <a href="#">Table 15</a>, and <a href="#">Table 17</a>. Updated <a href="#">Table 23</a>, including removing the <math>V_{CCO}</math> specification and adding <a href="#">Note 1</a>. Added <a href="#">Note 1</a> to <a href="#">Table 24</a>. Updated <a href="#">Table 25</a> speed specifications for Vivado Design Suite 2016.1. Added values to <a href="#">Table 28</a>. Updated the -2 value in <a href="#">Table 29</a>. Added <math>F_{DPLIVEVIDEO}</math> and updated <math>F_{FCIDMACLK}</math> in <a href="#">Table 33</a>. Added VCO frequencies to <a href="#">Table 36</a>. Added the <math>T_{PSPOR}</math> minimum to <a href="#">Table 37</a> and updated <a href="#">Note 1</a>. Added <a href="#">Table 38</a>. Added value delineation over <math>V_{CCINT}</math> operating voltages in <a href="#">Table 39</a>. Revised values for <math>F_{TCK}</math> and <math>T_{TAPTCK}/T_{TCKTAP}</math> in <a href="#">Table 40</a> and added value delineation over <math>V_{CCINT}</math> operating voltages. Updated the <a href="#">PS NAND Memory Controller Interface</a> section. Revised some units and <a href="#">Note 1</a> in <a href="#">Table 41</a> and <a href="#">Table 42</a>. Removed Figure 6: Quad-SPI Interface (Feedback Clock Disabled) Timing. Updated <a href="#">Note 1</a> of <a href="#">Table 43</a>. Added <math>F_{TSI\_REF\_CLK}</math> to <a href="#">Table 44</a> and updated <a href="#">Note 1</a>. In <a href="#">Table 45</a>, revised <math>T_{DCSDHSCLK1}</math>, <math>T_{DCSDHSCLK2}</math>, and <math>T_{DCSDHSCLK3}</math> and <a href="#">Note 1</a>. In <a href="#">Table 46</a>, revised <a href="#">Note 1</a>. In <a href="#">Table 47</a>, revised <a href="#">Note 1</a>. Revised <a href="#">Table 48</a>, including <a href="#">Note 1</a>, and added <a href="#">Note 2</a> and <a href="#">Note 3</a>. In <a href="#">Table 49</a>, <a href="#">Table 50</a>, <a href="#">Table 51</a>, and <a href="#">Table 53</a>, revised <a href="#">Note 1</a>. Updated <a href="#">Table 71</a>. Replaced <a href="#">Table 74</a>. Updated <a href="#">Table 75</a> and <a href="#">Table 76</a>. Updated <a href="#">Table 78</a> and <a href="#">Table 79</a>. In <a href="#">Table 80</a>, added the <a href="#">Block RAM and FIFO Clock-to-Out Delays</a> section. Updated the <math>R_{IN}</math> and <math>C_{EXT}</math> values in <a href="#">Table 57</a> and <a href="#">Table 95</a>. Updated the -2 (0.72V) and -1 (0.72V) values and added <a href="#">Note 1</a> to <a href="#">Table 97</a>. Added <a href="#">Table 100</a> and <a href="#">Table 112</a>. Added <a href="#">Note 2</a> to <a href="#">Table 106</a>. Revised data in <a href="#">Table 109</a>. Revised <a href="#">Table 114</a>. Revised data and added notes in the <a href="#">Integrated Interface Block for Interlaken</a> section and <a href="#">Table 121</a>. Moved <a href="#">Table 123</a>. Revised INL in <a href="#">Table 124</a>. Added notes to <a href="#">Table 125</a> and <a href="#">Table 126</a>. In the <a href="#">eFUSE and Programming Conditions</a> table, updated the <math>I_{PSFS}</math> description.</p>
11/24/2015	1.0	Initial Xilinx release.

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